Memory Systems and Memory-Centric Computing

Lecture 4.2: Memory Robustness

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18 July 2024

HiPEAC ACACES Summer School 2024

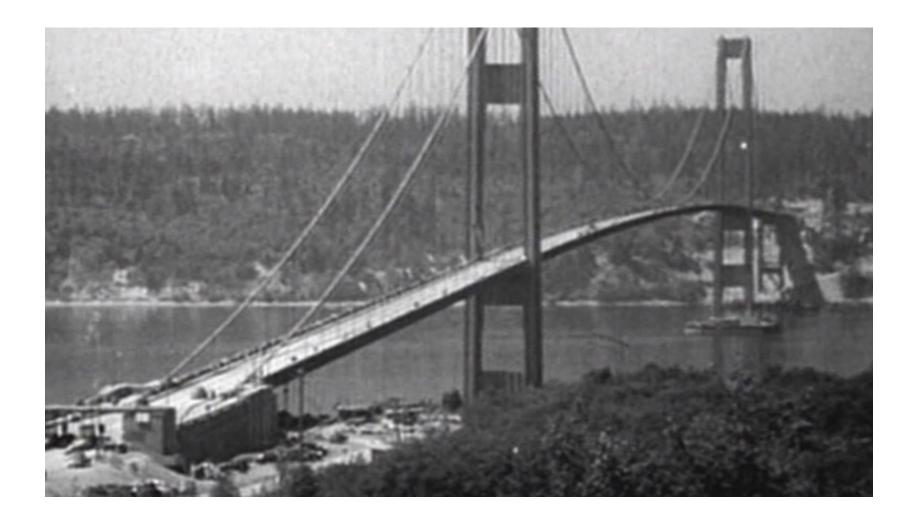




Agenda For Today

- Memory Systems and Memory-Centric Computing
 - July 15-19, 2024
- Topic 1: Memory Trends, Challenges, Opportunities, Basics
- Topic 2: Memory-Centric Computing
- Topic 3: Memory Robustness: RowHammer, RowPress & Beyond
- Topic 4: Machine Learning Driven Memory Systems
- Topic 5 (another course): Architectures for Genomics and ML
- Topic 6 (unlikely): Non-Volatile Memories and Storage
- Topic 7 (unlikely): Memory Latency, Predictability & QoS
- Major Overview Reading:
 - Mutlu et al., "A Modern Primer on Processing in Memory," Book Chapter on Emerging Computing and Devices, 2022.

How Reliable/Secure/Safe is This Bridge?



Collapse of the "Galloping Gertie"



How Safe & Secure Are These People?



Security is about preventing unforeseen consequences

How Safe & Secure Are Our Platforms?



Security is about preventing unforeseen consequences



What Is RowHammer?

- One can predictably induce bit flips in commodity DRAM chips
 - All recent DRAM chips are fundamentally vulnerable
- First example of how a simple hardware failure mechanism can create a widespread system security vulnerability



Forget Software—Now Hackers Are Exploiting Physics

BUSINESS CULTURE DESIGN GEAR SCIENCE







NDY GREENBERG SECURITY 08.31.16 7:00 AM

FORGET SOFTWARE—NOW HACKERS ARE EXPLOITING PHYSICS

An "Early" Position Paper [IMW'13]

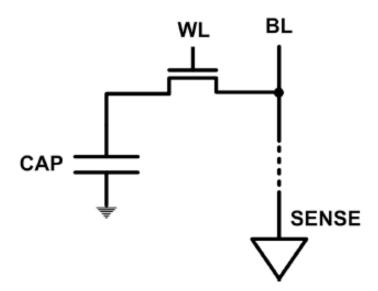
Onur Mutlu,
 "Memory Scaling: A Systems Architecture Perspective"
 Proceedings of the 5th International Memory
 Workshop (IMW), Monterey, CA, May 2013. Slides
 (pptx) (pdf)
 EETimes Reprint

Memory Scaling: A Systems Architecture Perspective

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The DRAM Scaling Problem

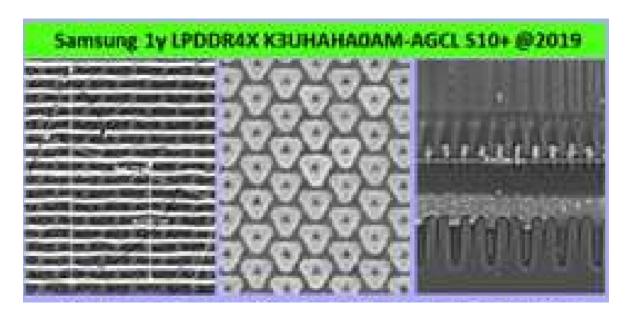
- DRAM stores charge in a capacitor (charge-based memory)
 - Capacitor must be large enough for reliable sensing
 - Access transistor should be large enough for low leakage and high retention time
 - Scaling beyond 40-35nm (2013) is challenging [ITRS, 2009]



DRAM capacity, cost, and energy/power hard to scale

The DRAM Scaling Problem

- DRAM stores charge in a capacitor (charge-based memory)
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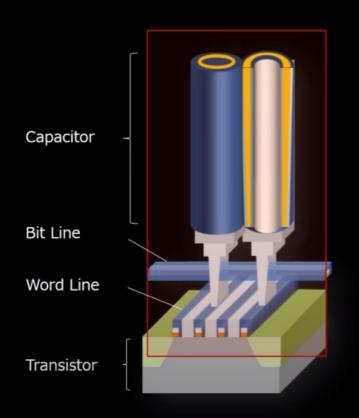
DRAM capacity, cost, and energy/power hard to scale

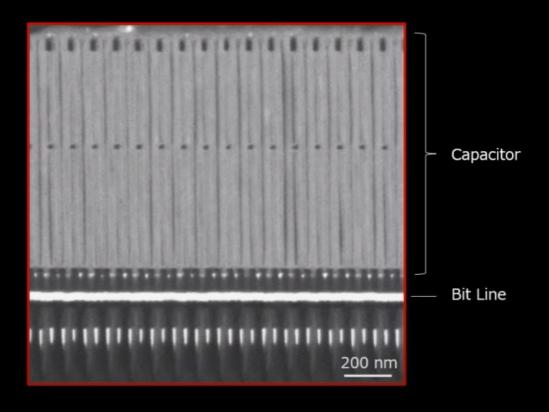
The DRAM Scaling Problem

Cross-sectional SEM of DDR5* DRAM

*Double Data Rate 5

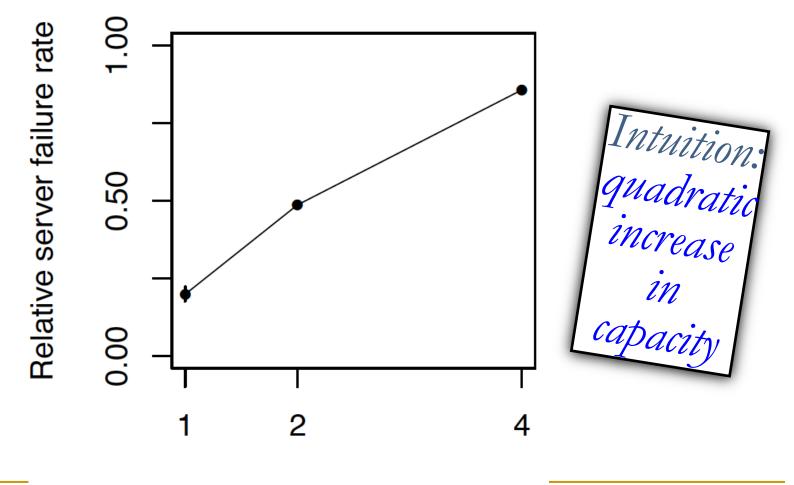
(1y nm generation)





As Memory Scales, It Becomes Unreliable

- Data from all of Facebook's servers worldwide
- Meza+, "Revisiting Memory Errors in Large-Scale Production Data Centers," DSN'15.



Large-Scale Failure Analysis of DRAM Chips

- Analysis and modeling of memory errors found in all of Facebook's server fleet
- Justin Meza, Qiang Wu, Sanjeev Kumar, and Onur Mutlu, "Revisiting Memory Errors in Large-Scale Production Data Centers: Analysis and Modeling of New Trends from the Field" Proceedings of the 45th Annual IEEE/IFIP International Conference on Dependable Systems and Networks (DSN), Rio de Janeiro, Brazil, June 2015.

[Slides (pptx) (pdf)] [DRAM Error Model]

Revisiting Memory Errors in Large-Scale Production Data Centers: Analysis and Modeling of New Trends from the Field

Justin Meza Qiang Wu* Sanjeev Kumar* Onur Mutlu Carnegie Mellon University * Facebook, Inc.

Infrastructures to Understand Such Issues

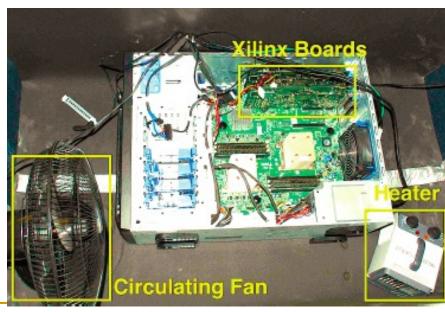


Flipping Bits in Memory Without Accessing
Them: An Experimental Study of DRAM
Disturbance Errors (Kim et al., ISCA 2014)

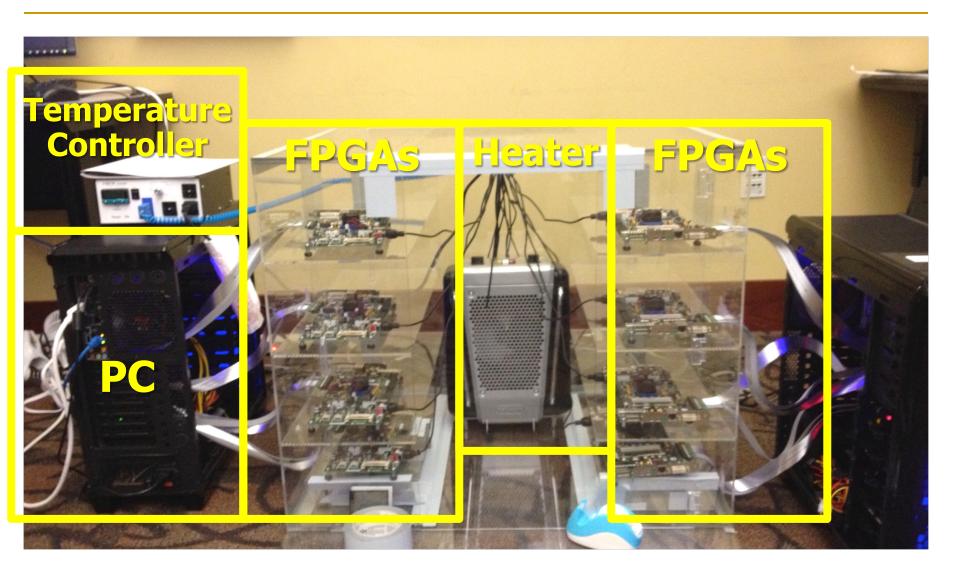
Adaptive-Latency DRAM: Optimizing DRAM
Timing for the Common-Case (Lee et al.,
HPCA 2015)

<u>AVATAR: A Variable-Retention-Time (VRT)</u> <u>Aware Refresh for DRAM Systems</u> (Qureshi et al., DSN 2015) An Experimental Study of Data Retention
Behavior in Modern DRAM Devices:
Implications for Retention Time Profiling
Mechanisms (Liu et al., ISCA 2013)

The Efficacy of Error Mitigation Techniques for DRAM Retention Failures: A Comparative Experimental Study (Khan et al., SIGMETRICS 2014)



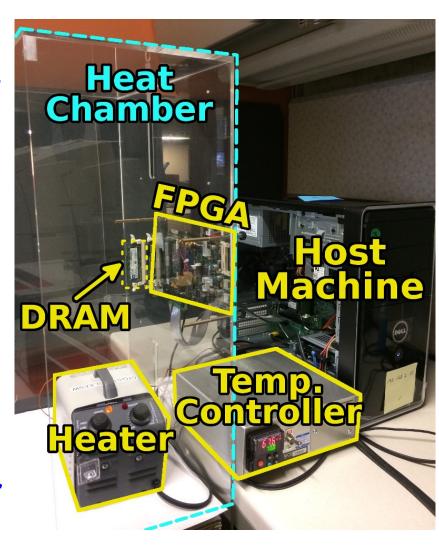
Infrastructures to Understand Such Issues



SoftMC: Open Source DRAM Infrastructure

Hasan Hassan et al., "SoftMC: A Flexible and Practical Open-Source Infrastructure for Enabling Experimental DRAM Studies," HPCA 2017.

- Flexible
- Easy to Use (C++ API)
- Open-source github.com/CMU-SAFARI/SoftMC



SoftMC: Open Source DRAM Infrastructure

Hasan Hassan, Nandita Vijaykumar, Samira Khan, Saugata Ghose, Kevin Chang, Gennady Pekhimenko, Donghyuk Lee, Oguz Ergin, and Onur Mutlu, "SoftMC: A Flexible and Practical Open-Source Infrastructure for Enabling Experimental DRAM Studies"
 Proceedings of the 23rd International Symposium on High-Performance Computer Architecture (HPCA), Austin, TX, USA, February 2017.

 [Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)]
 [Full Talk Lecture (39 minutes)]
 [Source Code]

SoftMC: A Flexible and Practical Open-Source Infrastructure for Enabling Experimental DRAM Studies

```
 Hasan Hassan^{1,2,3} Nandita Vijaykumar^3 Samira Khan^{4,3} Saugata Ghose^3 Kevin Chang^3 Gennady Pekhimenko^{5,3} Donghyuk Lee^{6,3} Oguz Ergin^2 Onur Mutlu^{1,3}
```

¹ETH Zürich ²TOBB University of Economics & Technology ³Carnegie Mellon University ⁴University of Virginia ⁵Microsoft Research ⁶NVIDIA Research

DRAM Bender

Ataberk Olgun, Hasan Hassan, A Giray Yağlıkçı, Yahya Can Tuğrul, Lois Orosa,
Haocong Luo, Minesh Patel, Oğuz Ergin, and Onur Mutlu,
"DRAM Bender: An Extensible and Versatile FPGA-based Infrastructure
to Easily Test State-of-the-art DRAM Chips"

<u>IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems</u> (**TCAD**), 2023.

[Extended arXiv version]

[DRAM Bender Source Code]

[DRAM Bender Tutorial Video (43 minutes)]

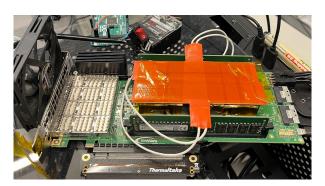
DRAM Bender: An Extensible and Versatile FPGA-based Infrastructure to Easily Test State-of-the-art DRAM Chips

Ataberk Olgun[§] Hasan Hassan[§] A. Giray Yağlıkçı[§] Yahya Can Tuğrul^{§†} Lois Orosa^{§⊙} Haocong Luo[§] Minesh Patel[§] Oğuz Ergin[†] Onur Mutlu[§] [§]ETH Zürich [†]TOBB ETÜ [⊙]Galician Supercomputing Center

DRAM Bender: Prototypes

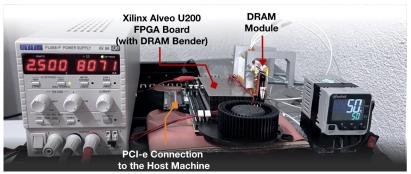
Testing Infrastructure	Protocol Support	FPGA Support
SoftMC [134]	DDR3	One Prototype
LiteX RowHammer Tester (LRT) [17]	DDR3/4, LPDDR4	Two Prototypes
DRAM Bender (this work)	DDR3/DDR4	Five Prototypes

Five out of the box FPGA-based prototypes











Data Retention in Memory [Liu et al., ISCA 2013]

Retention Time Profile of DRAM looks like this:

64-128ms

>256ms

128-256ms

Location dependent
Stored value pattern dependent
Time dependent

RAIDR: Heterogeneous Refresh [ISCA'12]

Jamie Liu, Ben Jaiyen, Richard Veras, and Onur Mutlu, "RAIDR: Retention-Aware Intelligent DRAM Refresh" Proceedings of the 39th International Symposium on Computer Architecture (ISCA), Portland, OR, June 2012. Slides (pdf) [Invited Retrospective at 50 Years of ISCA, 2023 (pdf)] Selected to the ISCA-50 25-Year Retrospective Issue covering 1996-2020 in 2023 (Retrospective (pdf) Full Issue).

RAIDR: Retention-Aware Intelligent DRAM Refresh

Jamie Liu Ben Jaiyen Richard Veras Onur Mutlu Carnegie Mellon University

Analysis of Data Retention Failures [ISCA'13]

Jamie Liu, Ben Jaiyen, Yoongu Kim, Chris Wilkerson, and Onur Mutlu,
 "An Experimental Study of Data Retention Behavior in Modern DRAM Devices:
 Implications for Retention Time Profiling Mechanisms"

Proceedings of the 40th International Symposium on Computer Architecture (ISCA), Tel-Aviv, Israel, June 2013. Slides (ppt) Slides (pdf)

[Invited Retrospective at 50 Years of ISCA, 2023 (pdf)]

Selected to the ISCA-50 25-Year Retrospective Issue covering 1996-2020 in 2023 (Retrospective (pdf) Full Issue).

An Experimental Study of Data Retention Behavior in Modern DRAM Devices: Implications for Retention Time Profiling Mechanisms

Jamie Liu*
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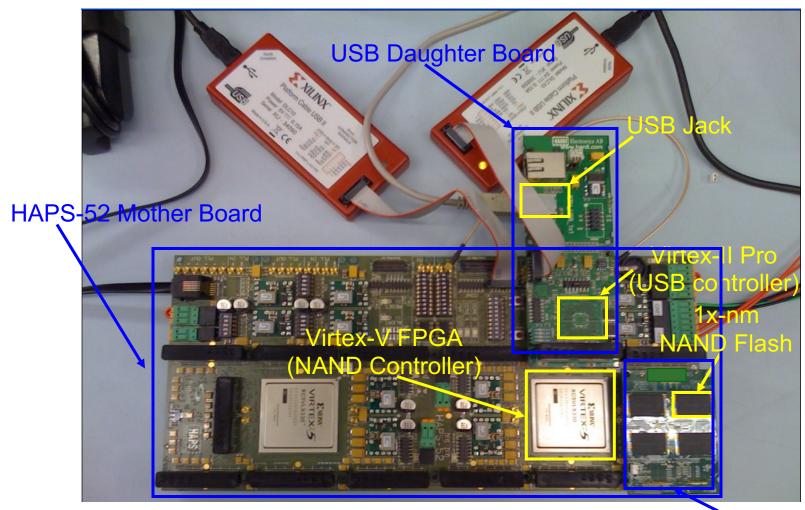
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Infrastructure for Testing NAND Flash Chips



[DATE 2012, ICCD 2012, DATE 2013, ITJ 2013, ICCD 2013, SIGMETRICS 2014, HPCA 2015, DSN 2015, MSST 2015, JSAC 2016, HPCA 2017, DFRWS 2017, PIEEE 2017, HPCA 2018, SIGMETRICS 2018]

NAND Daughter Board

Analysis of NAND Flash Errors [DATE'12]

Yu Cai, Erich F. Haratsch, Onur Mutlu, and Ken Mai, "Error Patterns in MLC NAND Flash Memory: Measurement, Characterization, and Analysis" Proceedings of the <u>Design, Automation, and Test in Europe</u> <u>Conference</u> (DATE), Dresden, Germany, March 2012. <u>Slides</u> (ppt)

Error Patterns in MLC NAND Flash Memory: Measurement, Characterization, and Analysis

Yu Cai¹, Erich F. Haratsch², Onur Mutlu¹ and Ken Mai¹

Department of Electrical and Computer Engineering, Carnegie Mellon University, Pittsburgh, PA

²LSI Corporation, 1110 American Parkway NE, Allentown, PA

¹{yucai, onur, kenmai}@andrew.cmu.edu, ²erich.haratsch@lsi.com

Analysis of NAND Flash Errors [ITJ'13]

Yu Cai, Gulay Yalcin, Onur Mutlu, Erich F. Haratsch, Adrian Cristal, Osman Unsal, and Ken Mai,
 "Error Analysis and Retention-Aware Error Management for NAND Flash Memory"
 Intel Technology Journal (ITJ) Special Issue on Memory Resiliency, Vol. 17, No. 1, May 2013.

Intel® Technology Journal | Volume 17, Issue 1, 2013

ERROR ANALYSIS AND RETENTION-AWARE ERROR MANAGEMENT FOR NAND FLASH MEMORY

Analysis of NAND Flash Errors [PIEEE'17]



Proceedings of the IEEE, Sept. 2017

Error Characterization, Mitigation, and Recovery in Flash-Memory-Based Solid-State Drives

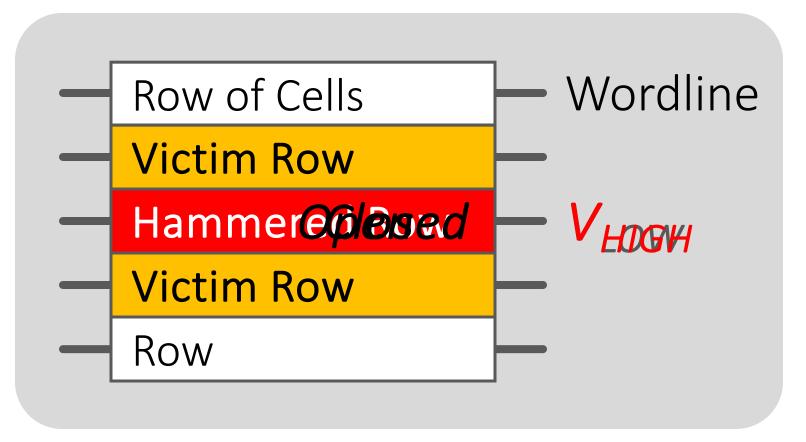


This paper reviews the most recent advances in solid-state drive (SSD) error characterization, mitigation, and data recovery techniques to improve both SSD's reliability and lifetime.

By Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu

A Curious Phenomenon

Modern DRAM is Prone to Disturbance Errors



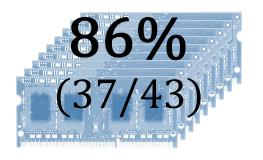
Repeatedly reading a row enough times (before memory gets refreshed) induces disturbance errors in adjacent rows in most real DRAM chips you can buy today

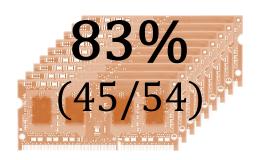
Most DRAM Modules Are Vulnerable

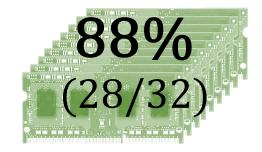
A company

B company

C company





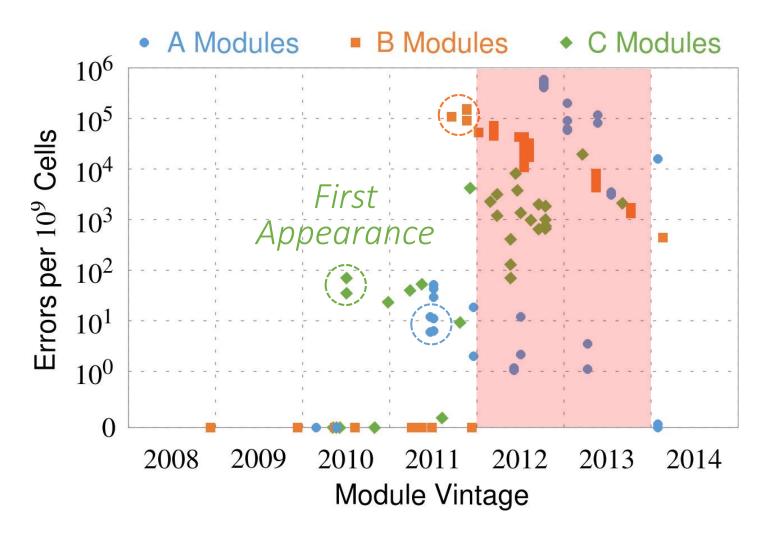


Up to 1.0×10^7 errors

Up to 2.7×10⁶ errors

Up to 3.3×10^5 errors

Recent DRAM Is More Vulnerable



All modules from 2012–2013 are vulnerable

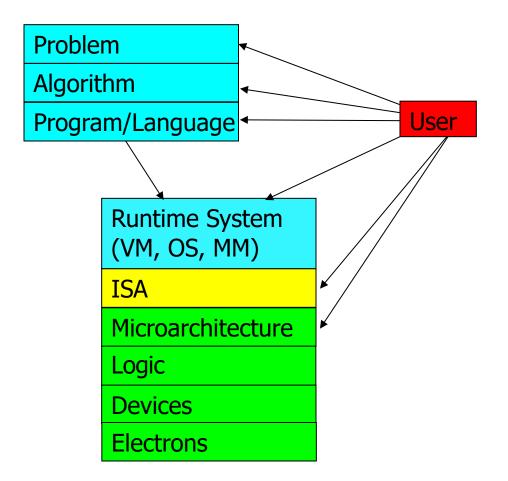
Why Is This Happening?

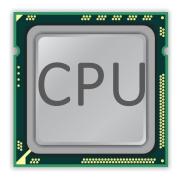
- DRAM cells are too close to each other!
 - They are not electrically isolated from each other
- Access to one cell affects the value in nearby cells
 - due to electrical interference between
 - the cells
 - wires used for accessing the cells
 - Also called cell-to-cell coupling/interference
- Example: When we activate (apply high voltage) to a row, an adjacent row gets slightly activated as well
 - Vulnerable cells in that slightly-activated row lose a little bit of charge
 - If RowHammer happens enough times, charge in such cells gets drained

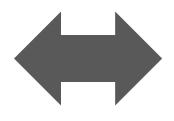
Higher-Level Implications

 This simple circuit level failure mechanism has enormous implications on upper layers of the transformation hierarchy

Problem Algorithm Program/Language **Runtime System** (VM, OS, MM) ISA (Architecture) Microarchitecture Logic Devices Electrons

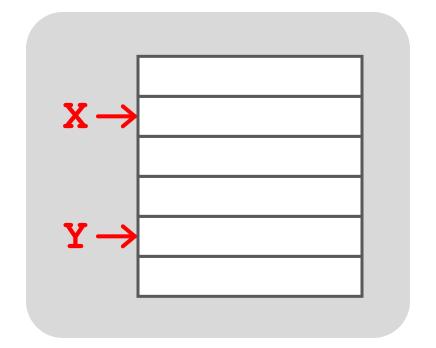




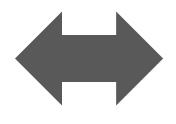




```
loop:
  mov (X), %eax
  mov (Y), %ebx
  clflush (X)
  clflush (Y)
  mfence
  jmp loop
```

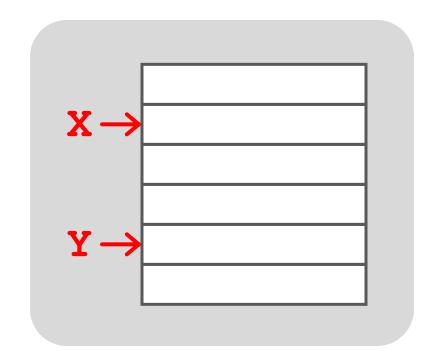


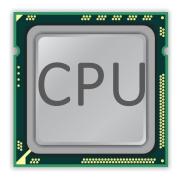


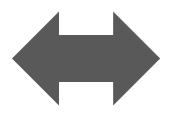




- 1. Avoid cache hits
 - Flush X from cache
- 2. Avoid *row hits* to X
 - Read Y in another row

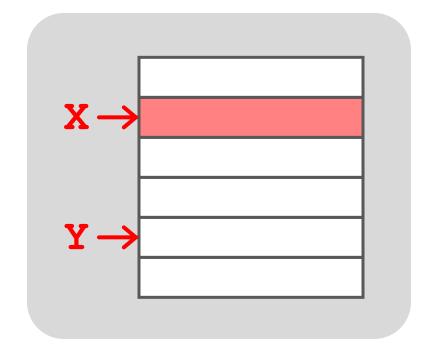


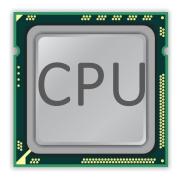


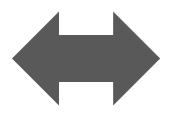




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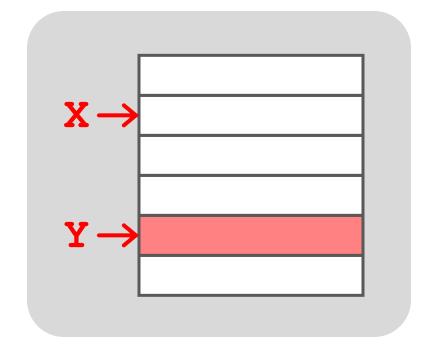




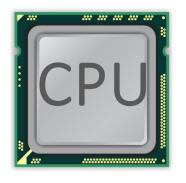


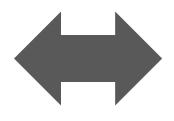


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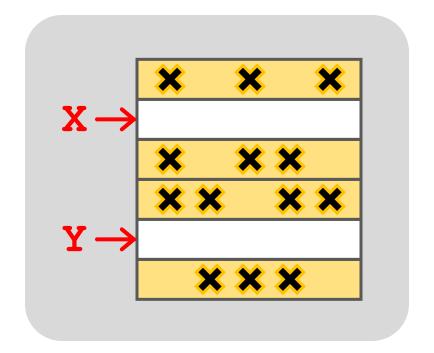
A Simple Program Can Induce Many Errors







```
loop:
  mov (X), %eax
  mov (Y), %ebx
  clflush (X)
  clflush (Y)
  mfence
  jmp loop
```



Download from: https://github.com/CMU-SAFARI/rowhammer

Observed Errors in Real Systems

CPU Architecture	Errors	Access-Rate
Intel Haswell (2013)	22.9K	12.3M/sec
Intel Ivy Bridge (2012)	20.7K	11.7M/sec
Intel Sandy Bridge (2011)	16.1K	11.6M/sec
AMD Piledriver (2012)	59	6.1M/sec

A real robustness issue (including reliability, security, safety)

We Covered Until Here in Lecture 4

Memory Systems and Memory-Centric Computing

Lecture 4.2: Memory Robustness

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18 July 2024

HiPEAC ACACES Summer School 2024





Backup Slides (To Be Covered in Lecture 5)

First Adopters: Memory Testing Software

- PassMark Software, memtest86, since 2014
 - https://www.memtest86.com/troubleshooting.htm#hammer

Why am I only getting errors during Test 13 Hammer Test?

The Hammer Test is designed to detect RAM modules that are susceptible to disturbance errors caused by charge leakage. This phenomenon is characterized in the research paper Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors by Yoongu Kim et al. According to the research, a significant number of RAM modules manufactured 2010 or newer are affected by this defect. In simple terms, susceptible RAM modules can be subjected to disturbance errors when repeatedly accessing addresses in the same memory bank but different rows in a short period of time. Errors occur when the repeated access causes charge loss in a memory cell, before the cell contents can be refreshed at the next DRAM refresh interval.

Starting from MemTest86 v6.2, the user may see a warning indicating that the RAM may be vulnerable to high frequency row hammer bit flips. This warning appears when errors are detected during the first pass (maximum hammer rate) but no errors are detected during the second pass (lower hammer rate). See MemTest86 Test Algorithms for a description of the two passes that are performed during the Hammer Test (Test 13). When performing the second pass, address pairs are hammered only at the rate deemed as the maximum allowable by memory vendors (200K accesses per 64ms). Once this rate is exceeded, the integrity of memory contents may no longer be guaranteed. If errors are detected in both passes, errors are reported as normal.

The errors detected during Test 13, albeit exposed only in extreme memory access cases, are most certainly real errors. During typical nome PC usage (eg. web prowsing, word processing, etc.), it is less likely that the memory usage pattern will fall into the extreme case that make it vulnerable to disturbance errors. It may be of greater concern if you were running highly sensitive equipment such as medical equipment, aircraft control systems, or bank database servers. It is impossible to predict with any accuracy if these errors will occur in real life applications. One would need to do a major scientific study of 1000 of computers and their usage patterns, then do a forensic analysis of each application to study how it makes use of the RAM while it executes. To date, we have only seen 1-bit errors as a result of running the Hammer Test.

First Adopters: Memory Testing Software

- PassMark Software, memtest86, since 2014
 - https://www.memtest86.com/troubleshooting.htm#hammer

Detection and mitigation of row hammer errors

The ability of MemTest86 to detect and report on row hammer errors depends on several factors and what mitigations are in place. To generate errors adjacent memory rows must be repeatedly accessed. But hardware features such as multiple channels, interleaving, scrambling, Channel Hashing, NUMA & XOR schemes make it nearly impossible (for an arbitrary CPU & RAM stick) to know which memory addresses correspond to which rows in the RAM. Various mitigations might also be in place. Different BIOS firmware might set the refresh interval to different values (tREFI). The shorter the interval the more resistant the RAM will be to errors. But shorter intervals result in higher power consumption and increased processing overhead. Some CPUs also support pseudo target row refresh (pTRR) that can be used in combination with pTRR-compliant RAM. This field allows the RAM stick to indicate the MAC (Maximum Active Count) level which is the RAM can support. A typical value might be 200,000 row activations. Some CPUs also support the Joint Electron Design Engineering Council (JEDEC) Targeted Row Refresh (TRR) algorithm. The TRR is an improved version of the previously implemented pTRR algorithm and does not inflict any performance drop or additional power usage. As a result the row hammer test implemented in MemTest86 maybe not be the worst case possible and vulnerabilities in the underlying RAM might be undetectable due to the mitigations in place in the BIOS and CPU.



43

One Can Take Over an Otherwise-Secure System

Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors

Abstract. Memory isolation is a key property of a reliable and secure computing system — an access to one memory address should not have unintended side effects on data stored in other addresses. However, as DRAM process technology

Project Zero

Flipping Bits in Memory Without Accessing Them:
An Experimental Study of DRAM Disturbance Errors
(Kim et al., ISCA 2014)

News and updates from the Project Zero team at Google

Exploiting the DRAM rowhammer bug to gain kernel privileges (Seaborn, 2015)

Monday, March 9, 2015

Exploiting the DRAM rowhammer bug to gain kernel privileges

Many RowHammer Security Exploits

- One can exploit RowHammer to
- Take over a system
- Read data they do not have access to
- Break out of virtual machine sandboxes
- Corrupt important data → e.g., render ML inference useless
- Steal secret data (e.g., crypto keys & ML model parameters)

RowHammer Security Attack Example

- "Rowhammer" is a problem with some recent DRAM devices in which repeatedly accessing a row of memory can cause bit flips in adjacent rows (Kim et al., ISCA 2014).
 - Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors (Kim et al., ISCA 2014)
- We tested a selection of laptops and found that a subset of them exhibited the problem.
- We built two working privilege escalation exploits that use this effect.
 - Exploiting the DRAM rowhammer bug to gain kernel privileges (Seaborn+, 2015)
- One exploit uses rowhammer-induced bit flips to gain kernel privileges on x86-64 Linux when run as an unprivileged userland process.
- When run on a machine vulnerable to the rowhammer problem, the process was able to induce bit flips in page table entries (PTEs).
- It was able to use this to gain write access to its own page table, and hence gain read-write access to all of physical memory.

Security Implications



Security Implications



It's like breaking into an apartment by repeatedly slamming a neighbor's door until the vibrations open the door you were after

More Security Implications (I)

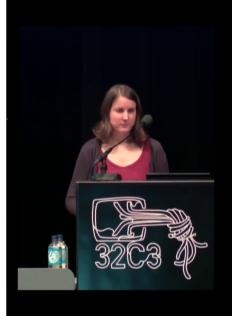
"We can gain unrestricted access to systems of website visitors."

www.iaik.tugraz.at

Not there yet, but ...



ROOT privileges for web apps!





Daniel Gruss (@lavados), Clémentine Maurice (@BloodyTangerine), December 28, 2015 — 32c3, Hamburg, Germany

Rowhammer.js: A Remote Software-Induced Fault Attack in JavaScript (DIMVA'16)

49

More Security Implications (II)

"Can gain control of a smart phone deterministically" Hammer And Root Millions of Androids

Drammer: Deterministic Rowhammer
Attacks on Mobile Platforms, CCS'16 50

More Security Implications (III)

 Using an integrated GPU in a mobile system to remotely escalate privilege via the WebGL interface. IEEE S&P 2018



"GRAND PWNING UNIT" —

Drive-by Rowhammer attack uses GPU to compromise an Android phone

JavaScript based GLitch pwns browsers by flipping bits inside memory chips.

DAN GOODIN - 5/3/2018, 12:00 PM

Grand Pwning Unit: Accelerating Microarchitectural Attacks with the GPU

Pietro Frigo Vrije Universiteit Amsterdam p.frigo@vu.nl Cristiano Giuffrida Vrije Universiteit Amsterdam giuffrida@cs.vu.nl Herbert Bos
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More Security Implications (IV)

Rowhammer over RDMA (I) USENIX ATC 2018



BIZ & IT

TECH

SCIENCE

POLIC

CARS

AMING & CULTUR

THROWHAMMER —

Packets over a LAN are all it takes to trigger serious Rowhammer bit flips

The bar for exploiting potentially serious DDR weakness keeps getting lower.

DAN GOODIN - 5/10/2018, 5:26 PM

Throwhammer: Rowhammer Attacks over the Network and Defenses

Andrei Tatar

VU Amsterdam

Radhesh Krishnan
VU Amsterdam
Herbert Bos

Herbert Bos VU Amsterdam Elias Athanasopoulos *University of Cyprus*

> Kaveh Razavi VU Amsterdam

Cristiano Giuffrida VU Amsterdam

More Security Implications (V)

Rowhammer over RDMA (II)



Nethammer—Exploiting DRAM Rowhammer Bug Through Network Requests



Nethammer: Inducing Rowhammer Faults through Network Requests

Moritz Lipp Graz University of Technology

Daniel Gruss Graz University of Technology Misiker Tadesse Aga University of Michigan

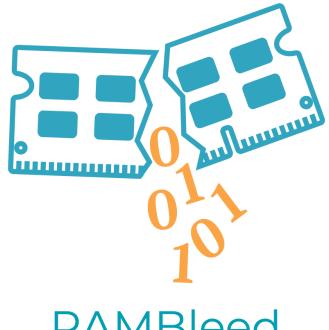
Clémentine Maurice Univ Rennes, CNRS, IRISA

Lukas Lamster Graz University of Technology Michael Schwarz Graz University of Technology

Lukas Raab Graz University of Technology

More Security Implications (VI)

IEEE S&P 2020



RAMBleed

RAMBleed: Reading Bits in Memory Without Accessing Them

Andrew Kwong University of Michigan ankwong@umich.edu

Daniel Genkin University of Michigan genkin@umich.edu

Daniel Gruss Graz University of Technology daniel.gruss@iaik.tugraz.at

Yuval Yarom University of Adelaide and Data61 yval@cs.adelaide.edu.au

More Security Implications (VII)

USENIX Security 2019

Terminal Brain Damage: Exposing the Graceless Degradation in Deep Neural Networks Under Hardware Fault Attacks

Sanghyun Hong, Pietro Frigo[†], Yiğitcan Kaya, Cristiano Giuffrida[†], Tudor Dumitraș

University of Maryland, College Park

†Vrije Universiteit Amsterdam



A Single Bit-flip Can Cause Terminal Brain Damage to DNNs

One specific bit-flip in a DNN's representation leads to accuracy drop over 90%

Our research found that a specific bit-flip in a DNN's bitwise representation can cause the accuracy loss up to 90%, and the DNN has 40-50% parameters, on average, that can lead to the accuracy drop over 10% when individually subjected to such single bitwise corruptions...

Read More

More Security Implications (VIII)

USENIX Security 2020

DeepHammer: Depleting the Intelligence of Deep Neural Networks through Targeted Chain of Bit Flips

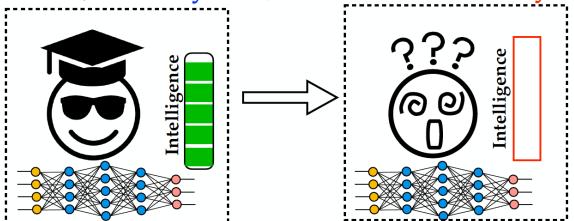
Fan Yao
University of Central Florida
fan.yao@ucf.edu

Adnan Siraj Rakin Deliang Fan Arizona State University asrakin@asu.edu dfan@asu.edu

Degrade the inference accuracy to the level of Random Guess

Example: ResNet-20 for CIFAR-10, 10 output classes

Before attack, Accuracy: 90.2% After attack, Accuracy: ~10% (1/10)



More Security Implications (IX)

CHES 2020

JackHammer: Efficient Rowhammer on Heterogeneous FPGA-CPU Platforms

Zane Weissman¹, Thore Tiemann², Daniel Moghimi¹, Evan Custodio³, Thomas Eisenbarth² and Berk Sunar¹

Worcester Polytechnic Institute, MA, USA

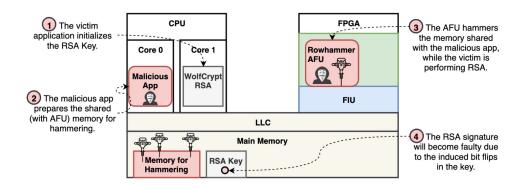
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An **FPGA-based** RowHammer attack recovering **private keys** twice as fast compared to **CPU-based** attacks

Google's Half-Double RowHammer Attack (May 2021)

Google Security Blog

The latest news and insights from Google on security and safety on the Internet

Introducing Half-Double: New hammering technique for DRAM Rowhammer bug

May 25, 2021

Research Team: Salman Qazi, Yoongu Kim, Nicolas Boichat, Eric Shiu & Mattias Nissler

Today, we are sharing details around our discovery of Half-Double, a new Rowhammer technique that capitalizes on the worsening physics of some of the newer DRAM chips to alter the contents of memory.

Rowhammer is a DRAM vulnerability whereby repeated accesses to one address can tamper with the data stored at other addresses. Much like speculative execution vulnerabilities in CPUs, Rowhammer is a breach of the security guarantees made by the underlying hardware. As an electrical coupling phenomenon within the silicon itself, Rowhammer allows the potential bypass of hardware and software memory protection policies. This can allow untrusted code to break out of its sandbox and take full control of the system.

More Security Implications (X)

- USENIX Security 2022
- Google's Half-Double RowHammer Attack



The latest news and insights from Google on security and safety on the Internet

Introducing Half-Double: New hammering technique for DRAM Rowhammer bug

May 25, 2021

Research Team: Salman Qazi, Yoongu Kim, Nicolas Boichat, Eric Shiu & Mattias Nissle

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Half-Double: Hammering From the Next Row Over

Andreas Kogler¹ Jonas Juffinger^{1,2} Salman Qazi³ Yoongu Kim³ Moritz Lipp^{4*} Nicolas Boichat³ Eric Shiu⁵ Mattias Nissler³ Daniel Gruss¹

¹Graz University of Technology ²Lamarr Security Research ³Google ⁴Amazon Web Services ⁵Rivos

More Security Implications?



A RowHammer Survey Across the Stack

Onur Mutlu and Jeremie Kim,

"RowHammer: A Retrospective"

<u>IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems</u> (**TCAD**) Special Issue on Top Picks in Hardware and Embedded Security, 2019.

[Preliminary arXiv version]

[Slides from COSADE 2019 (pptx)]

[Slides from VLSI-SOC 2020 (pptx) (pdf)]

[Talk Video (1 hr 15 minutes, with Q&A)]

RowHammer: A Retrospective

Onur Mutlu^{§‡} Jeremie S. Kim^{‡§} §ETH Zürich [‡]Carnegie Mellon University

61

A RowHammer Survey: Recent Update

Onur Mutlu, Ataberk Olgun, and A. Giray Yaglikci,
 "Fundamentally Understanding and Solving RowHammer"
 Invited Special Session Paper at the <u>28th Asia and South Pacific Design Automation Conference (ASP-DAC)</u>, Tokyo, Japan, January 2023.
 [arXiv version]
 [Slides (pptx) (pdf)]

[Talk Video (26 minutes)]

Fundamentally Understanding and Solving RowHammer

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https://arxiv.org/pdf/2211.07613.pdf

62

A Short Retrospective (a) 50 Years of ISCA

Retrospective: Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors

Onur Mutlu

Abstract—Our ISCA 2014 paper [1] provided the first scientific and detailed characterization, analysis, and real-system demonstration of what is now popularly known as the RowHammer phenomenon for vulnerability) in modern commodity DRAM (hips, which are used as main limest all modern computing systems with the properties of the problem at the properties of the problem at the properties of the problem at various (e.g., device/circuit, architecture, and system) levels, and exploit memory bulleting real systems and suggested that a security attack can be built using this proof-of-concept to hijack control of the system is multiple real systems and suggested that a security attack can be built using this proof-of-concept to hijack control of the system examined seven different approaches (including a novel probabilistic approach that has very low cost), some of which influenced or were adopted in different industrial products.

Many later works from various research communities examined RowHammer building real security attacks, proposing new defenses, further analyzing the problem at various (e.g., device/circuit, architecture, and system) levels, and exploiting RowHammer for various purposes (e.g., to reverse-engineer DRAM chips). Industry has worked and the problem, changing both memory controllers and many later works & Mindset Shift in Hardware Security.

purposes (e.g., to reverse-engineer DRAM (comps), industry his worked to mitigate the problem, changing both memory controllers and DRAM standards/chips. Iwo major DRAM vendors finally wrote papers on the topic in 2023, describing their current approaches to mitigate RowHammer. Research & development on RowHammer in both academia & industry continues to be very active and fascinating.

This short retrospective provides a brief analysis of our ISCA 2014 paper and its impact. We describe the circumstances that led to our paper, mention its influence on later works and products, describe the mindset change we believe it has helped enable in hardware security, and discuss our predictions for future.

I. BACKGROUND AND CIRCUMSTANCES

Our stumbling on the RowHammer problem and creation of its first scientific analysis happened as a result of a confluence of multiple factors. First, my group was working on DRAM technology scaling issues since late 2010. We were very interested in failure mechanisms that appear or worsen due to aggressive technology scaling. To study such issues (e.g., data retention errors [2]), we built an FPGA-based DRAM testing infrastrucerrors [2]), we out at 11 To To asked with the control of the cont solve DRAM technology scaling problems and build our DRAM infrastructure. Three of my students and I spent the summer of 2012 at Intel to work closely with our collaborators (two are co-authors): during this time, we finalized the calibration and stabilization of our infrastructure and had significant technical discussions and experimentation on DRAM scaling problems.

Although there was awareness of the RowHammer problem in industry in 2012 (see Footnote 1 in [1]), there was no comprehensive experimental analysis and detailed real-system demonstration of it. We believed it was critical to provide a rigorous scientific analysis using a wide variety of DRAM chips and scientifically establish major characteristics and prevalence of RowHammer. Hence, in the summer of 2012, we set out to use our DRAM testing infrastructure to analyze RowHammer. Our initial results showed how widespread the read disturbance problem was across the (at the time) recent DRAM chips we tested, so we studied the

milestones related to RowHammer.

RowHammer Attacks & Mindset Shift in Hardware Security. Our demander Anatos de Manaser 51191 in Tradavarie Security. Our demander Anatos de Manaser 51191 in Tradavarie Security. Our demander de La Casasily and predictably induce bifflips in commodity DRAM chips using a real user-level program enabled a major mindset shift in hardware security. It showed that general-purpose hardware is fallible in a very widespread manner and its problems are exploitable. Tens of works (see [13, 14]) built directly on our work to exploit RowHammer bitflips to develop many attacks that compromise system integrity and confidentiality, starting from the first RowHammer exploit by Google Project Zero in 2015 [16, 17] to recent works in 2022-2023 (e.g., [18, 19]). These attacks showed increasingly sophisticated ways by which an unprivileged attacker can exploit RowHammer bitflips to circumvent memory protection and gain complete control of a system (e.g., [16, 20–28]), gain access to confidential data (e.g., [18, 19, 29]), or maliciously destroy the safety and accuracy of a system, e.g., an otherwise accurate machine learning inference engine (e.g., [30,31]). The mindset enabled by RowHammer bitflips caused a renewed interest in hardware security research, enticing many researchers to deeply understand hardware's inner workings and find new vulnerabilities. Thus, hardware security issues have become mainstream discussion in top security & architecture venues, some having sessions entitled RowHammer.

RowHammer Defenses. Tens of works proposed mitigations against RowHammer, some of which were inspired by the solutions we discussed in our ISCA 2014 paper. To date, the search for more efficient and low-cost RowHammer solutions continues. We refer the reader to our prior overview papers [13, 14, 32] and more recent works in 2023 (e.g., [33–35]).

RowHammer Analyses. Our paper initiated works at both architectural & circuit/device-levels to better understand RowHammer and reverse-engineer DRAM chips, to develop better models, defenses, and attacks (see [13, 14]). Our ISCA 20 work [36] revisited RowHammer, comprehensively analyzed of 1580 DRAM chips of three different types from at least two generations, showing that RowHammer has gotten much worse with technology scaling & existing solutions are not effective at future vulnerability levels.

Industry Reaction: Attacks, Analyses, and Mitigations. Folks developing industrial memory testing programs immediately included RowHammer tests, e.g., in memtest86 [37], citing our work. Industry needed to immediately protect RowHammer-vulnerable chips already in the field, so almost all system vendors increased refresh problem comprehensively and developed many solutions to it. The rates; a solution we examined in our paper and deemed costly for resulting paper was submitted to MICRO in May 2013 but was performance and energy, yet it was the only practical lever that rejected. We strengthened the results, especially of the mitigation could be used in the field. Apple publicly acknowledged our work mechanisms and the number of tested chips, and made the analysis in their security release [38] that announced higher refresh rates to mitigate RowHammer. Intel designed memory controllers that performed probabilistic activations (i.e., pTRR [39, 40]), similar to our PARA solution [1]. DRAM vendors modified the DRAM standard to introduce TRR (arget row refresh) mechanisms [39] and claimed their new DDR4 chips to be RowHammer-free [39, 41]. This bold claim was later refuted by our TRRespass work [39] in 2020, which introduced the many-sided RowHammer attack to irrumwent internal protection mechanisms added to the DRAM chips. Our later work, Uncovering TRR [41] showed that one an almost completely reverse-engineer and thus easily bypass RowHammer mitigations employed in all tested DRAM chips, i.e., RowHammer sultions in DRAM chips are broken. The analysis done by our two major works in 2020 [36, 39] caused the industry to reorganize the RowHammer task group at JEDEC, which produced two white papers on mitigating RowHammer (24, 43). Nine years after our paper, in 2023, two major DRAM vendors, SK Hvnix and Samsune, finally wrote bazers [44, 45] on the standard provided results and samsune standard provided result

done by our two major works in 2020 [36, 39] caused the industry to reorganize the RowHammer task group at IEDEC, which produced two white papers on mitigating RowHammer [42, 43], the produced two white papers on mitigating RowHammer [42, 43], the produced two white papers on mitigating RowHammer [42, 43], the produced two white papers on mitigating RowHammer [42, 43], the produced residuating solutions build on the probabilistic & access-counterbased solutions build on the probabilistic & access-counterbased solutions approaches our ISCA 2014 paper introduced. Major Internet and cloud systems compared as lot took a deep interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest in RowHammer as it can greatly impact their yesten seeps interest and the properties in the RowHammer as it can greatly impact their yesten seeps as a proper introduced.

III. SUMMARY AND FUTURE OUTLOOK

III. SUMMARY AND FUTURE OUTLOOK

Since 2012-2014, RowHammer vulnerability as become must not done to technology scaling. without mitigation, one can not not seed the to technology scaling without mitigation, one can not not seed the to technology scaling without mitigation, one can not not contained to the problem and of avoiding bitlips. Unfortunately, we have also come a long way vulnerability. The industry is now (hipper face) of the problem and of avoiding bitlips. Unfortunately, and fifteen and completely-secure solution is not found yet. The solution space poses at rich area of tradeoffs in terms

Understanding RowHammer

First RowHammer Analysis [ISCA 2014]

Yoongu Kim, Ross Daly, Jeremie Kim, Chris Fallin, Ji Hye Lee, Donghyuk Lee, Chris Wilkerson, Konrad Lai, and Onur Mutlu,

"Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors"

Proceedings of the <u>41st International Symposium on Computer Architecture</u> (**ISCA**), Minneapolis, MN, June 2014.

[Slides (pptx) (pdf)] [Lightning Session Slides (pptx) (pdf)] [Source Code and Data] [Lecture Video (1 hr 49 mins), 25 September 2020]

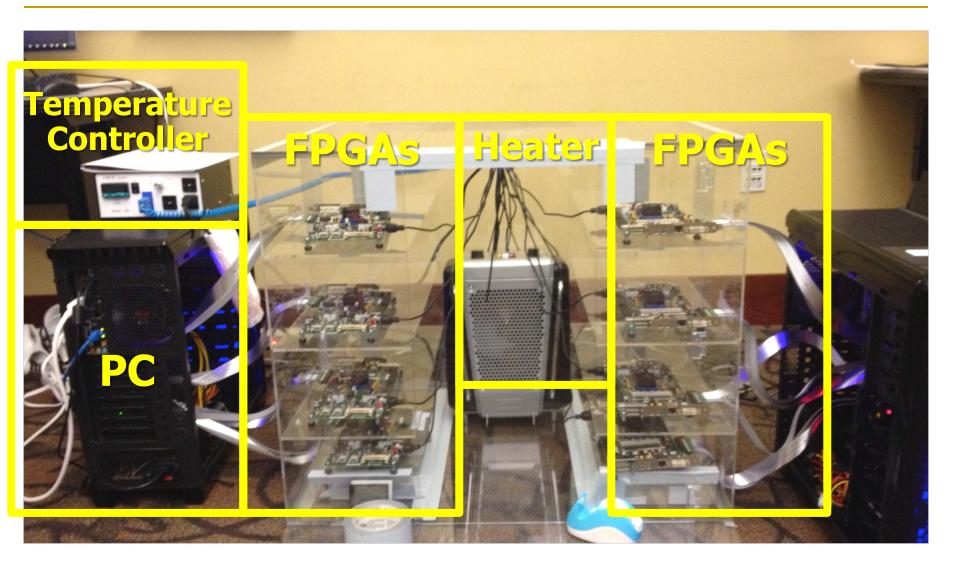
One of the 7 papers of 2012-2017 selected as Top Picks in Hardware and Embedded Security for IEEE TCAD (<u>link</u>). Selected to the ISCA-50 25-Year Retrospective Issue covering 1996-2020 in 2023 (<u>Retrospective</u> (<u>pdf</u>) <u>Full Issue</u>). Winner of the 2024 IFIP Jean-Claude Laprie Award in dependable computing (link).

Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors

Yoongu Kim¹ Ross Daly* Jeremie Kim¹ Chris Fallin* Ji Hye Lee¹ Donghyuk Lee¹ Chris Wilkerson² Konrad Lai Onur Mutlu¹

¹Carnegie Mellon University ²Intel Labs

RowHammer Infrastructure (2012-2014)



Tested
DRAM
Modules
from
2008-2014

(129 total)

Manufacturer	Module	Date* (yy-ww)	$Timing^{\dagger}$		Organization		Chip		Victims-per-Module			RI _{th} (ms)	
			Freq (MT/s)	t _{RC} (ns)	Size (GB)	Chips	Size (Gb) [‡]	Pins	Die Version [§]	Average	Minimum	Maximum	Min
	A_1	10-08	1066	50.625	0.5	4	1	×16	\mathcal{B}	0	0	0	-
	A ₂	10-20	1066	50.625	1	8	1	×8	F	0	0	0	-
	A ₃₋₅	10-20	1066	50.625	0.5	4	1	×16	В	0	0	0	
	A ₆₋₇	11-24	1066	49.125	1	4	2	×16	\mathcal{D}	7.8×10^{1}	5.2×10^{1}	1.0×10^{2}	21.3
	A ₈₋₁₂	11-26	1066	49.125	1	4	2	×16	D	2.4×10^{2}	5.4×10^{1}	4.4×10^{2}	16.4
Α	A ₁₃₋₁₄	11-50	1066	49.125	1	4	2	×16	\mathcal{D}	8.8×10^{1}	1.7×10^{1}	1.6×10^{2}	26.2
A	A ₁₅₋₁₆	12-22	1600	50.625	1	4	2	×16		9.5	9	1.0×10^{1}	34.4
Total of	A ₁₇₋₁₈	12-26	1600	49.125	2	8	2	×8	M	1.2×10^2	3.7×10^{1}	2.0×10^{2}	21.3
43 Modules	A ₁₉₋₃₀	12-40	1600	48.125	2	8	2	×8	κ		7.0×10^6		8.2
	A ₃₁₋₃₄	13-02	1600	48.125	2 2	8	2 2	×8 ×8	_	1.8×10^{6}	1.0×10^6 1.9×10^1	3.5×10^{6}	11.5
	A ₃₅₋₃₆	13-14	1600	48.125						4.0×10^{1} 1.7×10^{6}	1.9×10^{6} 1.4×10^{6}	6.1×10^{1} 2.0×10^{6}	21.3
	A ₃₇₋₃₈	13-20	1600	48.125	2	8	2 2	×8	K	5.7×10^{4}		6.0×10^4	9.8
	A ₃₉₋₄₀	13-28	1600	48.125	2	8	2	×8	λ.		2.7×10^5		16.4
	A ₄₁	14-04 14-04	1600 1600	49.125 48.125	2	8	2	×8 ×8	ĸ	0.5	0	2.7×10^{5}	18.0 62.3
	A ₄₂₋₄₃												02.3
	Bı	08-49	1066	50.625	1	8	1	×8	\mathcal{D}	0	0	0	-
	B ₂	09-49	1066	50.625	1	8	1	×8	$\frac{\mathcal{E}}{T}$	0	0	0	-
	B ₃	10-19	1066	50.625	1	8	1	×8	F	0	0	0	-
	B ₄	10-31	1333	49.125	2	8	2	×8	C	0	0	0	-
	B ₅	11-13	1333	49.125	2	8	2	×8	C F	0	0	0	-
	B ₆	11-16	1066	50.625		8	1	×8	F	0	0	0	-
	B ₇ B ₈	11-19 11-25	1066 1333	50.625 49.125	2	8	2	×8 ×8	C	0	0	0	
В	B ₉	11-23	1333	49.125	2	8	2	×8	\mathcal{D}	1.9×10^{6}	1.9×10^{6}	1.9×10^{6}	11.5
Ь	D ₉	11-46	1333	49.125	2	8	2	×8	\mathcal{D}	2.2×10^6		2.7×10^6	11.5
Total of	B ₁₀₋₁₂	11-40	1333	49.125	2	8	2	×8	c	0	0	0	11.3
54 Modules	B ₁₃ B ₁₄	12-01	1866	47.125	2	8	2	×8	\mathcal{D}	9.1×10^{5}	9.1×10^{5}		9.8
	D ₁₄	12-10	1866	47.125	2	8	2	×8	\mathcal{D}	9.8×10^{5}	7.8×10^{5}	1.2×10^{6}	11.5
	B ₁₅₋₃₁	12-10	1600	48.125	2	8	2	×8	ε		7.4×10^5		11.5
	B ₃₂	12-23	1600	48.125	2	8	2	×8	ε		1.9×10^{5}		11.5
	B ₃₃₋₄₂ B ₄₃₋₄₇	12-28	1600	48.125	2	8	2	×8	ε		2.9×10^{5}	5.5×10^5	13.1
		13-19	1600	48.125	2	8	2	×8	ε		7.4×10^4		14.7
	B ₄₈₋₅₁	13-40	1333	49.125	2	8	2	×8	\mathcal{D}		2.3×10^4		21.3
	B ₅₂₋₅₃ B ₅₄	14-07	1333	49.125	2	8	2	×8	\mathcal{D}		7.5×10^3		26.2
	C ₁	10-18	1333	49.125	2	8	2	×8	\mathcal{A}	0	0	0	-
	C ₂	10-20	1066	50.625	2	8	2	×8	A	0	0	0	-
	C ₃	10-22	1066	50.625	2	8	2	×8	A	0	0	0	-
	C ₄₋₅	10-26	1333	49.125	2	8	2	×8	B	8.9×10^{2}	6.0×10^{2}	1.2×10^{3}	29.5
C Total of 32 Modules	U ₆	10-43	1333	49.125	1 2	8	1 2	×8	\mathcal{T} \mathcal{B}	0	$0 \\ 4.0 \times 10^{2}$	$0 \\ 4.0 \times 10^{2}$	- 20.5
	C ₇	10-51	1333 1333	49.125	2	8	2	×8 ×8	В	4.0×10^2 6.9×10^2	6.9×10^{2}	6.9×10^{2}	29.5 21.3
	C ₈	11-12		46.25		8					9.2×10^{-2}		
	C ₉ C ₁₀	11-19 11-31	1333 1333	46.25 49.125	2 2	8	2 2	×8 ×8	B B	9.2×10^{2}	3.2 × 10-	3.2 × 10-	27.9 39.3
		11-31	1333	49.125	2	8	2	×8	В	1.6×10^{2}	1.6×10^{2}	1.6×10^{2}	39.3
	C ₁₁	11-42	1600	48.125	2	8	2	×8	C	7.1×10^{4}	7.1×10^4		19.7
	C ₁₂	12-08	1333	49.125	2	8	2	×8	c	3.9×10^4	3.9×10^4		21.3
	C ₁₃	12-08	1333	49.125	2	8	2	×8	c	3.7 × 10 ⁴	2.1×10^4		21.3
	C ₁₄₋₁₅	12-12	1600	48.125	2	8	2	×8	c	3.7×10^{3} 3.5×10^{3}	1.2×10^3	7.0×10^3	27.9
	C ₁₆₋₁₈ C ₁₉	12-23	1600	48.125	2	8	2	×8	ε	1.4×10^5	1.4×10^{5}	1.4×10^{5}	18.0
	C ₂₀	12-23	1600	48.125	2	8	2	×8	c	6.5×10^4	6.5×10^4		21.3
	C ₂₁	12-24	1600	48.125	2	8	2	×8	c	2.3×10^4			24.6
	C ₂₂	12-20	1600	48.125	2	8	2	×8	c		1.7×10^4		22.9
	G ₂₂	12-32	1600	48.125	2	8	2	×8	c		1.1×10^4		18.0
	C ₂₃₋₂₄ C ₂₅₋₃₀	12-37	1600	48.125	2	8	2	×8	c		1.1×10^4		19.7
	C ₃₁	13-11	1600	48.125	2	8	2	×8	c		3.3×10^{5}		14.7
	C ₃₂	13-35	1600	48.125	2	8	2	×8	c	3.7×10^4	3.7×10^4		21.3

^{*} We report the manufacture date marked on the chip packages, which is more accurate than other dates that can be gleaned from a module.

† We report timing constraints stored in the module's on-board ROM [33], which is read by the system BIOS to calibrate the memory controller.

‡ The maximum DRAM chip size supported by our testing platform is 2Gb.



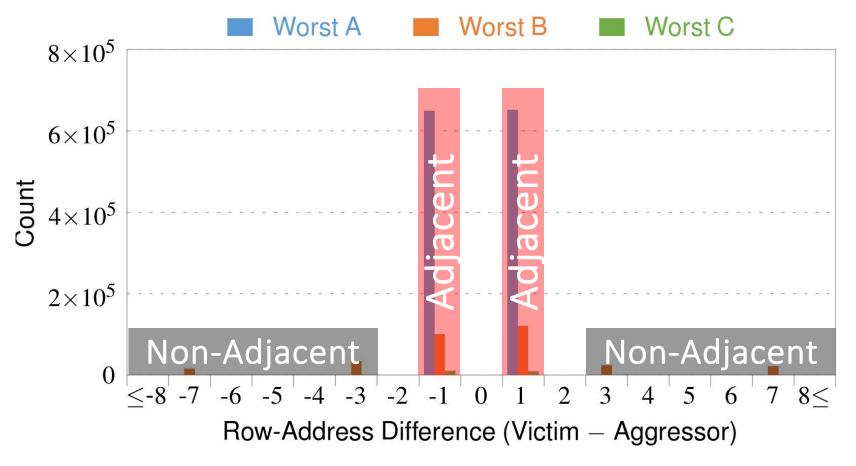
[§] We report DRAM die versions marked on the chip packages, which typically progress in the following manner: $\mathcal{M} \to \mathcal{A} \to \mathcal{B} \to \mathcal{C} \to \cdots$.

Table 3. Sample population of 129 DDR3 DRAM modules, categorized by manufacturer and sorted by manufacture date

RowHammer Characterization Results

- 1. Most Modules Are at Risk
- 2. Errors vs. Vintage
- 3. Error = Charge Loss
- 4. Adjacency: Aggressor & Victim
- 5. Sensitivity Studies
- 6. Other Results in Paper
- 7. Solution Space

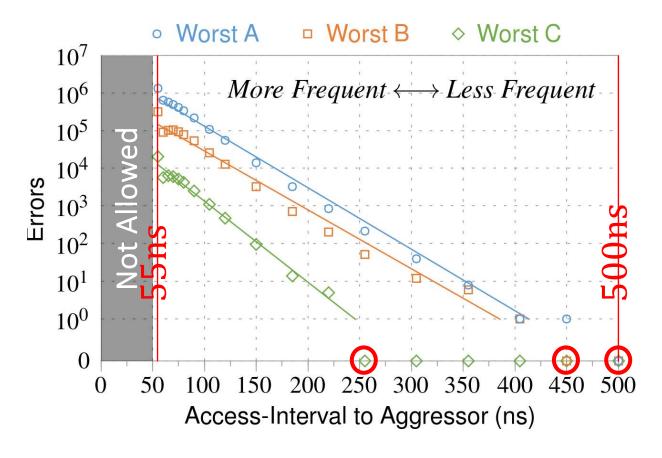
4. Adjacency: Aggressor & Victim



Note: For three modules with the most errors (only first bank)

Most aggressors & victims are adjacent

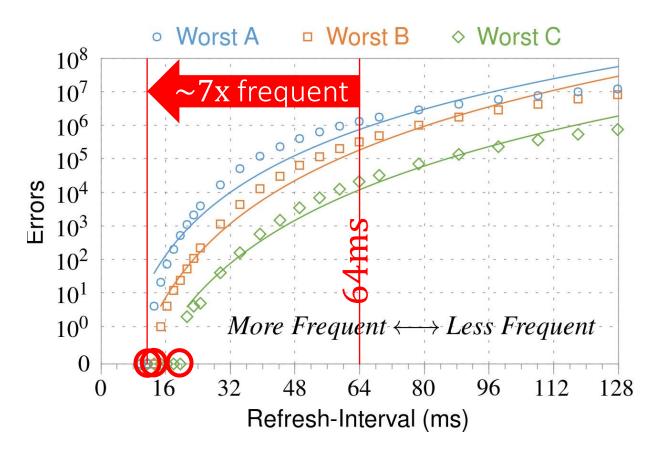
Access Interval (Aggressor)



Note: For three modules with the most errors (only first bank)

Less frequent accesses → Fewer errors

2 Refresh Interval

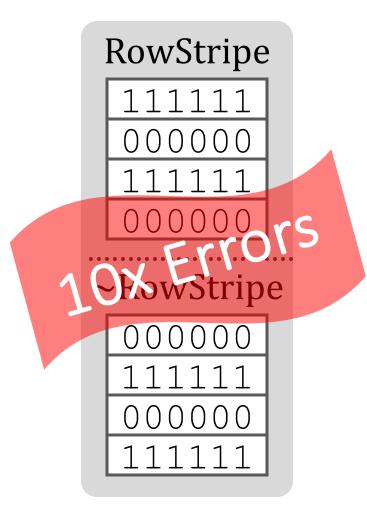


Note: Using three modules with the most errors (only first bank)

More frequent refreshes \rightarrow *Fewer errors*

B Data Pattern

Solid ~Solid 00000 00000 00000 00000



Errors affected by data stored in other cells

6. Other Key Observations [ISCA'14]

- Victim Cells ≠ Retention-Weak Cells
 - Almost no overlap between them
- Errors are repeatable
 - Across ten iterations of testing, >70% of victim cells had errors in every iteration
- As many as 4 errors per cache-line
 - Simple ECC (e.g., SECDED) cannot prevent all errors
- Cells affected by two aggressors on either side
 - Double sided hammering

Major RowHammer Characteristics (2014)

 Yoongu Kim, Ross Daly, Jeremie Kim, Chris Fallin, Ji Hye Lee, Donghyuk Lee, Chris Wilkerson, Konrad Lai, and Onur Mutlu,

<u>"Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors"</u>

Proceedings of the <u>41st International Symposium on Computer Architecture</u> (**ISCA**), Minneapolis, MN, June 2014.

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Flipping Bits in Memory Without Accessing Them: An Experimental Study of DRAM Disturbance Errors

Yoongu Kim¹ Ross Daly* Jeremie Kim¹ Chris Fallin* Ji Hye Lee¹ Donghyuk Lee¹ Chris Wilkerson² Konrad Lai Onur Mutlu¹

¹Carnegie Mellon University ²Intel Labs

RowHammer is Getting Much Worse (2020)

 Jeremie S. Kim, Minesh Patel, A. Giray Yaglikci, Hasan Hassan, Roknoddin Azizi, Lois Orosa, and Onur Mutlu,
 "Revisiting RowHammer: An Experimental Analysis of Modern Devices and Mitigation Techniques"

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Revisiting RowHammer: An Experimental Analysis of Modern DRAM Devices and Mitigation Techniques

Jeremie S. Kim^{§†} Minesh Patel[§] A. Giray Yağlıkçı[§] Hasan Hassan[§] Roknoddin Azizi[§] Lois Orosa[§] Onur Mutlu^{§†}

§ETH Zürich †Carnegie Mellon University

RowHammer Has Many Dimensions (2021)

Lois Orosa, Abdullah Giray Yaglikci, Haocong Luo, Ataberk Olgun, Jisung Park, Hasan Hassan,
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RowHammer vs. Wordline Voltage (2022)

A. Giray Yağlıkçı, Haocong Luo, Geraldo F. de Oliviera, Ataberk Olgun, Minesh Patel, Jisung Park, Hasan Hassan, Jeremie S. Kim, Lois Orosa, and Onur Mutlu, "Understanding RowHammer Under Reduced Wordline Voltage: An Experimental Study Using Real DRAM Devices"

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¹ETH Zürich ²Galicia Supercomputing Center (CESGA)

RowHammer in HBM Chips (2023)

Ataberk Olgun, Majd Osserian, A. Giray Yağlıkçı, Yahya Can Tugrul, Haocong Luo, Steve Rhyner, Behzad Salami, Juan Gomez-Luna, and Onur Mutlu, "An Experimental Analysis of RowHammer in HBM2 DRAM Chips" Proceedings of the <u>53nd Annual IEEE/IFIP International Conference on Dependable Systems and Networks</u> Disrupt Track (DSN Disrupt), Porto, Portugal, June 2023.

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An Experimental Analysis of RowHammer in HBM2 DRAM Chips

Ataberk Olgun¹ Majd Osseiran^{1,2} A. Giray Yağlıkçı¹ Yahya Can Tuğrul¹ Haocong Luo¹ Steve Rhyner¹ Behzad Salami¹ Juan Gomez Luna¹ Onur Mutlu¹

ISAFARI Research Group, ETH Zürich

Parameter Variation

Parameter Variation

ISAFARI Research Group, ETH Zürich

Parameter Variation

**Para

RowHammer in HBM Chips (2024)

Appears at DSN 2024

Read Disturbance in High Bandwidth Memory: A Detailed Experimental Study on HBM2 DRAM Chips

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Ataberk Olgun<sup>1</sup> Majd Osseiran<sup>1</sup> A. Giray Yağlıkçı<sup>1</sup> Yahya Can Tuğrul<sup>1</sup> Haocong Luo<sup>1</sup> Steve Rhyner<sup>1</sup> Behzad Salami<sup>2</sup> Juan Gomez Luna<sup>1</sup> Onur Mutlu<sup>1</sup>

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https://arxiv.org/pdf/2310.14665

RowHammer Spatial Variation Analysis (2024)

Appears at HPCA 2024

Spatial Variation-Aware Read Disturbance Defenses: Experimental Analysis of Real DRAM Chips and Implications on Future Solutions

Abdullah Giray Yağlıkçı Yahya Can Tuğrul Geraldo F. Oliveira İsmail Emir Yüksel Ataberk Olgun Haocong Luo Onur Mutlu ETH Zürich

https://arxiv.org/pdf/2402.18652

RowHammer Solutions

Two Types of RowHammer Solutions

Immediate

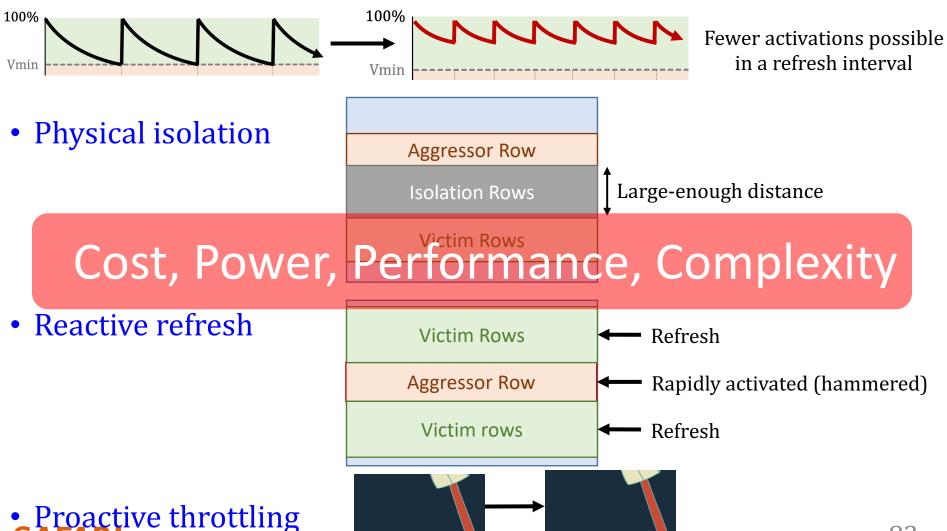
- To protect the vulnerable DRAM chips in the field
- Limited possibilities

- Longer-term
 - To protect future DRAM chips
 - Wider range of protection mechanisms

- Our ISCA 2014 paper proposes both types of solutions
 - Seven solutions in total
 - □ PARA proposed as best solution → already employed in the field

RowHammer Solution Approaches

- More robust DRAM chips and/or error-correcting codes
- Increased refresh rate



83

Apple's Security Patch for RowHammer

https://support.apple.com/en-gb/HT204934

Available for: OS X Mountain Lion v10.8.5, OS X Mavericks v10.9.5

Impact: A malicious application may induce memory corruption to escalate privileges

Description: A disturbance error, also known as Rowhammer, exists with some DDR3 RAM that could have led to memory corruption. This issue was mitigated by increasing memory refresh rates.

CVE-ID

CVE-2015-3693 : Mark Seaborn and Thomas Dullien of Google, working from original research by Yoongu Kim et al (2014)

HP, Lenovo, and many other vendors released similar patches

Our First Solution to RowHammer

• PARA: Probabilistic Adjacent Row Activation

Key Idea

- After closing a row, activate (i.e., refresh) its neighbors with a low probability: p = 0.005

Reliability Guarantee

- When p=0.005, errors in one year: 9.4×10^{-14}
- By adjusting the value of p, we can vary the strength of protection against errors

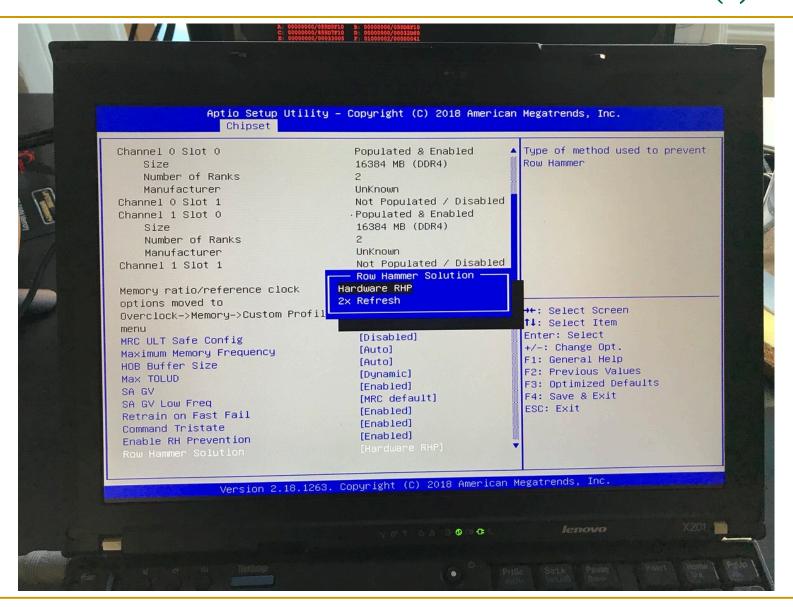
Advantages of PARA

- PARA refreshes rows infrequently
 - Low power
 - Low performance-overhead
 - Average slowdown: 0.20% (for 29 benchmarks)
 - Maximum slowdown: 0.75%
- PARA is stateless
 - Low cost
 - Low complexity
- PARA is an effective and low-overhead solution to prevent disturbance errors

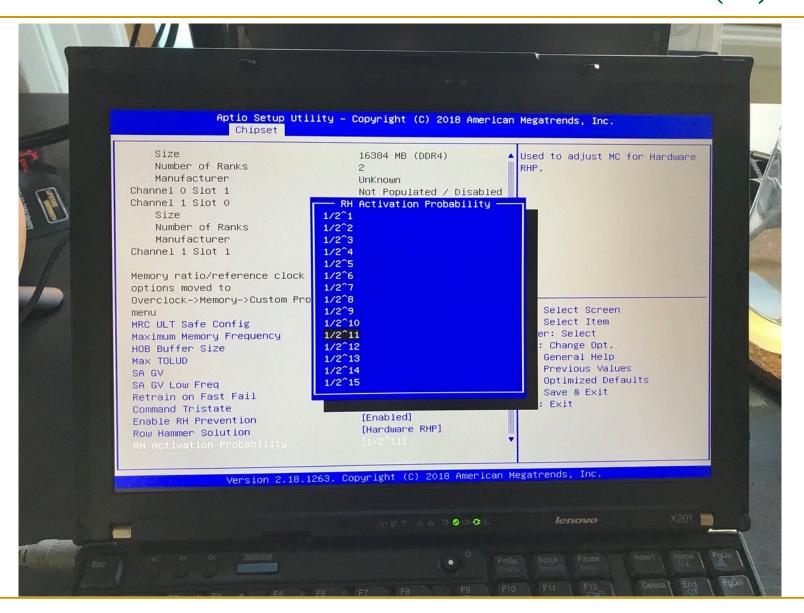
Requirements for PARA

- If implemented in DRAM chip (done today)
 - Enough slack in timing and refresh parameters
 - Plenty of slack today:
 - Lee et al., "Adaptive-Latency DRAM: Optimizing DRAM Timing for the Common Case," HPCA 2015.
 - Chang et al., "Understanding Latency Variation in Modern DRAM Chips," SIGMETRICS 2016.
 - Lee et al., "Design-Induced Latency Variation in Modern DRAM Chips," SIGMETRICS 2017.
 - Chang et al., "Understanding Reduced-Voltage Operation in Modern DRAM Devices," SIGMETRICS 2017.
 - Ghose et al., "What Your DRAM Power Models Are Not Telling You: Lessons from a Detailed Experimental Study," SIGMETRICS 2018.
 - Kim et al., "Solar-DRAM: Reducing DRAM Access Latency by Exploiting the Variation in Local Bitlines," ICCD 2018.
- If implemented in memory controller
 - Need coordination between controller and DRAM
 - Memory controller should know which rows are physically adjacent

Probabilistic Activation in Real Life (I)



Probabilistic Activation in Real Life (II)



Seven RowHammer Solutions Proposed

 Yoongu Kim, Ross Daly, Jeremie Kim, Chris Fallin, Ji Hye Lee, Donghyuk Lee, Chris Wilkerson, Konrad Lai, and Onur Mutlu,

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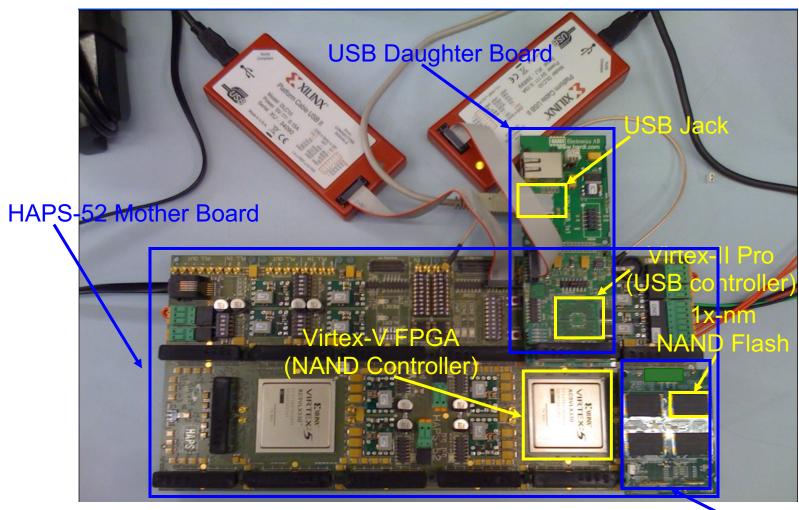
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¹Carnegie Mellon University ²Intel Labs

Main Memory Needs Intelligent Controllers for Security, Safety, Reliability, Scaling

Aside: Intelligent Controller for NAND Flash



[DATE 2012, ICCD 2012, DATE 2013, ITJ 2013, ICCD 2013, SIGMETRICS 2014, HPCA 2015, DSN 2015, MSST 2015, JSAC 2016, HPCA 2017, DFRWS 2017, PIEEE 2017, HPCA 2018, SIGMETRICS 2018]

NAND Daughter Board

Intelligent Flash Controllers [PIEEE'17]



Proceedings of the IEEE, Sept. 2017

Error Characterization, Mitigation, and Recovery in Flash-Memory-Based Solid-State Drives



This paper reviews the most recent advances in solid-state drive (SSD) error characterization, mitigation, and data recovery techniques to improve both SSD's reliability and lifetime.

By Yu Cai, Saugata Ghose, Erich F. Haratsch, Yixin Luo, and Onur Mutlu

Two Major RowHammer Directions

Understanding RowHammer

- Many effects still need to be rigorously examined
 - Aging of DRAM Chips
 - Environmental Conditions (e.g., Process, Voltage, Temperature)
 - Memory Access Patterns
 - Memory Controller & System Design Decisions

Solving RowHammer

- Flexible and efficient solutions are necessary
 - In-field patchable / reconfigurable / programmable solutions
- Co-architecting System and Memory is important
 - To avoid performance and denial-of-service problems

RowHammer in 2020-2024

Revisiting RowHammer

RowHammer is Getting Much Worse

 Jeremie S. Kim, Minesh Patel, A. Giray Yaglikci, Hasan Hassan, Roknoddin Azizi, Lois Orosa, and Onur Mutlu,
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Revisiting RowHammer: An Experimental Analysis of Modern DRAM Devices and Mitigation Techniques

Jeremie S. Kim^{§†} Minesh Patel[§] A. Giray Yağlıkçı[§] Hasan Hassan[§] Roknoddin Azizi[§] Lois Orosa[§] Onur Mutlu^{§†}

§ETH Zürich †Carnegie Mellon University

Key Takeaways from 1580 Chips

 Newer DRAM chips are much more vulnerable to RowHammer (more bit flips, happening earlier)

 There are new chips whose weakest cells fail after only 4800 hammers

• Chips of newer DRAM technology nodes can exhibit RowHammer bit flips 1) in **more rows** and 2) **farther away** from the victim row.

 Existing mitigation mechanisms are NOT effective at future technology nodes

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1580 DRAM Chips Tested

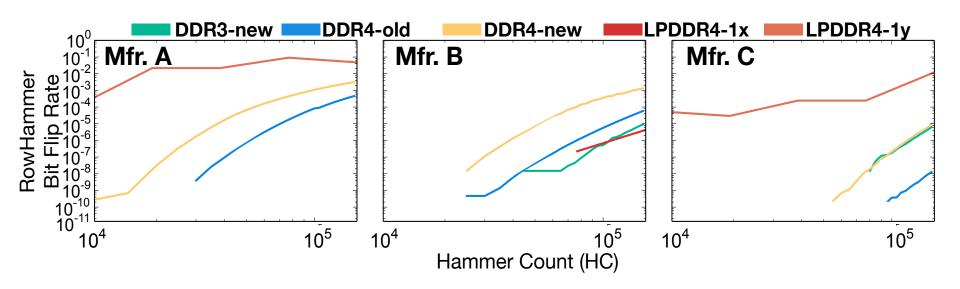
DRAM	Number of Chips (Modules) Tested			
type-node	Mfr. A	Mfr. B	Mfr. C	Total
DDR3-old	56 (10)	88 (11)	28 (7)	172 (28)
DDR3-new	80 (10)	52 (9)	104 (13)	236 (32)
DDR4-old	112 (16)	24 (3)	128 (18)	264 (37)
DDR4-new	264 (43)	16 (2)	108 (28)	388 (73)
LPDDR4-1x	12 (3)	180 (45)	N/A	192 (48)
LPDDR4-1y	184 (46)	N/A	144 (36)	328 (82)

1580 total DRAM chips tested from **300** DRAM modules

- Three major DRAM manufacturers {A, B, C}
- **Three** DRAM *types* or *standards* {DDR3, DDR4, LPDDR4}
 - LPDDR4 chips we test implement on-die ECC
- Two technology nodes per DRAM type {old/new, 1x/1y}
 - Categorized based on manufacturing date, datasheet publication date, purchase date, and characterization results

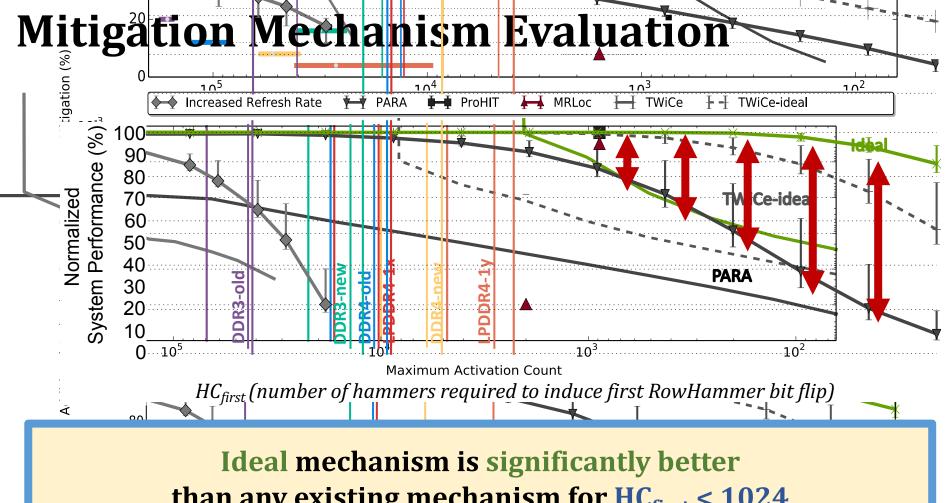
Type-node: configuration describing a chip's type and technology node generation: **DDR3-old/new, DDR4-old/new, LPDDR4-1x/1y**

3. Hammer Count (HC) Effects



RowHammer bit flip rates **increase** when going **from old to new** DDR4 technology node generations

RowHammer bit flip rates (i.e., RowHammer vulnerability) increase with technology node generation



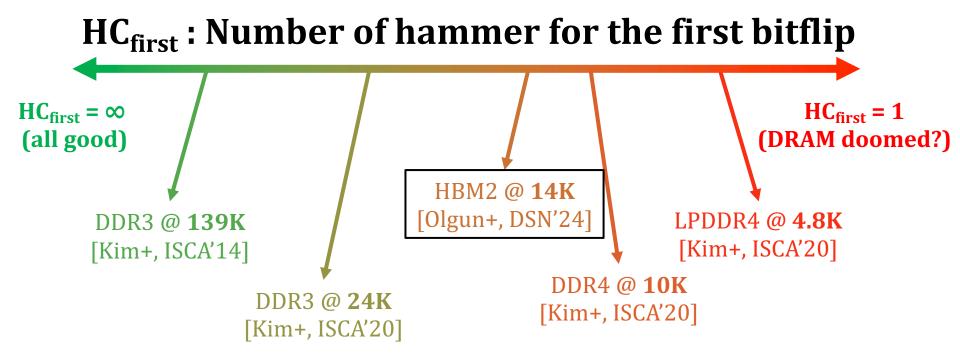
than any existing mechanism for $HC_{first} < 1024$

Significant opportunity for developing a RowHammer solution with low performance overhead that supports low HC_{first}

RowHammer is a technology scaling problem

Finding a good solution to RowHammer is difficult (and will become more so)

Reported HC_{first} Values (2012 - Now)



*Not shown: Significant variance in HC_{first} across vendors and die variations



New RowHammer Characteristics

RowHammer Has Many Dimensions

Lois Orosa, Abdullah Giray Yaglikci, Haocong Luo, Ataberk Olgun, Jisung Park, Hasan Hassan,
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ETH Zürich

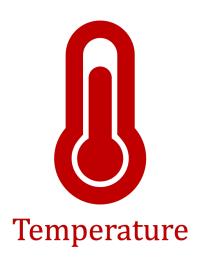
Haocong Luo ETH Zürich Ataberk Olgun ETH Zürich, TOBB ETÜ Jisung Park ETH Zürich

Hasan Hassan ETH Zürich Minesh Patel ETH Zürich

Jeremie S. Kim ETH Zürich Onur Mutlu ETH Zürich

Our Goal

Provide insights into three fundamental properties







To find effective and efficient attacks and defenses

Summary of The Study & Key Results

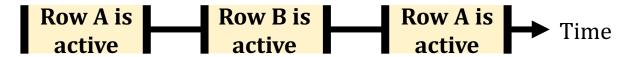
• 272 DRAM chips from four major manufacturers

- 6 major takeaways from 16 novel observations
- A RowHammer bit flip is more likely to occur
 - 1) in a bounded range of temperature
 - 2) if the aggressor row is active for longer time
 - 3) in certain physical regions of the DRAM module under attack

- Our novel observations can inspire and aid future work
 - Craft more effective attacks
 - Design more effective and efficient defenses

Example Attack Improvement 3: Bypassing Defenses with Aggressor Row Active Time

Activating aggressor rows as frequently as possible:



Keeping aggressor rows active for a longer time:

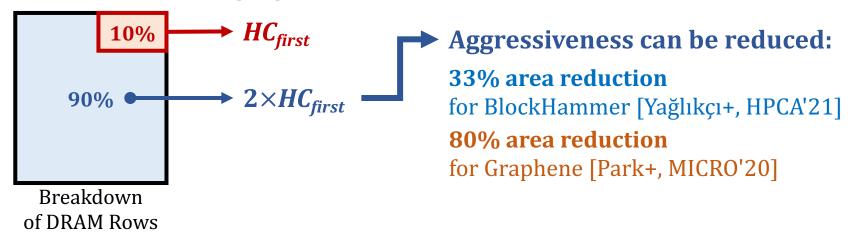


Reduces the minimum activation count to induce a bit flip by 36%

Bypasses defenses that do not account for this reduction

Example Defense Improvements

Example 1: Leveraging variation across DRAM rows



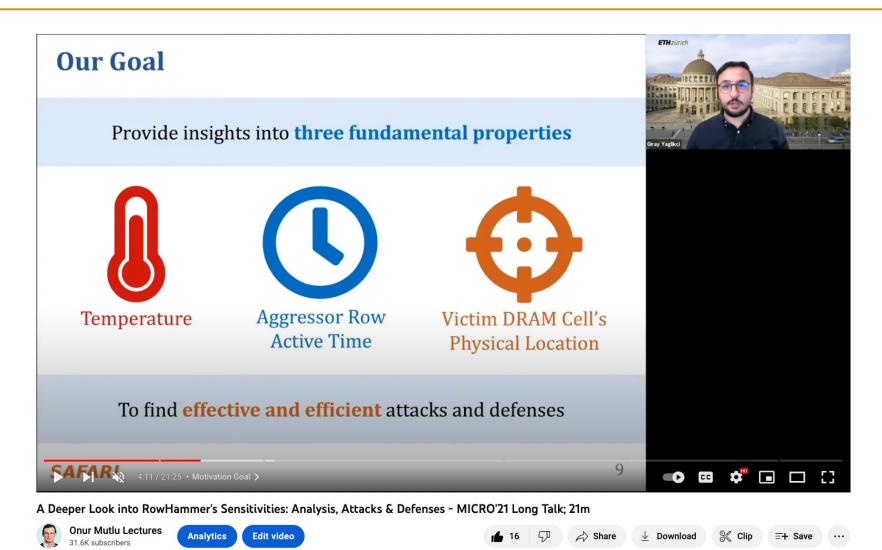
- Example 2: Leveraging variation with temperature
 - A DRAM cell experiences bit flips within a bounded temperature range



• A row can be **disabled** within the row's **vulnerable temperature range**



Deeper Look into RowHammer: Talk Video



More RowHammer Analysis

RowHammer vs. Wordline Voltage (2022)

A. Giray Yağlıkçı, Haocong Luo, Geraldo F. de Oliviera, Ataberk Olgun, Minesh Patel, Jisung Park, Hasan Hassan, Jeremie S. Kim, Lois Orosa, and Onur Mutlu, "Understanding RowHammer Under Reduced Wordline Voltage: An Experimental Study Using Real DRAM Devices"

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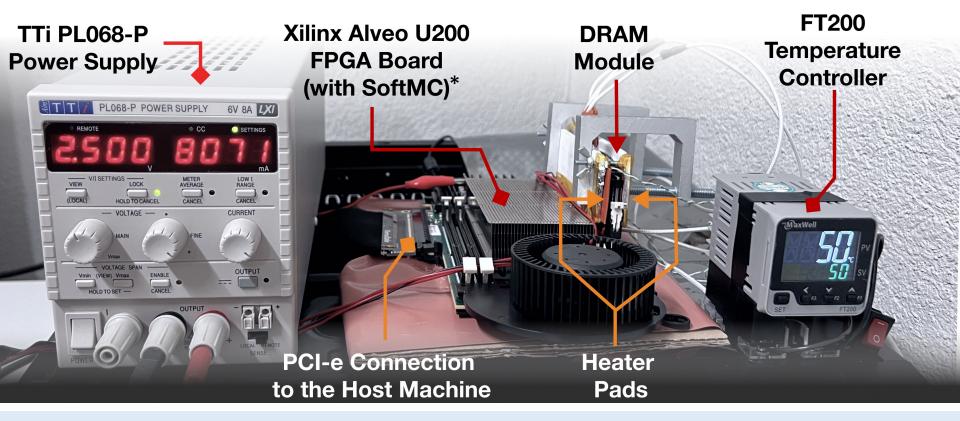
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¹ETH Zürich

²Galicia Supercomputing Center (CESGA)

Updated DRAM Testing Infrastructure

FPGA-based SoftMC (Xilinx Virtex UltraScale+ XCU200)



Fine-grained control over **DRAM commands**, **timing parameters (±1.5ns)**, **temperature (±0.1°C)**, and **wordline voltage (±1mV)**



Summary

We provide the first RowHammer characterization under reduced wordline voltage

Experimental results with 272 real DRAM chips show that reducing wordline voltage:

1. Reduces RowHammer vulnerability

- Bit error rate caused by a RowHammer attack reduces by 15.2% (66.9% max)
- A row needs to be activated **7.4% more times (85.8% max)** to induce the first bit flip

2. Increases row activation latency

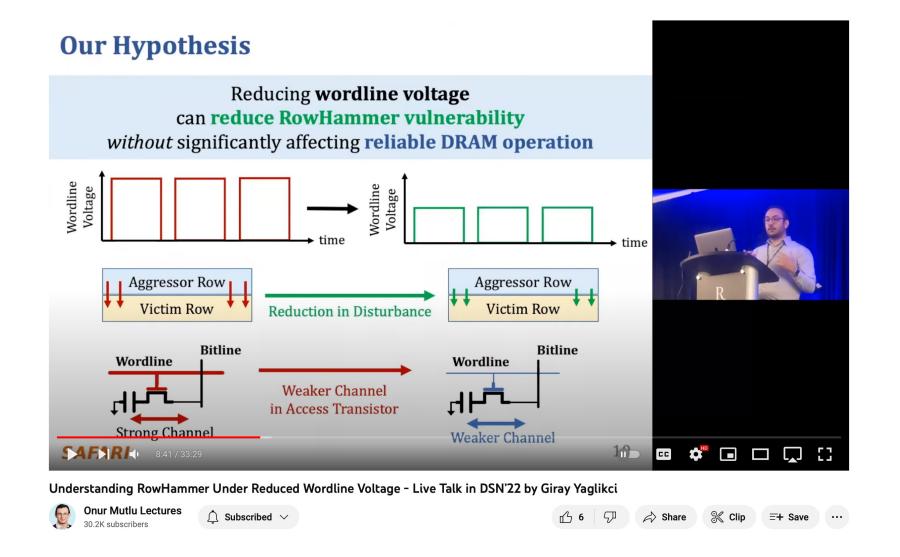
- More than **76%** of the tested DRAM chips **reliably operate** using **nominal** timing parameters
- Remaining 24% reliably operate with increased (up to 24ns) row activation latency

3. Reduces data retention time

- 80% of the tested DRAM chips reliably operate using nominal refresh rate
- Remaining 20% reliably operate by
 - Using single error correcting codes
 - Doubling the refresh rate for a small fraction (16.4%) of DRAM rows

Reducing wordline voltage can **reduce RowHammer vulnerability** without significantly affecting **reliable DRAM operation**

RowHammer vs. Wordline Voltage: Talk Video



RowHammer in HBM Chips (2023)

Ataberk Olgun, Majd Osserian, A. Giray Yağlıkçı, Yahya Can Tugrul, Haocong Luo, Steve Rhyner, Behzad Salami, Juan Gomez-Luna, and Onur Mutlu, "An Experimental Analysis of RowHammer in HBM2 DRAM Chips" Proceedings of the <u>53nd Annual IEEE/IFIP International Conference on Dependable Systems and Networks Disrupt Track (DSN Disrupt)</u>, Porto, Portugal, June 2023.

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ISAFARI Research Group, ETH Zürich

Parameter Variation

Parameter Variation

Parameter Variation

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Parameter Variation

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117

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https://arxiv.org/pdf/2402.18652

New RowHammer Solutions

TRRespass

Industry-Adopted Solutions Do Not Work

 Pietro Frigo, Emanuele Vannacci, Hasan Hassan, Victor van der Veen, Onur Mutlu, Cristiano Giuffrida, Herbert Bos, and Kaveh Razavi,

"TRRespass: Exploiting the Many Sides of Target Row Refresh"

Proceedings of the <u>41st IEEE Symposium on Security and Privacy</u> (**S&P**), San Francisco, CA, USA, May 2020.

[Slides (pptx) (pdf)]

[Lecture Slides (pptx) (pdf)]

[Talk Video (17 minutes)]

[Lecture Video (59 minutes)]

[Source Code]

[Web Article]

Best Paper Award. IEEE Micro Top Pick Honorable Mention.

Pwnie Award 2020 for Most Innovative Research. Pwnie Awards 2020

TRRespass: Exploiting the Many Sides of Target Row Refresh

Pietro Frigo*† Emanuele Vannacci*† Hasan Hassan§ Victor van der Veen¶ Onur Mutlu§ Cristiano Giuffrida* Herbert Bos* Kaveh Razavi*

*Vrije Universiteit Amsterdam

§ETH Zürich

¶Oualcomm Technologies Inc.

A Poor RowHammer Solution



TRRespass

- First work to show that TRR-protected DRAM chips are vulnerable to RowHammer in the field
 - Mitigations advertised as secure are not secure
- Introduces the Many-sided RowHammer attack
 - Idea: Hammer many rows to bypass TRR mitigations (e.g., by overflowing proprietary TRR tables that detect aggressor rows)
- (Partially) reverse-engineers the TRR and pTRR mitigation mechanisms implemented in DRAM chips and memory controllers
- Provides an automatic tool that can effectively create manysided RowHammer attacks in DDR4 and LPDDR4(X) chips

SAFARI

Example Many-Sided Hammering Patterns

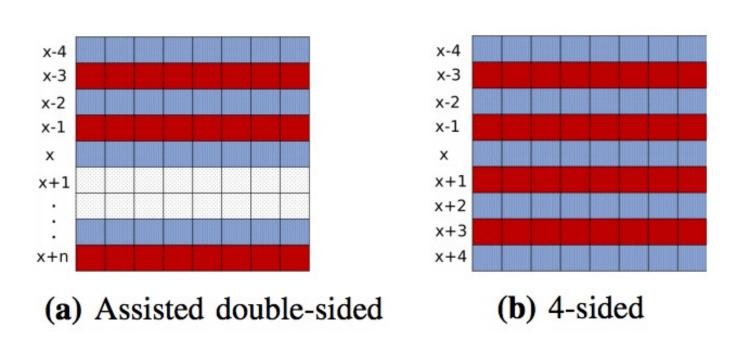


Fig. 12: Hammering patterns discovered by *TRRespass*. Aggressor rows are in red (■) and victim rows are in blue (□).

BitFlips vs. Number of Aggressor Rows

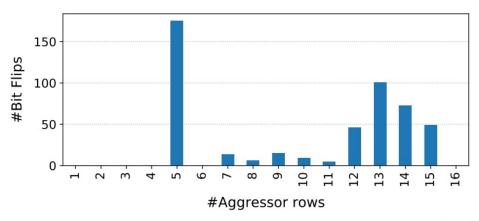


Fig. 10: Bit flips vs. number of aggressor rows. Module \mathcal{C}_{12} : Number of bit flips in bank 0 as we vary the number of aggressor rows. Using SoftMC, we refresh DRAM with standard tREFI and run the tests until each aggressor rows is hammered 500K times.

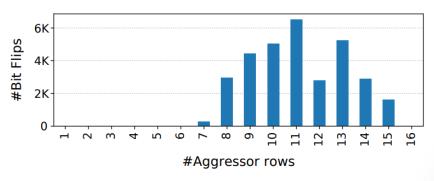


Fig. 11: Bit flips vs. number of aggressor rows. Module \mathcal{A}_{15} : Number of bit flips in bank 0 as we vary the number of aggressor rows. Using SoftMC, we refresh DRAM with standard tREFI and run the tests until each aggressor rows is hammered 500K times.

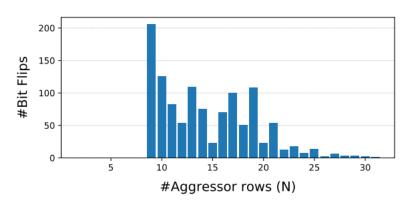


Fig. 13: Bit flips vs. number of aggressor rows. Module A_{10} : Number of bit flips triggered with *N-sided* RowHammer for varying number of *N* on Intel Core i7-7700K. Each aggressor row is one row away from the closest aggressor row (i.e., VAVAVA... configuration) and aggressor rows are hammered in a round-robin fashion.

TRRespass Vulnerable DRAM Modules

TABLE II: TRRespass results. We report the number of patterns found and bit flips detected for the 42 DRAM modules in our set.

Module	Date (yy-ww)	Freq. (MHz)	Size (GB)	Organization			1446	Found	D D	Corruptions			Double
				Ranks	Banks	Pins	MAC	Patterns	Best Pattern	Total	$1 \rightarrow 0$	$0 \rightarrow 1$	Refresh
$A_{0,1,2,3}$	16-37	2132	4	1	16	×8	UL	1	_	_		_	
\mathcal{A}_4	16-51	2132	4	1	16	$\times 8$	UL	4	9-sided	7956	4008	3948	-
A_5	18-51	2400	4	1	8	×16	UL	_	_	_	_	_	_
$A_{6,7}$	18-15	2666	4	1	8	×16	UL	-			—,		_
\mathcal{A}_8	17-09	2400	8	1	16	$\times 8$	UL	33	19-sided	20808	10289	10519	_
\mathcal{A}_9	17-31	2400	8	1	16	$\times 8$	UL	33	19-sided	24854	12580	12274	_
\mathcal{A}_{10}	19-02	2400	16	2	16	$\times 8$	UL	488	10-sided	11342	1809	11533	√
\mathcal{A}_{11}	19-02	2400	16	2	16	$\times 8$	UL	523	10-sided	12830	1682	11148	√
$\mathcal{A}_{12,13}$	18-50	2666	8	1	16	$\times 8$	UL	_	_	_	_	_	_
\mathcal{A}_{14}	19-08 [†]	3200	16	2	16	$\times 8$	UL	120	14-sided	32723	16490	16233	_
${\mathcal{A}_{15}}^{\ddagger}$	17-08	2132	4	1	16	$\times 8$	UL	2	9-sided	22397	12351	10046	_
\mathcal{B}_0	18-11	2666	16	2	16	×8	UL	2	3-sided	17	10	7	-
\mathcal{B}_1	18-11	2666	16	2	16	$\times 8$	UL	2	3-sided	22	16	6	1 1
\mathcal{B}_2	18-49	3000	16	2	16	×8	UL	2	3-sided	5	2	3	_
\mathcal{B}_3	19-08 [†]	3000	8	1	16	$\times 8$	UL	_	_	_	_	-	_
$\mathcal{B}_{4,5}$	19-08 [†]	2666	8	2	16	$\times 8$	UL	<u></u> -	7 <u>9. 11</u> .	_	_0	<u></u>	<u></u>
$\mathcal{B}_{6,7}$	19-08 [†]	2400	4	1	16	$\times 8$	UL	_	_	_	_	<u></u>	_
\mathcal{B}_8 \diamond	19-08 [†]	2400	8	1	16	$\times 8$	UL	_		-	-,	_	-
$\mathcal{B}_9{^\diamond}$	19-08 [†]	2400	8	1	16	$\times 8$	UL	2	3-sided	12		12	√
$\mathcal{B}_{10,11}$	16-13 [†]	2132	8	2	16	×8	UL	_	.—	-		_	_
$\mathcal{C}_{0,1}$	18-46	2666	16	2	16	×8	UL	_	_	_	_	_	_
$\mathcal{C}_{2,3}$	19-08 [†]	2800	4	1	16	×8	UL	<u> 10 0</u> 1		10 <u> </u>		1 <u>0 0</u> 1	<u> </u>
$\mathcal{C}_{4,5}$	19-08 [†]	3000	8	1	16	$\times 8$	UL	_	_	_	_	_	_
$\mathcal{C}_{6,7}$	19-08 [†]	3000	16	2	16	×8	UL	_	_	_	_	_	_
\mathcal{C}_8	19-08 [†]	3200	16	2	16	$\times 8$	UL	_	_	_	-		_
\mathcal{C}_9	18-47	2666	16	2	16	×8	UL	_	_	_		_	_
$\mathcal{C}_{10,11}$	19-04	2933	8	1	16	$\times 8$	UL	_	_	_	—8	_	_
$\mathcal{C}_{12}^{\dagger}$	15-01 [†]	2132	4	1	16	×8	UT	25	10-sided	190037	63904	126133	√
$\mathcal{C}_{13}^{\dagger}$	18-49	2132	4	1	16	×8	UT	3	9-sided	694	239	455	

The module does not report manufacturing date. Therefore, we report purchase date as an approximation.

UL = Unlimited

TRRespass Vulnerable Mobile Phones

TABLE III: LPDDR4(X) results. Mobile phones tested against *TRRespass* on ARMv8 sorted by production date. We found bit flip inducing RowHammer patterns on 5 out of 13mobile phones.

Mobile Phone	Year	SoC	Memory (GB)	Found Patterns
Google Pixel	2016	MSM8996	4 [†]	√
Google Pixel 2	2017	MSM8998	4	_
Samsung G960F/DS	2018	Exynos 9810	4	_
Huawei P20 DS	2018	Kirin 970	4	_
Sony XZ3	2018	SDM845	4	_
HTC U12+	2018	SDM845	6	_
LG G7 ThinQ	2018	SDM845	4 [†]	\checkmark
Google Pixel 3	2018	SDM845	4	\checkmark
Google Pixel 4	2019	SM8150	6	_
OnePlus 7	2019	SM8150	8	\checkmark
Samsung G970F/DS	2019	Exynos 9820	6	\checkmark
Huawei P30 DS	2019	Kirin 980	6	_
Xiaomi Redmi Note 8 Pro	2019	Helio G90T	6	_

TRRespass Based RowHammer Attack

TABLE IV: Time to exploit. Time to find the first exploitable template on two sample modules from each DRAM vendor.

Module	τ (ms)	PTE [81]	RSA-2048 [79]	sudo [27]
\mathcal{A}_{14}	188.7	4.9s	6m 27s	_
${\cal A}_4$	180.8	38.8s	39m 28s	_
\mathcal{B}_1	360.7	_	_	_
\mathcal{B}_2	331.2	_	_	_
\mathcal{C}_{12}	300.0	2.3s	74.6s	54m16s
\mathcal{C}_{13}	180.9	3h 15m	_	_

 $[\]tau$: Time to template a single row: time to fill the victim and aggressor rows + hammer time + time to scan the row.

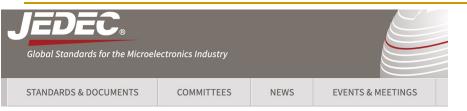
TRRespass Key Results

- 13 out of 42 tested DDR4 DRAM modules are vulnerable
 - From all 3 major manufacturers
 - □ 3-, 9-, 10-, 14-, 19-sided hammer attacks needed
- 5 out of 13 mobile phones tested vulnerable
 - From 4 major manufacturers
 - With LPDDR4(X) DRAM chips
- These results are scratching the surface
 - TRRespass tool is not exhaustive
 - There is a lot of room for uncovering more vulnerable chips and phones

RowHammer is still an open problem

Security by obscurity is likely not a good solution

Improvements in JEDEC (2020-2021)



NEAR-TERM DRAM LEVEL ROWHAMMER MITIGATION

JEP300-1

Published: Mar 2021

RAM process node transistor scaling for power and DRAM capacity has made DRAM cells more sensitive to disturbances or transient faults. This sensitivity becomes much worse if external stresses are applied in a meticulously manipulated sequence, such as Rowhammer. Rowhammer related papers have been written outside of JEDEC, but some assumptions used in those papers didn't explain the problem very clearly or correctly, so the perception for this matter is not precisely understood within the industry. This publication defines the problem and recommends following mitigations to address such concerns across the DRAM industry or academia. Item 1866.01.

Committee(s): JC-42

https://www.jedec.org/standards-documents/docs/jep300-1



SYSTEM LEVEL ROWHAMMER MITIGATION

JEP301-1

Published: Mar 2021

A DRAM rowhammer security exploit is a serious threat to cloud service providers, data centers, laptops, smart phones, self-driving cars and IoT devices. Hardware research and development will take time. DRAM components, DRAM DIMMs, System-on-chip (SoC), chipsets and system products have their own design cycle time and overall life time. This publication recommends best practices to mitigate the security risks from rowhammer attacks. Item 1866.02.

Committee(s): JC-42

https://www.jedec.org/standards-documents/docs/jep301-1

Improvements in JEDEC (2024)



Version 1.30

This standard defines the DDR5 SDRAM specification, including features, functionalities, AC and DC characteristics, packages, and ball/signal assignments. The purpose of this Standard is to define the minimum set of requirements for JEDEC compliant 8 Gb through 32 Gb for x4, x8, and x16 DDR5 SDRAM devices. This standard was created based on the DDR4 standards (JESD79-4) and some aspects of the DDR, DDR2, DDR3, and LPDDR4 standards (JESD79, JESD79-2, JESD79-3, and JESD209-4).

Committee(s): JC-42, JC-42.3

Uncovering TRR Almost Completely

Industry-Adopted Solutions Are Very Poor

Hasan Hassan, Yahya Can Tugrul, Jeremie S. Kim, Victor van der Veen, Kaveh Razavi, and Onur Mutlu,

"Uncovering In-DRAM RowHammer Protection Mechanisms: A New Methodology, Custom RowHammer Patterns, and Implications"

Proceedings of the <u>54th International Symposium on Microarchitecture</u> (**MICRO**), Virtual, October 2021.

[Slides (pptx) (pdf)]

[Short Talk Slides (pptx) (pdf)]

[Lightning Talk Slides (pptx) (pdf)]

[Talk Video (25 minutes)]

[Lightning Talk Video (100 seconds)]

[arXiv version]

Uncovering In-DRAM RowHammer Protection Mechanisms: A New Methodology, Custom RowHammer Patterns, and Implications

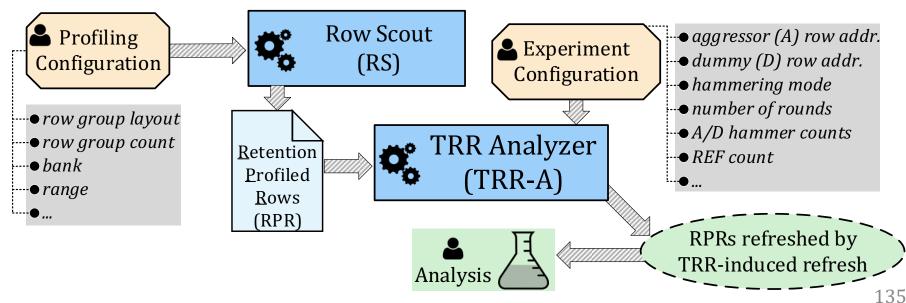
Yahya Can Tuğrul^{†‡} Jeremie S. Kim[†] Hasan Hassan[†] Victor van der Veen $^{\sigma}$ Kaveh Razavi[†] Onur Mutlu[†]

†ETH Zürich [‡]TOBB University of Economics & Technology σ Qualcomm Technologies Inc.

Overview of U-TRR

U-TRR: A new methodology to *uncover* the inner workings of TRR

Key idea: Use data retention failures as a side channel to detect when a row is refreshed by TRR



Key Takeaways

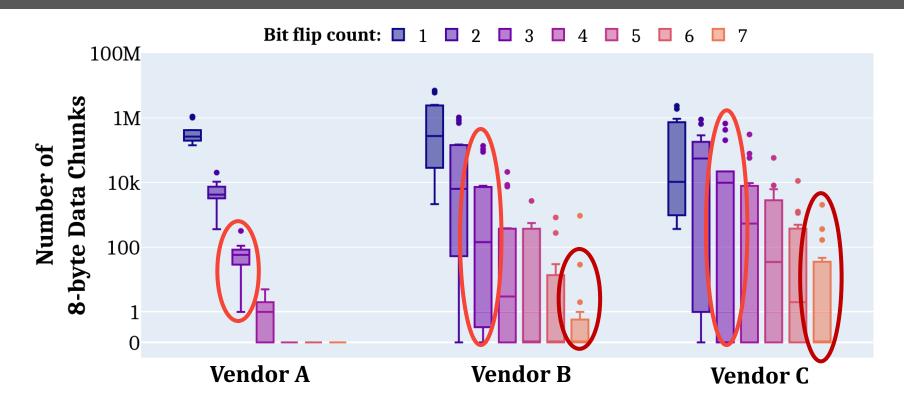
All 45 modules we test are vulnerable

99.9% of rows in a DRAM bank experience at least one RowHammer bit flip

ECC is ineffective: up to 7 RowHammer bit flips in an 8-byte dataword

Module	Date (yy-ww)	Chip Density (Gbit)	Or	Organization			Our Key TRR Observations and Results							
			Ranks	Banks	Pins	HC_{first}^{\dagger}	Version	Aggressor Detection	Aggressor Capacity	Per-Bank TRR	TRR-to-REF Ratio	Neighbors Refreshed	% Vulnerable DRAM Rows†	Max. Bit Flips per Row per Hammer†
A0	19-50	8	1	16	8	16K	A _{TRR1}	Counter-based	16	/	1/9	4	73.3%	1.16
A1-5	19-36	8	1	8	16	13K-15K	A_{TRR1}	Counter-based	16	/	1/9	4	99.2% - 99.4%	2.32 - 4.73
A6-7	19-45	8	1	8	16	13K-15K	ATRR1	Counter-based	16	1	1/9	4	99.3% - 99.4%	2.12 - 3.86
A8-9	20-07	8	1	16	8	12K-14K	A_{TRR1}	Counter-based	16	1	1/9	4	74.6% - 75.0%	1.96 - 2.96
A10-12	19-51	8	1	16	8	12K-13K	A_{TRR1}	Counter-based	16	1	1/9	4	74.6% - 75.0%	1.48 - 2.86
A13-14	20-31	8	1	8	16	11K-14K	A_{TRR2}	Counter-based	16	✓	1/9	2	94.3% - 98.6%	1.53 - 2.78
B0	18-22	4	1	16	8	44K	B_{TRR1}	Sampling-based	1	Х	1/4	2	99.9%	2.13
B1-4	20-17	4	1	16	8	159K-192K	B_{TRR1}	Sampling-based	1	×	1/4	2	23.3% - 51.2%	0.06 - 0.11
B5-6	16-48	4	1	16	8	44K-50K	B_{TRR1}	Sampling-based	1	X	1/4	2	99.9%	1.85 - 2.03
B7	19-06	8	2	16	8	20K	B_{TRR1}	Sampling-based	1	X	1/4	2	99.9%	31.14
B8	18-03	4	1	16	8	43K	B_{TRR1}	Sampling-based	1	X	1/4	2	99.9%	2.57
B9-12	19-48	8	1	16	8	42K-65K	B_{TRR2}	Sampling-based	1	×	1/9	2	36.3% - 38.9%	16.83 - 24.26
B13-14	20-08	4	1	16	8	11K-14K	B_{TRR3}	Sampling-based	1	✓	1/2	4	99.9%	16.20 - 18.12
C0-3	16-48	4	1	16	x8	137K-194K	CTRR1	Mix	Unknown	1	1/17	2	1.0% - 23.2%	0.05 - 0.15
C4-6	17-12	8	1	16	x8	130K-150K	C_{TRR1}	Mix	Unknown	/	1/17	2	7.8% - 12.0%	0.06 - 0.08
C7-8	20-31	8	1	8	x16	40K-44K	C_{TRR1}	Mix	Unknown	1	1/17	2	39.8% - 41.8%	9.66 - 14.56
C9-11	20-31	8	1	8	x16	42K-53K	C_{TRR2}	Mix	Unknown	/	1/9	2	99.7%	9.30 - 32.04
C12-14	20-46	16	1	8	x16	6K-7K	C_{TRR3}	Mix	Unknown	✓	1/8	2	99.9%	4.91 - 12.64

Bypassing ECC with New RowHammer Patterns



Modules from all three vendors have many **8-byte data chunks** with 3 and more (up to 7) RowHammer bit flips

Conventional DRAM ECC cannot protect against our new RowHammer access patterns

Google's Half-Double RowHammer Attack (May 2021)

Google Security Blog

The latest news and insights from Google on security and safety on the Internet

Introducing Half-Double: New hammering technique for DRAM Rowhammer bug

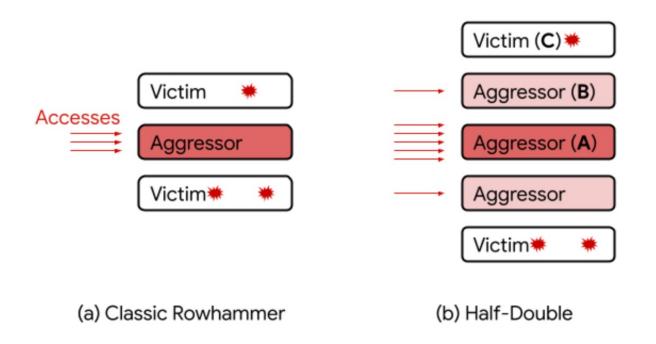
May 25, 2021

Research Team: Salman Qazi, Yoongu Kim, Nicolas Boichat, Eric Shiu & Mattias Nissler

Today, we are sharing details around our discovery of Half-Double, a new Rowhammer technique that capitalizes on the worsening physics of some of the newer DRAM chips to alter the contents of memory.

Rowhammer is a DRAM vulnerability whereby repeated accesses to one address can tamper with the data stored at other addresses. Much like speculative execution vulnerabilities in CPUs, Rowhammer is a breach of the security guarantees made by the underlying hardware. As an electrical coupling phenomenon within the silicon itself, Rowhammer allows the potential bypass of hardware and software memory protection policies. This can allow untrusted code to break out of its sandbox and take full control of the system.

Google's Half-Double RowHammer Attack (May 2021)



- Given three consecutive rows A, B, and C, we were able to attack C by directing a very large number of accesses to A, along with just a handful (~dozens) to B.
- Based on our experiments, accesses to B have a non-linear gating effect, in which they appear to "transport" the Rowhammer effect of A onto C.
- This is likely an indication that the electrical coupling responsible for Rowhammer is a property of distance, effectively becoming stronger and longer-ranged as cell geometries shrink down.

Google's Half-Double RowHammer Attack

Appears at USENIX Security 2022

Half-Double: Hammering From the Next Row Over

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Andreas Kogler<sup>1</sup> Jonas Juffinger<sup>1,2</sup> Salman Qazi<sup>3</sup> Yoongu Kim<sup>3</sup> Moritz Lipp<sup>4*</sup>
Nicolas Boichat<sup>3</sup> Eric Shiu<sup>5</sup> Mattias Nissler<sup>3</sup> Daniel Gruss<sup>1</sup>

<sup>1</sup>Graz University of Technology <sup>2</sup>Lamarr Security Research <sup>3</sup>Google

<sup>4</sup>Amazon Web Services <sup>5</sup>Rivos
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Microsoft's MOESI-prime Work [ISCA'22]

- Introduces coherence-induced hammering
- Hammering in commodity workloads (non-malicious code)

MOESI-prime: Preventing Coherence-Induced Hammering in Commodity Workloads

Kevin Loughlin University of Michigan Stefan Saroiu Microsoft Alec Wolman Microsoft

Yatin A. Manerkar University of Michigan Baris Kasikci University of Michigan

ABSTRACT

Prior work shows that Rowhammer attacks—which flip bits in DRAM via frequent activations of the same row(s)—are viable. Adversaries typically mount these attacks via instruction sequences that are carefully-crafted to bypass CPU caches. However, we discover a novel form of hammering that we refer to as *coherence-induced hammering*, caused by Intel's implementations of cache coherent non-uniform memory access (ccNUMA) protocols. We show that this hammering *occurs in commodity benchmarks* on a major cloud provider's production hardware, the first hammering found to be generated by non-malicious code. Given DRAM's rising susceptibility to bit flips, it is paramount to prevent coherence-induced hammering to ensure reliability and security in the cloud.

1 INTRODUCTION

The threat of Rowhammer [61] bit flips (i.e., DRAM disturbances) is a widespread concern, especially in multi-tenant computing environments such as the cloud. Rowhammer arises from frequent activations—to a first approximation, accesses—of the same DRAM rows, which can disturb data in nearby rows due to electromagnetic interference. These bit flips manifest at the system level as data loss, machine failure, or system subversion.

Prior attacks and analyses [20, 22, 25, 30, 38, 39, 41, 48, 49, 51, 58, 61, 65, 70, 84, 88, 94, 95, 101, 108, 111–114, 119] confirm that malicious adversaries can trigger sufficient activations to flip bits, establishing Rowhammer as a *security* threat. At a high level, existing attacks require a carefully-crafted sequence of instructions to

BlockHammer Solution in 2021

 A. Giray Yaglikci, Minesh Patel, Jeremie S. Kim, Roknoddin Azizi, Ataberk Olgun, Lois Orosa, Hasan Hassan, Jisung Park, Konstantinos Kanellopoulos, Taha Shahroodi, Saugata Ghose, and Onur Mutlu,

"BlockHammer: Preventing RowHammer at Low Cost by Blacklisting Rapidly-Accessed DRAM Rows"

Proceedings of the <u>27th International Symposium on High-Performance Computer</u> <u>Architecture</u> (**HPCA**), Virtual, February-March 2021.

[Slides (pptx) (pdf)]

[Short Talk Slides (pptx) (pdf)]

[Intel Hardware Security Academic Awards Short Talk Slides (pptx) (pdf)]

[Talk Video (22 minutes)]

[Short Talk Video (7 minutes)]

[Intel Hardware Security Academic Awards Short Talk Video (2 minutes)]

[BlockHammer Source Code]

Intel Hardware Security Academic Award Finalist (one of 4 finalists out of 34 nominations)

BlockHammer: Preventing RowHammer at Low Cost by Blacklisting Rapidly-Accessed DRAM Rows

A. Giray Yağlıkçı¹ Minesh Patel¹ Jeremie S. Kim¹ Roknoddin Azizi¹ Ataberk Olgun¹ Lois Orosa¹ Hasan Hassan¹ Jisung Park¹ Konstantinos Kanellopoulos¹ Taha Shahroodi¹ Saugata Ghose² Onur Mutlu¹

¹ETH Zürich ²University of Illinois at Urbana–Champaign

Two Key Challenges

1

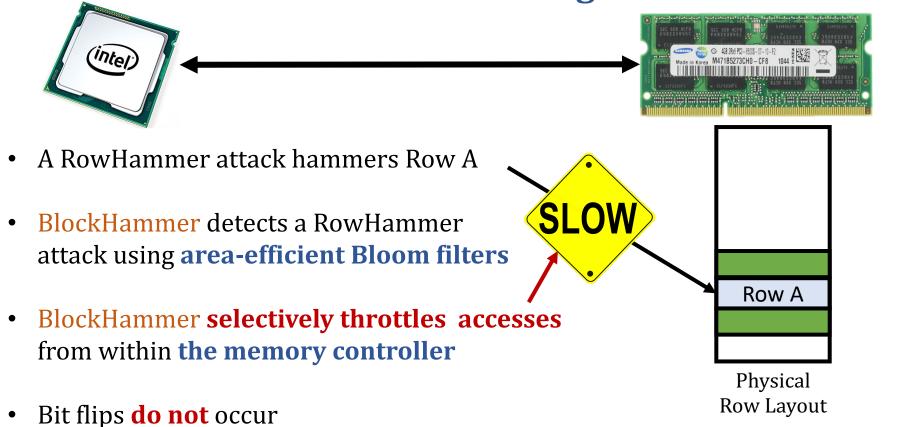
Scalability with worsening RowHammer vulnerability

2

Compatibility with commodity DRAM chips



BlockHammer: Practical Throttling-based Mechanism



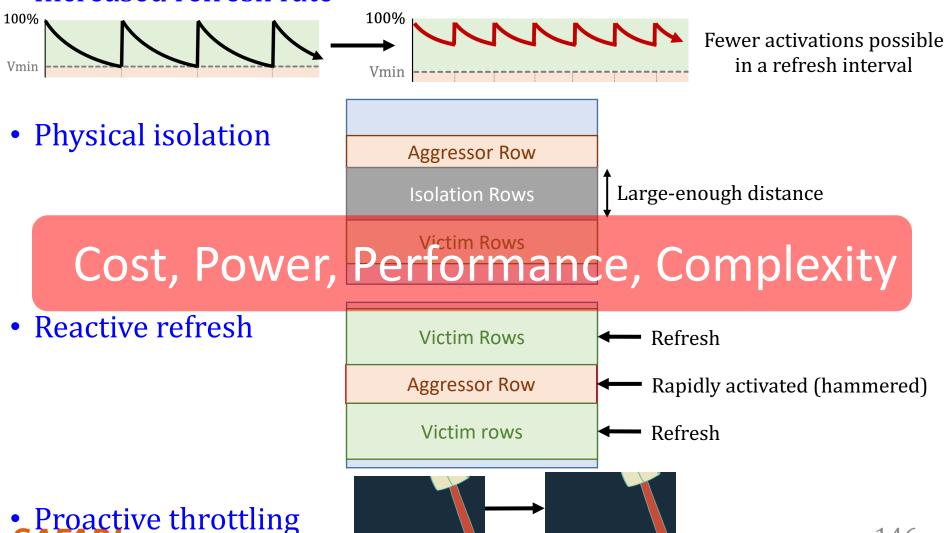
BlockHammer can optionally inform the system software about the attack

BlockHammer is compatible with commodity DRAM chips No need for proprietary info of or modifications to DRAM chips

Main Memory Needs Intelligent Controllers for Security, Safety, Reliability, Scaling

RowHammer Solution Approaches

- More robust DRAM chips and/or error-correcting codes
- Increased refresh rate



146

RowHammer in 2023: SK Hynix

ISSCC 2023 / SESSION 28 / HIGH-DENSITY MEMORIES

28.8 A 1.1V 16Gb DDR5 DRAM with Probabilistic-Aggressor Tracking, Refresh-Management Functionality, Per-Row Hammer Tracking, a Multi-Step Precharge, and Core-Bias Modulation for Security and Reliability Enhancement

Woongrae Kim, Chulmoon Jung, Seongnyuh Yoo, Duckhwa Hong, Jeongjin Hwang, Jungmin Yoon, Ohyong Jung, Joonwoo Choi, Sanga Hyun, Mankeun Kang, Sangho Lee, Dohong Kim, Sanghyun Ku, Donhyun Choi, Nogeun Joo, Sangwoo Yoon, Junseok Noh, Byeongyong Go, Cheolhoe Kim, Sunil Hwang, Mihyun Hwang, Seol-Min Yi, Hyungmin Kim, Sanghyuk Heo, Yeonsu Jang, Kyoungchul Jang, Shinho Chu, Yoonna Oh, Kwidong Kim, Junghyun Kim, Soohwan Kim, Jeongtae Hwang, Sangil Park, Junphyo Lee, Inchul Jeong, Joohwan Cho, Jonghwan Kim

SK hynix Semiconductor, Icheon, Korea

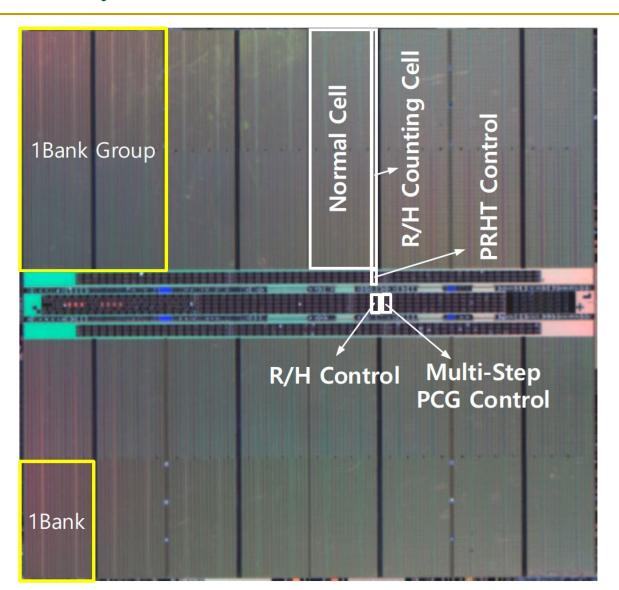


Industry's RowHammer Solutions (I)

SK hynix Semiconductor, Icheon, Korea

DRAM products have been recently adopted in a wide range of high-performance computing applications: such as in cloud computing, in big data systems, and IoT devices. This demand creates larger memory capacity requirements, thereby requiring aggressive DRAM technology node scaling to reduce the cost per bit [1,2]. However, DRAM manufacturers are facing technology scaling challenges due to row hammer and refresh retention time beyond 1a-nm [2]. Row hammer is a failure mechanism, where repeatedly activating a DRAM row disturbs data in adjacent rows. Scaling down severely threatens reliability since a reduction of DRAM cell size leads to a reduction in the intrinsic row hammer tolerance [2,3]. To improve row hammer tolerance, there is a need to probabilistically activate adjacent rows with carefully sampled active addresses and to improve intrinsic row hammer tolerance [2]. In this paper, row-hammer-protection and refresh-management schemes are presented to guarantee DRAM security and reliability despite the aggressive scaling from 1a-nm to sub 10-nm nodes. The probabilisticaggressor-tracking scheme with a refresh-management function (RFM) and per-row hammer tracking (PRHT) improve DRAM resilience. A multi-step precharge reinforces intrinsic row-hammer tolerance and a core-bias modulation improves retention time: even in the face of cell-transistor degradation due to technology scaling. This comprehensive scheme leads to a reduced probability of failure, due to row hammer attacks, by 93.1% and an improvement in retention time by 17%.

Industry's RowHammer Solutions (II)



ISSCC 2023 / SESSION 28 / HIGH-DENSITY MEMORIES

28.8 A 1.1V 16Gb DDR5 DRAM with Probabilistic-Aggressor Tracking, Refresh-Management Functionality, Per-Row Hammer Tracking, a Multi-Step Precharge, and Core-Bias Modulation for Security and Reliability Enhancement

Woongrae Kim, Chulmoon Jung, Seongnyuh Yoo, Duckhwa Hong, Jeongjin Hwang, Jungmin Yoon, Ohyong Jung, Joonwoo Choi, Sanga Hyun, Mankeun Kang, Sangho Lee, Dohong Kim, Sanghyun Ku, Donhyun Choi, Nogeun Joo, Sangwoo Yoon, Junseok Noh, Byeongyong Go, Cheolhoe Kim, Sunil Hwang, Mihyun Hwang, Seol-Min Yi, Hyungmin Kim, Sanghyuk Heo, Yeonsu Jang, Kyoungchul Jang, Shinho Chu, Yoonna Oh, Kwidong Kim, Junghyun Kim, Soohwan Kim, Jeongtae Hwang, Sangil Park, Junphyo Lee, Inchul Jeong, Joohwan Cho, Jonghwan Kim

149

SK hynix Semiconductor, Icheon, Korea

RowHammer in 2023: Samsung

DSAC: Low-Cost Rowhammer Mitigation Using In-DRAM Stochastic and Approximate Counting Algorithm

Seungki Hong Dongha Kim Jaehyung Lee Reum Oh Changsik Yoo Sangjoon Hwang Jooyoung Lee

DRAM Design Team, Memory Division, Samsung Electronics

https://arxiv.org/pdf/2302.03591v1.pdf

A Solution from Microsoft

Panopticon: A Complete In-DRAM Rowhammer Mitigation

Tanj Bennett[§], Stefan Saroiu, Alec Wolman, and Lucian Cojocar Microsoft, [§]Avant-Gray LLC

https://stefan.t8k2.com/publications/dramsec/2021/panopticon.pdf

Solutions in JEDEC (2024)



Version 1.30

This standard defines the DDR5 SDRAM specification, including features, functionalities, AC and DC characteristics, packages, and ball/signal assignments. The purpose of this Standard is to define the minimum set of requirements for JEDEC compliant 8 Gb through 32 Gb for x4, x8, and x16 DDR5 SDRAM devices. This standard was created based on the DDR4 standards (JESD79-4) and some aspects of the DDR, DDR2, DDR3, and LPDDR4 standards (JESD79, JESD79-2, JESD79-3, and JESD209-4).

Committee(s): JC-42, JC-42.3

Evaluation of Industry's Recent Solutions

Appears at DRAMSec 2024

Understanding the Security Benefits and Overheads of Emerging Industry Solutions to DRAM Read Disturbance

```
Oğuzhan Canpolat<sup>§†</sup> A. Giray Yağlıkçı<sup>§</sup> Geraldo F. Oliveira<sup>§</sup> Ataberk Olgun<sup>§</sup> Oğuz Ergin<sup>†</sup> Onur Mutlu<sup>§</sup> † TOBB University of Economics and Technology
```

https://arxiv.org/pdf/2406.19094 https://github.com/CMU-SAFARI/ramulator2

SAFARI 153

Are we now RowHammer-free in 2024 and Beyond?

Are We Now BitFlip Free?

Appeared at ISCA in June 2023

What if there is another phenomenon that does NOT require high row activation count?

RowPress: Amplifying Read-Disturbance in Modern DRAM Chips

Haocong Luo Ataberk Olgun A. Giray Yağlıkçı Yahya Can Tuğrul Steve Rhyner Meryem Banu Cavlak Joël Lindegger Mohammad Sadrosadati Onur Mutlu

ETH Zürich

https://arxiv.org/pdf/2306.17061.pdf

RowPress

RowPress [ISCA 2023]







Haocong Luo, Ataberk Olgun, Giray Yaglikci, Yahya Can Tugrul, Steve Rhyner,
 M. Banu Cavlak, Joel Lindegger, Mohammad Sadrosadati, and Onur Mutlu,
 "RowPress: Amplifying Read Disturbance in Modern DRAM Chips"

Proceedings of the <u>50th International Symposium on Computer</u> <u>Architecture</u> (**ISCA**), Orlando, FL, USA, June 2023.

[Slides (pptx) (pdf)]

[Lightning Talk Slides (pptx) (pdf)]

[<u>Lightning Talk Video</u> (3 minutes)]

[RowPress Source Code and Datasets (Officially Artifact Evaluated with All Badges)]

Officially artifact evaluated as available, reusable and reproducible. Best artifact award at ISCA 2023. IEEE Micro Top Pick in 2024.

RowPress: Amplifying Read-Disturbance in Modern DRAM Chips

Haocong Luo Ataberk Olgun A. Giray Yağlıkçı Yahya Can Tuğrul Steve Rhyner Meryem Banu Cavlak Joël Lindegger Mohammad Sadrosadati Onur Mutlu

ETH Zürich







RowPress

Amplifying Read Disturbance in Modern DRAM Chips

ISCA 2023 Session 2B: Monday 19 June, 2:15 PM EDT

Haocong Luo

Ataberk Olgun

A. Giray Yağlıkçı Yahya Can Tuğrul Steve Rhyner Meryem Banu Cavlak Joël Lindegger Mohammad Sadrosadati Onur Mutlu





High-Level Summary

- We demonstrate and analyze RowPress, a new read disturbance phenomenon that causes bitflips in real DRAM chips
- We show that RowPress is different from the RowHammer vulnerability
- We demonstrate RowPress using a user-level program on a real Intel system with real DRAM chips

We provide effective solutions to RowPress

What is RowPress?

Keeping a DRAM row **open for a long time** causes bitflips in adjacent rows

These bitflips do NOT require many row activations

Only one activation is enough in some cases!



Now, let's delve into some background and see how this is **different from RowHammer**



Are There Other Read-Disturb Issues in DRAM?

- RowHammer is the only studied read-disturb phenomenon
- Mitigations work by detecting high row activation count

What if there is another read-disturb phenomenon that does NOT rely on high row activation count?

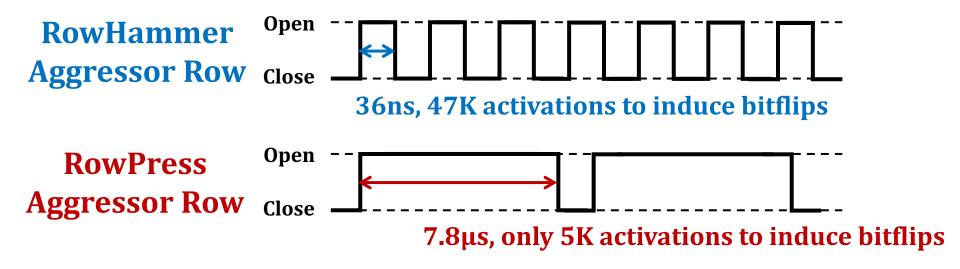


https://www.reddit.com/r/CrappyDesign/comments/arw0q8/now_this_this_is_poor_fencing/



RowPress vs. RowHammer

Instead of using a high activation count, increase the time that the aggressor row stays open



We observe bitflips even with **ONLY ONE activation** in extreme cases where the row stays open for 30ms

Real DRAM Chip Characterization (I)

FPGA-Based DDR4 Testing Infrastructure

- Based on SoftMC [Hassan+, HPCA'17] and DRAM Bender [Olgun+, TCAD'23]
- Fine-grained control over DRAM commands, timings, and temperature



Real DRAM Chip Characterization (II)

DRAM chips tested

- 164 DDR4 chips from all 3 major DRAM manufacturers
- Covers different die densities and revisions

Mfr.	#DIMMs	#Chips	Density	Die Rev.	Org.	Date
Mfr. S (Samsung)	2	8	8Gb	В	x8	20-53
	1	8	8Gb	С	x8	N/A
	3	8	8Gb	D	x8	21-10
	2	8	4Gb	F	x8	N/A
Mfr. H (SK Hynix)	1	8	4Gb	А	x8	19-46
	1	8	4Gb	X	x8	N/A
	2	8	16Gb	A	x8	20-51
	2	8	16Gb	С	x8	21-36
Mfr. M (Micron)	1	16	8Gb	В	x4	N/A
	2	4	16Gb	В	x16	21-26
	1	16	16Gb	E	x4	20-14
	2	4	16Gb	Е	x16	20-46
	1	4	16Gb	F	x16	21-50



Major Takeaways from Real DRAM Chips

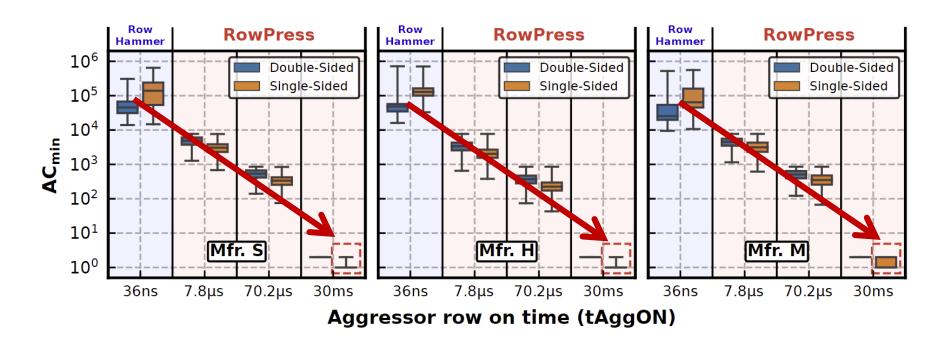
RowPress significantly **amplifies**DRAM's vulnerability to read disturbance

RowPress has a different underlying error mechanism from RowHammer

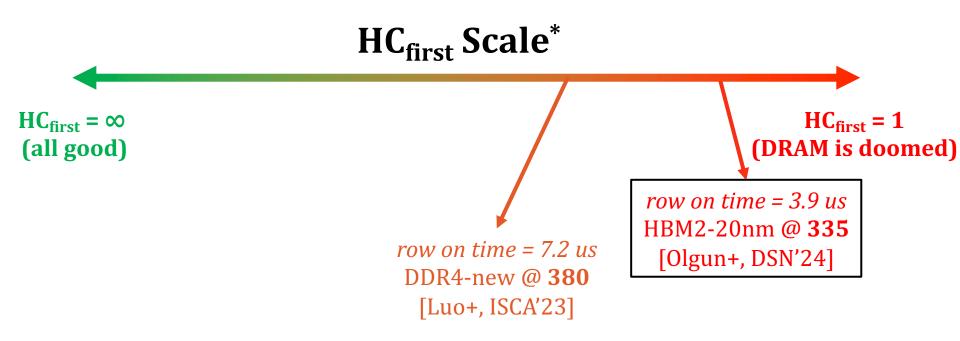
Key Characteristics of RowPress (I)

Amplifying Read Disturbance in DRAM

- Reduces the minimum number of row activations needed to induce a bitflip (ACmin) by 1-2 orders of magnitude
- In extreme cases, activating a row only once induces bitflips



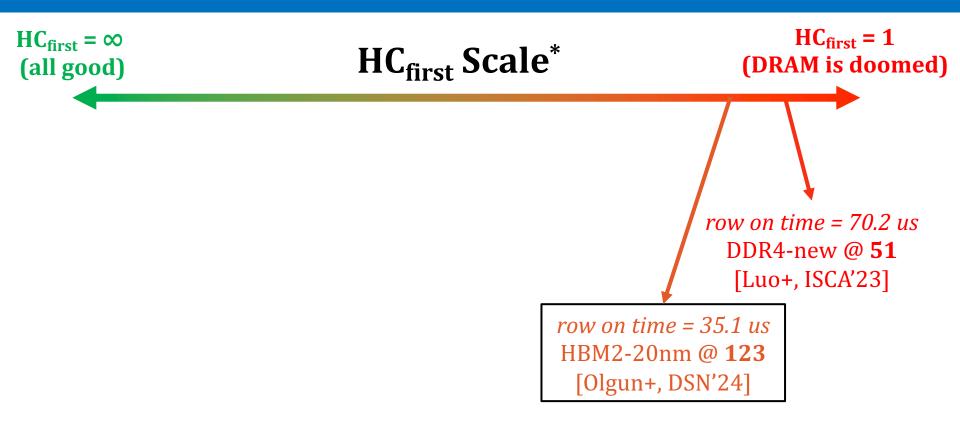
RowPress at t_{AggON} = Refresh Interval



*Not shown: Significant variance in HC_{first} across vendors and die variations



RowPress at $t_{AggON} = 9 * Refresh Interval$



*Not shown: Significant variance in HC_{first} across vendors and die variations



Key Characteristics of RowPress (II)

Amplifying Read Disturbance in DRAM

- Reduces the minimum number of row activations needed to induce a bitflip (ACmin) by 1-2 orders of magnitude
- In extreme cases, activating a row only once induces bitflips
- Gets worse as temperature increases

Different From RowHammer

- Affects a different set of cells compared to RowHammer and retention failures
- Behaves differently as access pattern and temperature changes compared to RowHammer

Real-System Demonstration (I)



Intel Core i5-10400 (Comet Lake)



Samsung DDR4 Module M378A2K43CB1-CTD (Date Code: 20-10)

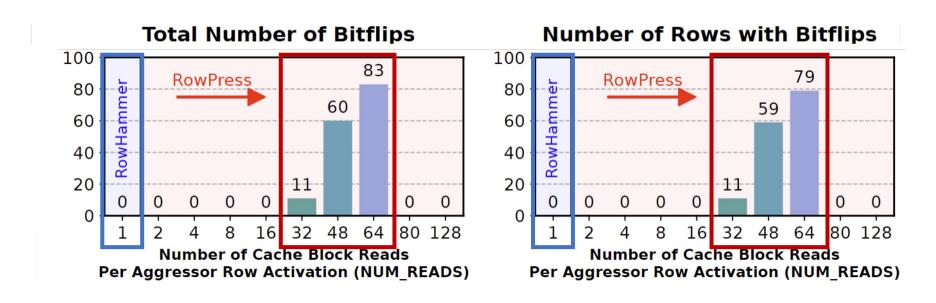
w/ TRR RowHammer Mitigation

Key Idea: A proof-of-concept RowPress program keeps a DRAM row open for a longer period by **keeping on accessing different cache blocks in the row**

```
// Sync with Refresh and Loop Below for (k = 0; k < NUM_AGGR_ACTS; k++) for (j = 0; j < NUM_READS j++) *AGGRESSOR1[j]; for (j = 0; j < NUM_READS j++) *AGGRESSOR2[j]; for (j = 0; j < NUM_READS j++) *AGGRESSOR2[j]; Per Aggressor Row ACT (NUM_READS=1 is Rowhammer) clflushopt(AGGRESSOR2[j]); mfence(); activate_dummy_rows();
```

Real-System Demonstration (II)

On 1500 victim rows



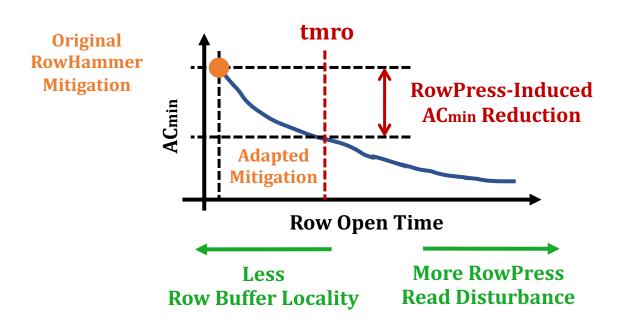
Leveraging RowPress, our user-level program induces bitflips when RowHammer cannot

Mitigating RowPress (I)

We propose a methodology to adapt existing RowHammer mitigations to also mitigate RowPress

Key Idea:

- Limit the maximum row open time (tmro)
- Configure the RowHammer mitigation to account for the RowPress-induced reduction in ACmin



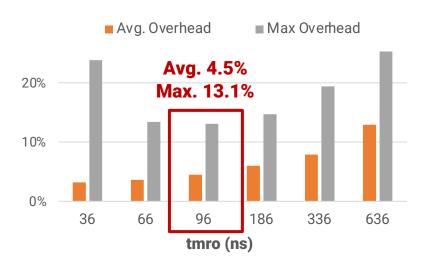
Mitigating RowPress (II)

Key evaluation results

Additional Performance Overhead of Graphene-RP



Additional Performance Overhead of PARA-RP



Our solutions mitigate RowPress at low additional performance overhead

More Results & Source Code

Many more results & analyses in the paper

- ➤ 6 major takeaways
- > 19 major empirical observations
- > 3 more potential mitigations



Fully open source and artifact evaluated

https://github.com/CMU-SAFARI/RowPress









RowPress [ISCA 2023]





Haocong Luo, Ataberk Olgun, Giray Yaglikci, Yahya Can Tugrul, Steve Rhyner,
 M. Banu Cavlak, Joel Lindegger, Mohammad Sadrosadati, and Onur Mutlu,
 "RowPress: Amplifying Read Disturbance in Modern DRAM Chips"

Proceedings of the <u>50th International Symposium on Computer</u> <u>Architecture</u> (**ISCA**), Orlando, FL, USA, June 2023.

[Slides (pptx) (pdf)]

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[RowPress Source Code and Datasets (Officially Artifact Evaluated with All Badges)]

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RowPress: Amplifying Read-Disturbance in Modern DRAM Chips

Haocong Luo Ataberk Olgun A. Giray Yağlıkçı Yahya Can Tuğrul Steve Rhyner Meryem Banu Cavlak Joël Lindegger Mohammad Sadrosadati Onur Mutlu

ETH Zürich

More to Come...

Two Major Directions

Understanding Bitflips (Hardware errors in general)

- Many effects on bitflips still need to be rigorously examined
 - Aging of DRAM Chips
 - Environmental Conditions (e.g., Process, Voltage, Temperature)
 - Memory Access Patterns
 - Memory Controller & System Design Decisions
 - **...**

Solving Bitflips (Hardware errors in general)

- Flexible and efficient solutions are necessary
 - In-field patchable / reconfigurable / programmable solutions
- Co-architecting across the system stack/components is important
 - To avoid performance and denial-of-service problems

A RowHammer Survey: Recent Update

Onur Mutlu, Ataberk Olgun, and A. Giray Yaglikci,
 "Fundamentally Understanding and Solving RowHammer"
 Invited Special Session Paper at the <u>28th Asia and South Pacific Design Automation Conference (ASP-DAC)</u>, Tokyo, Japan, January 2023.
 [arXiv version]
 [Slides (pptx) (pdf)]

[<u>Talk Video</u> (26 minutes)]

Fundamentally Understanding and Solving RowHammer

Onur Mutlu
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Zürich, Switzerland

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https://arxiv.org/pdf/2211.07613.pdf

178

Combining RowHammer and RowPress

Appears at DSN Disrupt 2024

An Experimental Characterization of Combined RowHammer and RowPress Read Disturbance in Modern DRAM Chips

Haocong Luo İsmail Emir Yüksel Ataberk Olgun A. Giray Yağlıkçı Mohammad Sadrosadati Onur Mutlu ETH Zürich

Better Communication Between DRAM & Controller

A Case for Transparent Reliability in DRAM Systems

```
Minesh Patel<sup>†</sup> Taha Shahroodi<sup>‡†</sup> Aditya Manglik<sup>†</sup> A. Giray Yağlıkçı<sup>†</sup> Ataberk Olgun<sup>†</sup> Haocong Luo<sup>†</sup> Onur Mutlu<sup>†</sup> ^{\dagger}ETH \ Z \ddot{u} rich \ ^{\ddagger}TU \ Delft
```

https://arxiv.org/pdf/2204.10378.pdf

Better Partitioning of DRAM & Controller

A Case for Self-Managing DRAM Chips: Improving Performance, Efficiency, Reliability, and Security via Autonomous in-DRAM Maintenance Operations

Hasan Hassan

Ataberk Olgun

A. Giray Yağlıkçı

Haocong Luo

Onur Mutlu

ETH Zürich

https://arxiv.org/pdf/2207.13358.pdf

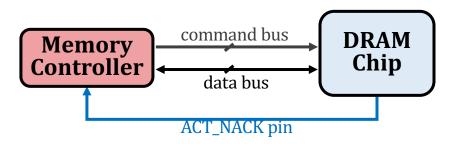
Self-Managing DRAM: Overview

Self-Managing DRAM (SMD)

enables autonomous in-DRAM maintenance operations

Key Idea:

Prevent the memory controller from accessing DRAM regions that are under maintenance by rejecting row activation (ACT) commands



Leveraging the ability to *reject an ACT*, a maintenance operation can be implemented *completely* within a DRAM chip

SMD-Based Maintenance Mechanisms

DRAM Refresh

Fixed Rate (SMD-FR)

uniformly refreshes all DRAM rows
with a fixed refresh period

Variable Rate (SMD-VR)

skips refreshing rows that can **retain their data for longer** than the default refresh period

RowHammer Protection

Probabilistic (SMD-PRP)

Performs **neighbor row refresh**with **a small probability**on every row activation

Deterministic (SMD-DRP)

keeps track of most frequently activated rows and performs neighbor row refresh when activation count threshold is exceeded

Memory Scrubbing

Periodic Scrubbing (SMD-MS)

periodically **scans** the **entire** DRAM for errors and corrects them

Self-Managing DRAM: Summary

The three major DRAM maintenance operations:

- *Refresh
- **❖** RowHammer Protection
- Memory Scrubbing

Implementing new maintenance mechanisms often requires difficult-to-realize changes

Our Goal

- 1 Ease the process of enabling new DRAM maintenance operations
- 2 Enable more efficient in-DRAM maintenance operations

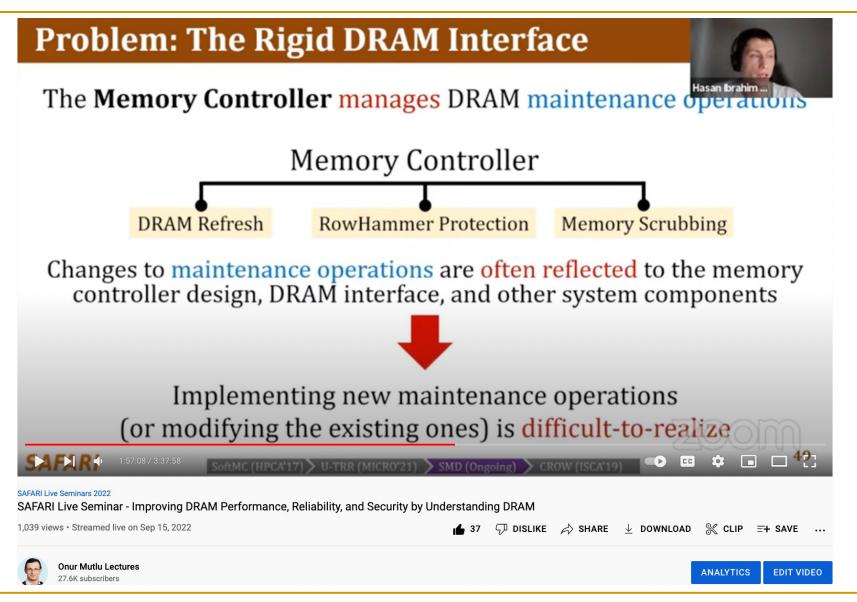
Self-Managing DRAM (SMD)

Enables implementing new **in-DRAM** maintenance mechanisms with **no further changes** in the *DRAM interface* and *memory controller*

SMD-based *refresh*, *RowHammer protection*, and *scrubbing* achieve **9.2% speedup** and **6.2% lower DRAM energy** vs. conventional DRAM



Talk on Self-Managing DRAM



ABACuS: Another Intelligent Memory Controller

 Ataberk Olgun, Yahya Can Tugrul, Nisa Bostanci, Ismail Emir Yuksel, Haocong Luo, Steve Rhyner, Abdullah Giray Yaglikci, Geraldo F. Oliveira, and Onur Mutlu,

"ABACuS: All-Bank Activation Counters for Scalable and Low Overhead RowHammer Mitigation"

To appear in Proceedings of the <u>33rd USENIX Security</u> <u>Symposium</u> (**USENIX Security**), Philadelphia, PA, USA, August 2024.

[arXiv version]

[ABACuS Source Code]

ABACuS: All-Bank Activation Counters for Scalable and Low Overhead RowHammer Mitigation

Ataberk Olgun Yahya Can Tugrul Nisa Bostanci Ismail Emir Yuksel Haocong Luo Steve Rhyner Abdullah Giray Yaglikci Geraldo F. Oliveira Onur Mutlu

ETH Zurich

CoMeT: Another Intelligent Memory Controller

Appears at HPCA 2024

CoMeT: Count-Min-Sketch-based Row Tracking to Mitigate RowHammer at Low Cost

F. Nisa Bostanci Yahya Can Tuğrul İsmail Emir Yüksel A. Giray Yağlıkçı Ataberk Olgun

Konstantinos Kanellopoulos Mohammad Sadrosadati Onur Mutlu

ETH Zürich

https://arxiv.org/pdf/2402.18769

https://github.com/CMU-SAFARI/CoMeT

SVaRD: Another Intelligent Memory Controller

Appears at HPCA 2024

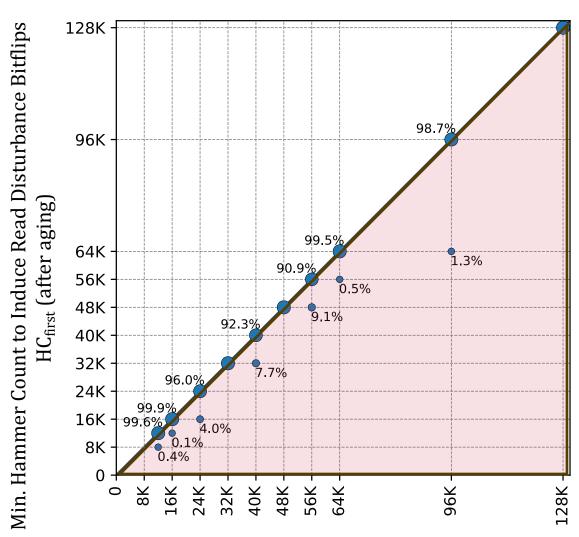
Spatial Variation-Aware Read Disturbance Defenses: Experimental Analysis of Real DRAM Chips and Implications on Future Solutions

Abdullah Giray Yağlıkçı Yahya Can Tuğrul Geraldo F. Oliveira İsmail Emir Yüksel Ataberk Olgun Haocong Luo Onur Mutlu ETH Zürich

https://arxiv.org/pdf/2402.18652

Effect of Aging on RowHammer BitFlips

Aging can lead to
RowHammer
bitflips
at smaller
hammer counts



Min. Hammer Count to Induce Read Disturbance Bitflips HC_{first} (before aging)

RowHammer Defenses Can Cause Denial of Service

Leveraging Adversarial Detection to Enable Scalable and Low Overhead RowHammer Mitigations

Oğuzhan Canpolat^{§†} A. Giray Yağlıkçı[§] Ataberk Olgun[§] İsmail Emir Yüksel[§] Yahya Can Tuğrul^{§†} Konstantinos Kanellopoulos[§] Oğuz Ergin[†] Onur Mutlu[§] [†]TOBB University of Economics and Technology *SAFARI Research Group

https://arxiv.org/pdf/2404.13477

BreakHammer

- <u>Key Observation</u>: Mitigating DRAM read disturbance causes delays in memory accesses
- **Our Exploit**: Denial of memory service is possible via triggering mitigation mechanisms
- <u>Key Idea</u>: Throttling memory accesses of threads that trigger mitigation mechanisms repeatedly

BreakHammer:

- Detects the threads that repeatedly trigger the mitigation mechanisms
- Limits their on-the-fly memory request counts and MSHRs
- Near-zero area overhead and no additional memory access latency

• **Evaluation**:

- Improves system performance by 48.7% on average (105.5% max)
- Reduces the maximum slowdown by 14.6% on average



Industry's Recent Solutions Are Vulnerable

Appears at DRAMSec 2024

Understanding the Security Benefits and Overheads of Emerging Industry Solutions to DRAM Read Disturbance

```
Oğuzhan Canpolat<sup>§†</sup> A. Giray Yağlıkçı<sup>§</sup> Geraldo F. Oliveira<sup>§</sup> Ataberk Olgun<sup>§</sup> Oğuz Ergin<sup>†</sup> Onur Mutlu<sup>§</sup> † TOBB University of Economics and Technology
```

https://arxiv.org/pdf/2406.19094

https://github.com/CMU-SAFARI/ramulator2

Some RowHammer Works in 2024



Session 5B: Rowhammer

Location: Sidlaw Session Chair: TBD

10:00 AM-10:20 AM

Spatial Variation-Aware Read Disturbance **Defenses: Experimental Analysis of Real DRAM Chips and Implications on Future Solutions**

Abdullah Giray Yaglikci, Geraldo Francisco de Oliveira Junior, Yahya Can Tugrul, Ismail Yuksel, Ataberk Olgun, Haocong Luo, Onur Mutlu

10:20 AM-10:40 AM

START: Scalable Tracking for Any Rowhammer Threshold

Anish Saxena, Moinuddin Qureshi

10:40 AM - 11:00 AM

CoMeT: Count-Min Sketch-based Row Tracking to Mitigate RowHammer with Low Cost

Nisa Bostanci, Ismail Emir Yuksel, Ataberk Olgun, Konstantinos Kanellopoulos, Yahya Can Tuğrul, Giray Yaglikci, Mohammad Sadrosadati, Onur Mutlu



PrIDE: Achieving Secure Rowhammer Mitigation with Low-Cost In-DRAM Trackers

ABACuS: All-Bank Activation Counters for Scalable and Low Overhead RowHammer Mitigation

Ataberk Olgun, Yahya Can Tugrul, Nisa Bostanci, Ismail Emir Yuksel, Haocong Luo, Steve Rhyner, A Zurich Track 2

Go Go Gadget Hammer: Flipping Nested Pointers for Arbitrary Data Leakage Youssef Tobah, University of Michigan; Andrew Kwong, UNC Chapel Hill; Ingab Kans

Michigan

SledgeHammer: Amplifying Rowhammer via Bank-level Parallelism

Ingab Kang, University of Michigan; Walter Wang and Jason Kim, Georgia Tech; Step Tech; Andrew Kwong, UNC Chapel Hill; Yuval Yarom, Ruhr University Bochum

ZenHammer: Rowhammer Attacks on AMD Zen-based Platforms

Patrick Jattke, Max Wipfli, Flavien Solt, Michele Marazzi, Matej Bölcskei,



Rubix: Reducing the Overhead of Secure Rowhammer Mitigations via Randomized Line-to-Row Mapping

TAROT: A CXL SmartNIC-Based **Defense Against Multi-bit Errors by Row-Hammer Attacks**



Show details >

Side Channel II:

RowHammer

Read Disturbance in High Bandwidth Memory: A by Ataberk Olgun, Majd Osseiran, Giray Yaglikci, Salami, Juan Gómez Luna, Onur Mutlu

An Experimental Analysis of Combined RowHammer and RowPress Chips by Haocong Luo, Ismail Emir Yüksel, Ataberk Olgun, Giray Yaglik Mutlu



Understanding the Physical Mechanism of RowPress at the— Device-Level in Sub-20 nm DRAM

SAFARI

Some RowHammer Works in 2024 (II)

Fourth Workshop on DRAM Security (DRAMSec) June 29, 2024, co-located with ISCA 2024

RISC-H: Rowhammer Attacks on RISC-V

Michele Marazzi, Kaveh Razavi

Paper

GbHammer: Malicious Inter-process Page Sharing by Hammering Global Bits in Page Table Entries

Keigo Yoshioka, Soramichi Akiyama

Paper

Understanding the Security Benefits and Overheads of Emerging Industry Solutions to DRAM Read Disturbance

Oğuzhan Canpolat, Giray Yaglikci, Geraldo Francisco de Oliveira Junior, Ataberk Olgun, Oguz Ergin, Onur Mutlu

SoothSayer: Bypassing DSAC Mitigation by Predicting Counter Replacement Salman Qazi, Daniel Moghimi
Paper

Six Years of Rowhammer: Breakthroughs and Future Directions

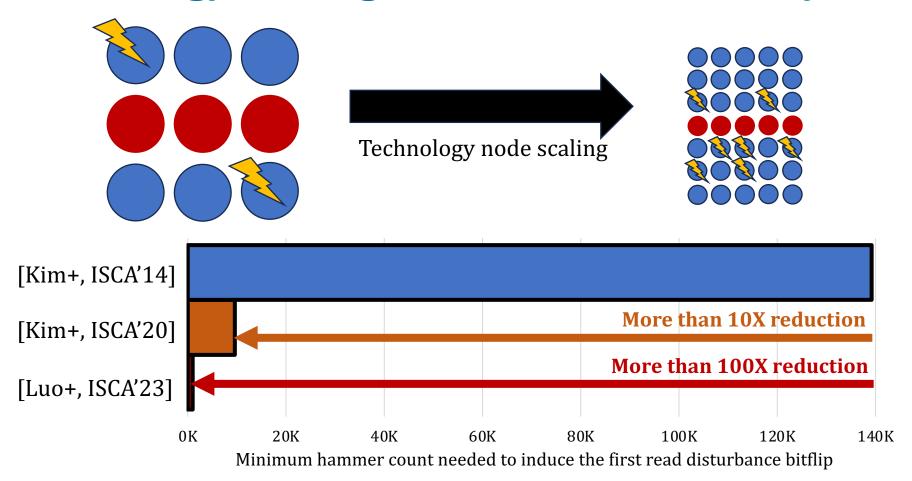
Stefan Saroiu Microsoft Research

This talk will present the work done over the past six years as part of Project STEMA at Microsoft. STEMA stands for Secure, Trusted, and Enhanced Memory for Azure. We will discuss our journey in understanding Rowhammer, developing a testing methodology for cloud providers, and finding effective solutions for the DRAM industry to address Rowhammer once and for all. We will also highlight significant related work that has helped keep the DRAM industry honest. We will explain why Rowhammer remains a significant attack vector, particularly in the context of nation-state attacks, and how this has driven us to develop a suite of pragmatic solutions. Finally, we will argue that Rowhammer is far from being a solved problem and outline several important research challenges that remain in this space.



Future Memory Robustness Challenges

Technology Scaling Worsens Vulnerability



DRAM cells become increasingly more vulnerable (to read disturbance)



Future of Main Memory Robustness

- DRAM is becoming less reliable → more vulnerable
- Due to difficulties in DRAM scaling, other problems may also appear (or they may be going unnoticed)
- Some errors may already be slipping into the field
 - Read disturb errors (Rowhammer)
 - Retention errors
 - Read errors, write errors
 - ...
- These errors can also pose security vulnerabilities

Future of Main Memory Robustness

- DRAM
- Flash memory
- Emerging Technologies
 - Phase Change Memory
 - STT-MRAM
 - RRAM, memristors
 - **...**

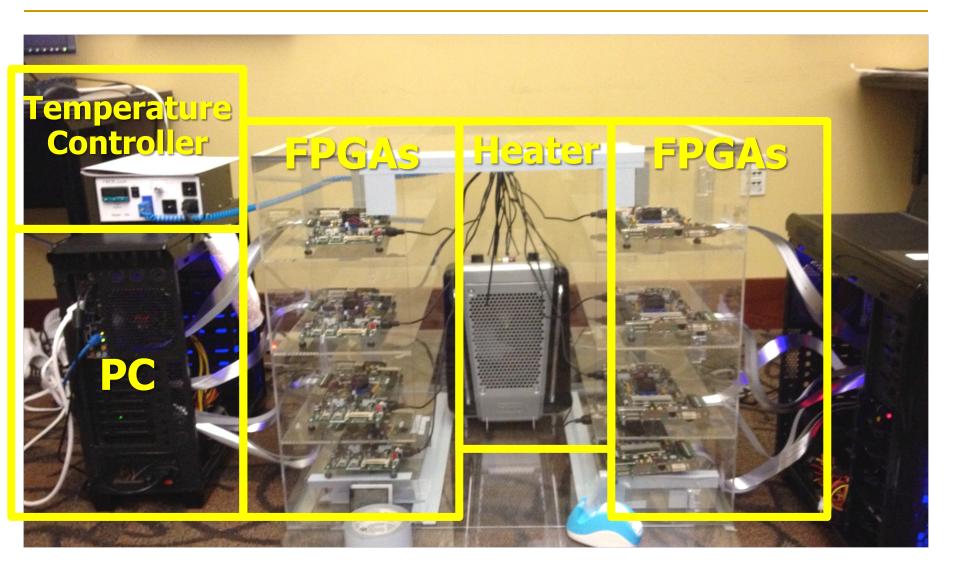
Architecting Robust Memory Systems

- Understand: Methods for vulnerability modeling & discovery
 - Modeling and prediction based on real (device) data and analysis

- Architect: Principled architectures with security as key concern
 - Good partitioning of duties across the stack
 - Cannot give up performance and efficiency
 - Patch-ability in the field

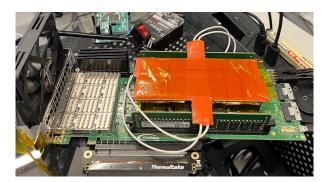
- Design & Test: Principled design, automation, (online) testing
 - Design for security/safety/reliability
 - High coverage and good interaction with system reliability methods

Understand and Model with Experiments (DRAM)

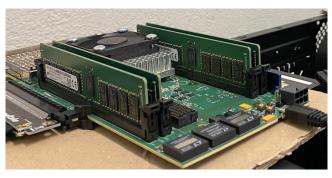


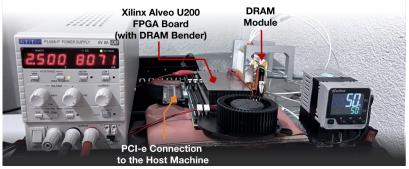
Understand and Model with Experiments (DRAM)

Five out of the box FPGA-based prototypes



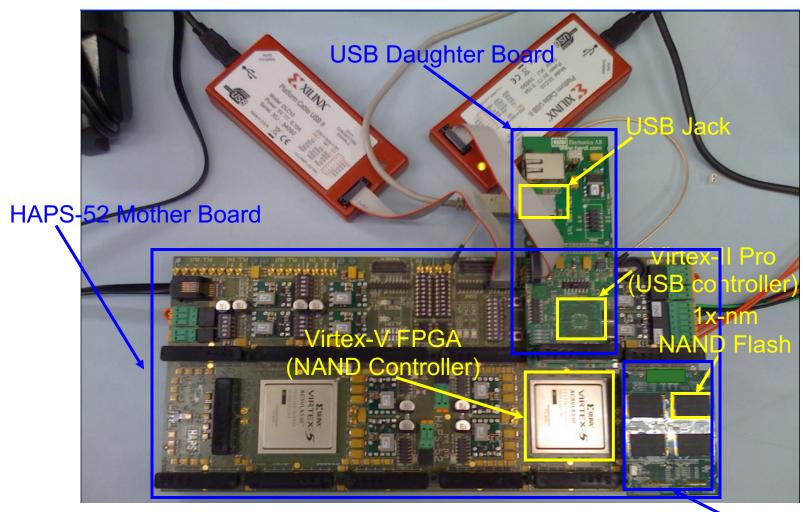








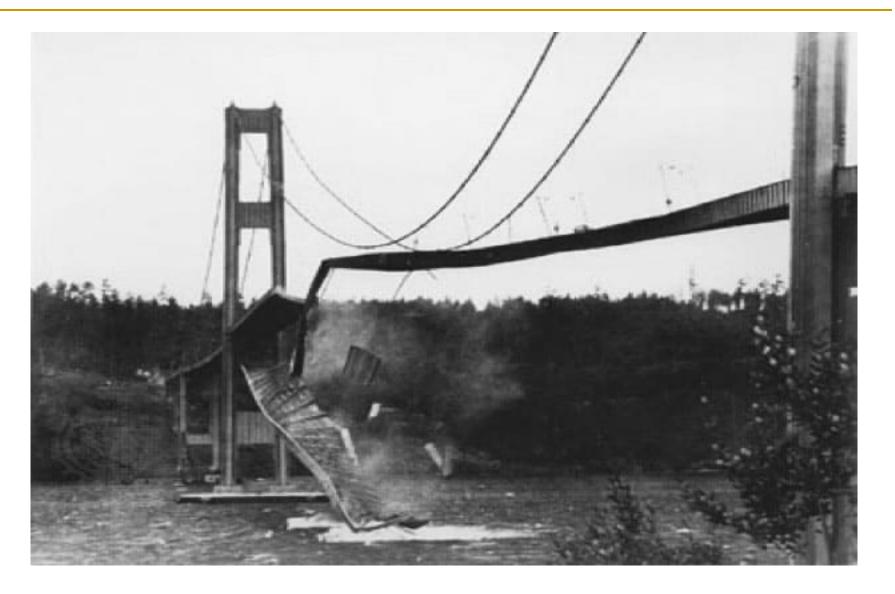
Understand and Model with Experiments (Flash)



[DATE 2012, ICCD 2012, DATE 2013, ITJ 2013, ICCD 2013, SIGMETRICS 2014, HPCA 2015, DSN 2015, MSST 2015, JSAC 2016, HPCA 2017, DFRWS 2017, PIEEE 2017, HPCA 2018, SIGMETRICS 2018]

NAND Daughter Board

Collapse of the "Galloping Gertie" (1940)



Another Example (1994)



Yet Another Example (2007)



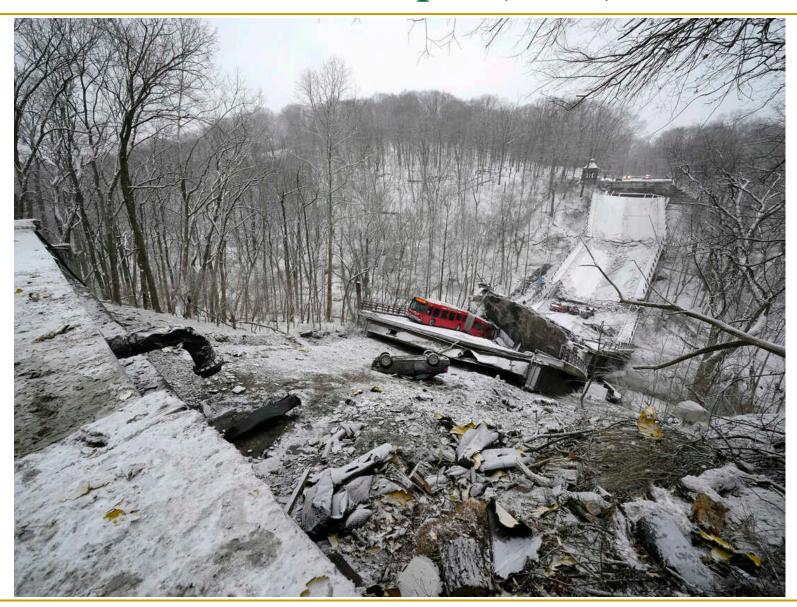
A More Recent Example (2018)











Intelligent Memory Controllers Can Avoid Such Failures

Main Memory Needs Intelligent Controllers for Security, Safety, Reliability, Scaling

Challenge and Opportunity for Future

Fundamentally Robust (Reliable, Secure, Safe) Computing Architectures

Final Thoughts on RowHammer

Aside: Byzantine Failures

- This class of failures is known as Byzantine failures
- Characterized by
 - Undetected erroneous computation
 - Opposite of "fail fast (with an error or no result)"
- "erroneous" can be "malicious" (intent is the only distinction)
- Very difficult to detect and confine Byzantine failures
- Do all you can to avoid them
- Lamport et al., "The Byzantine Generals Problem," ACM TOPLAS 1982.

Aside: Byzantine Generals Problem

The Byzantine Generals Problem

LESLIE LAMPORT, ROBERT SHOSTAK, and MARSHALL PEASE SRI International

Reliable computer systems must handle malfunctioning components that give conflicting information to different parts of the system. This situation can be expressed abstractly in terms of a group of generals of the Byzantine army camped with their troops around an enemy city. Communicating only by messenger, the generals must agree upon a common battle plan. However, one or more of them may be traitors who will try to confuse the others. The problem is to find an algorithm to ensure that the loyal generals will reach agreement. It is shown that, using only oral messages, this problem is solvable if and only if more than two-thirds of the generals are loyal; so a single traitor can confound two loyal generals. With unforgeable written messages, the problem is solvable for any number of generals and possible traitors. Applications of the solutions to reliable computer systems are then discussed.

Categories and Subject Descriptors: C.2.4. [Computer-Communication Networks]: Distributed Systems—network operating systems; D.4.4 [Operating Systems]: Communications Management—network communication; D.4.5 [Operating Systems]: Reliability—fault tolerance

General Terms: Algorithms, Reliability

Additional Key Words and Phrases: Interactive consistency

ACM TOPLAS 1982

Before RowHammer (I)

Using Memory Errors to Attack a Virtual Machine

Sudhakar Govindavajhala * Andrew W. Appel Princeton University {sudhakar,appel}@cs.princeton.edu

We present an experimental study showing that soft memory errors can lead to serious security vulnerabilities in Java and .NET virtual machines, or in any system that relies on type-checking of untrusted programs as a protection mechanism. Our attack works by sending to the JVM a Java program that is designed so that almost any memory error in its address space will allow it to take control of the JVM. All conventional Java and .NET virtual machines are vulnerable to this attack. The technique of the attack is broadly applicable against other language-based security schemes such as proof-carrying code.

We measured the attack on two commercial Java Virtual Machines: Sun's and IBM's. We show that a single-bit error in the Java program's data space can be exploited to execute arbitrary code with a probability of about 70%, and multiple-bit errors with a lower probability.

Our attack is particularly relevant against smart cards or tamper-resistant computers, where the user has physical access (to the outside of the computer) and can use various means to induce faults; we have successfully used heat. Fortunately, there are some straightforward defenses against this attack.

7 Physical fault injection

If the attacker has physical access to the outside of the machine, as in the case of a smart card or other tamper-resistant computer, the attacker can induce memory errors. We considered attacks on boxes in form factors ranging from a credit card to a palmtop to a desktop PC.

We considered several ways in which the attacker could induce errors.⁴

IEEE S&P 2003

Before RowHammer (II)

Using Memory Errors to Attack a Virtual Machine

Sudhakar Govindavajhala * Andrew W. Appel
Princeton University
{sudhakar,appel}@cs.princeton.edu



Figure 3. Experimental setup to induce memory errors, showing a PC built from surplus components, clip-on gooseneck lamp, 50-watt spotlight bulb, and digital thermometer. Not shown is the variable AC power supply for the lamp.

IEEE S&P 2003

After RowHammer

A simple, exploitable memory error can be induced by software



Forget Software—Now Hackers Are Exploiting Physics

BUSINESS CULTURE DESIGN GEAR SCIENCE

SHARE





ANDY GREENBERG SECURITY 08.31.16 7:00 AM

FORGET SOFTWARE—NOW HACKERS ARE EXPLOITING PHYSICS

After RowHammer

A simple, exploitable memory error can be induced by software



SON OF ROWHAMMER

There's a new way to flip bits in DRAM, and it works against the latest defenses

New technique produces lots of bitflips and could one day help form an attack.

DAN GOODIN - 10/19/2023, 5:30 AM

01001000100101001000010010011110110110011011100100

RowHammer: Retrospective

- New mindset that has enabled a renewed interest in HW security attack research:
 - □ Real (memory) chips are vulnerable, in a simple and widespread manner
 → this causes real security problems
 - □ Hardware reliability → security connection is now mainstream discourse
- Many new RowHammer & bitflip attacks...
 - Tens of papers in top security, architecture, systems venues
 - More to come as RowHammer is getting worse (DDR4 & beyond)
- Many new RowHammer solutions...
 - Apple security release; Memtest86 updated
 - Many solution proposals in top venues (latest in HPCA/Usenix Sec 2024)
 - Principled system-DRAM co-design (in original RowHammer paper)
 - More to come...

Perhaps Most Importantly...

- RowHammer enabled a shift of mindset in mainstream security researchers
 - General-purpose hardware is fallible, in a widespread manner
 - Its problems are exploitable
- This mindset has enabled many systems security researchers to examine hardware in more depth
 - And understand HW's inner workings and vulnerabilities
- It is no coincidence that two of the groups that discovered Meltdown and Spectre heavily worked on RowHammer attacks before
 - More to come...

Conclusion

Summary: RowHammer

- Memory reliability is reducing
- Reliability issues open up security and safety vulnerabilities
 - Very hard to defend against
- Rowhammer is a prime example
 - First example of how a simple hardware failure mechanism can create
 a widespread system security vulnerability
 - Implications on system security & safety are tremendous & exciting
- Bad news: RowHammer is getting worse
- Good news: We have a lot more to do
 - We are now fully aware hardware is easily fallible
 - We are developing both attacks and defenses
 - We are developing principled models, methodologies, solutions

SAFARI

Data Corruption in Logic

Data Corruption is in Logic, Too

- Intermittent defects can cause silent data corruption
- They may be hard to detect or replicate
- They may be exploitable

Silent Data Corruption in Logic (2021)

Silent Data Corruptions at Scale

Harish Dattatraya Dixit Facebook, Inc. hdd@fb.com Sneha Pendharkar Facebook, Inc. spendharkar@fb.com

Matt Beadon Facebook, Inc. mbeadon@fb.com Chris Mason Facebook, Inc. clm@fb.com

Tejasvi Chakravarthy Facebook, Inc. teju@fb.com Bharath Muthiah Facebook, Inc. bharathm@fb.com

Sriram Sankar Facebook Inc. sriramsankar@fb.com

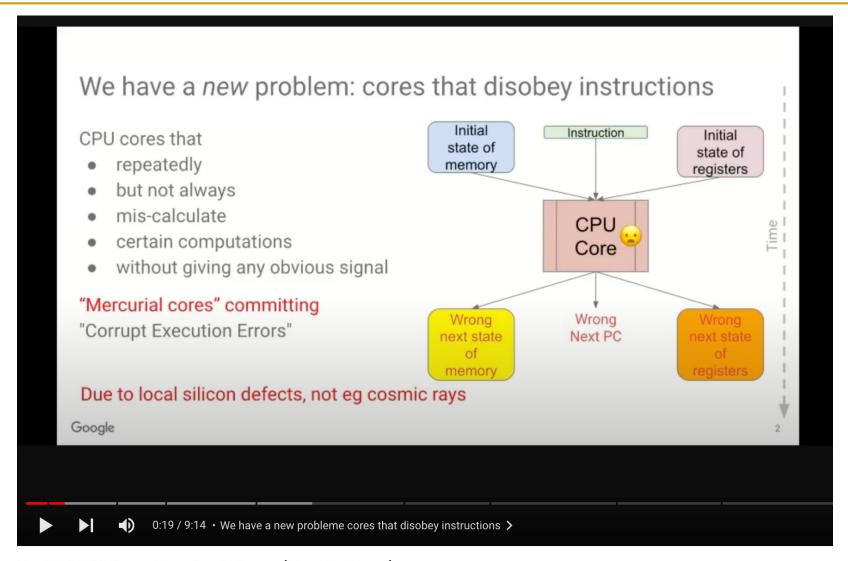
Cores that don't count

Peter H. Hochschild
Paul Turner
Jeffrey C. Mogul
Google
Sunnyvale, CA, US

Rama Govindaraju
Parthasarathy
Ranganathan
Google
Sunnyvale, CA, US

David E. Culler Amin Vahdat Google Sunnyvale, CA, US

Silent Data Corruption In-the-Field (2021)



HotOS 2021: Cores That Don't Count (Fun Hardware)

Silent Data Corruption in Logic (2023)

Understanding Silent Data Corruptions in a Large Production CPU Population

Shaobu Wang Tsinghua University

Yang Wang The Ohio State University Guangyan Zhang* Tsinghua University

> Jiesheng Wu Alibaba Cloud

Junyu Wei Tsinghua University

Qingchao Luo Alibaba Cloud

Understanding and Mitigating Hardware Failures in Deep Learning Training Accelerator Systems

Yi He University of Chicago Chciago, IL, USA yiizy@uchicago.edu

Robert de Gruijl Google Sunnyvale, CA, USA rdegruijl@google.com Mike Hutton Google Sunnyvale, CA, USA mdhutton@google.com

Rama Govindaraju Google Sunnyvale, CA, USA govindaraju@google.com

Yanjing Li University of Chicago Chciago, IL, USA yanjingl@uchicago.edu Steven Chan Google Sunnyvale, CA, USA scchan@google.com

Nishant Patil Google Sunnyvale, CA, USA nishantpatil@google.com

Takeaways

 Both memory and logic errors will become worse with technology scaling

Hardware errors will create worse robustness problems

We cannot afford to ignore data corruption

Acknowledgments

Acknowledgments



Think BIG, Aim HIGH!

https://safari.ethz.ch

SAFARI Research Group

Computer architecture, HW/SW, systems, bioinformatics, security, memory

https://safari.ethz.ch/safari-newsletter-january-2021/



Think BIG, Aim HIGH!

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https://safari.ethz.ch

SAFARI Research Group: December 2021

https://safari.ethz.ch/safari-newsletter-december-2021/



Think Big, Aim High





View in your browser December 2021



SAFARI Newsletter June 2023 Edition

https://safari.ethz.ch/safari-newsletter-june-2023/



Think Big, Aim High

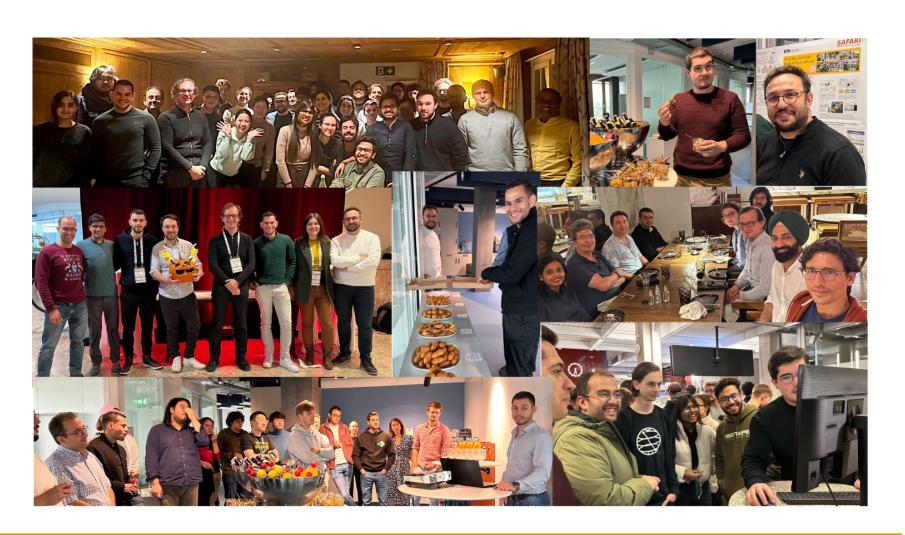






SAFARI Newsletter July 2024 Edition

https://safari.ethz.ch/safari-newsletter-july-2024/



SAFARI Introduction & Research

Computer architecture, HW/SW, systems, bioinformatics, security, memory



Seminar in Computer Architecture - Lecture 5: Potpourri of Research Topics (Spring 2023)













SAFARI

https://www.youtube.com/watch?v=mV2OuB2djEs

Funding Acknowledgments

- Alibaba, AMD, ASML, Google, Facebook, Hi-Silicon, HP Labs, Huawei, IBM, Intel, Microsoft, Nvidia, Oracle, Qualcomm, Rambus, Samsung, Seagate, VMware, Xilinx
- NSF
- NIH
- GSRC
- SRC
- CyLab
- EFCL
- SNSF
- ACCESS

Thank you!

Referenced Papers, Talks, Artifacts

All are available at

https://people.inf.ethz.ch/omutlu/projects.htm

https://www.youtube.com/onurmutlulectures

https://github.com/CMU-SAFARI/

Open Source Tools: SAFARI GitHub



SAFARI Research Group at ETH Zurich and Carnegie Mellon University

Site for source code and tools distribution from SAFARI Research Group at ETH Zurich and Carnegie Mellon University.

● ETH Zurich and Carnegie Mellon U...

Anttps://safari.ethz.ch/ omutlu@gmail.com

Overview

Repositories 98

Packages

8 People 13

☐ ramulator Public

A Fast and Extensible DRAM Simulator, with built-in support for modeling many different DRAM technologies including DDRx, LPDDRx, GDDRx, WIOx, HBMx, and various academic proposals. Described in the...

● C++ ☆ 519 ¥ 206

prim-benchmarks Public

PrIM (Processing-In-Memory benchmarks) is the first benchmark suite for a real-world processing-in-memory (PIM) architecture. PrIM is developed to evaluate, analyze, and characterize the first publ...

● C ☆ 125 ♀ 45

MQSim Public

MQSim is a fast and accurate simulator modeling the performance of modern multi-queue (MQ) SSDs as well as traditional SATA based SSDs. MQSim faithfully models new high-bandwidth protocol implement...

rowhammer Public

Source code for testing the Row Hammer error mechanism in DRAM devices. Described in the ISCA 2014 paper by Kim et al. at http://users.ece.cmu.edu/~omutlu/pub/dram-row-hammer_isca14.pdf.

● C ☆ 210 ♀ 43

SoftMC Public

SoftMC is an experimental FPGA-based memory controller design that can be used to develop tests for DDR3 SODIMMs using a C++ based API. The design, the interface, and its capabilities and limitatio...

Verilog ☆ 120 ♀ 27

Pythia (Public)

A customizable hardware prefetching framework using online reinforcement learning as described in the MICRO 2021 paper by Bera et al. (https://arxiv.org/pdf/2109.12021.pdf).

● C++ ☆ 107 ♀ 34

Ramulator 2.0

 Haocong Luo, Yahya Can Tugrul, F. Nisa Bostanci, Ataberk Olgun, A. Giray Yaglikci, and Onur Mutlu,

"Ramulator 2.0: A Modern, Modular, and Extensible DRAM Simulator" Preprint on arxiv, August 2023.

[arXiv version]

[Ramulator 2.0 Source Code]

Ramulator 2.0: A Modern, Modular, and Extensible DRAM Simulator

Haocong Luo, Yahya Can Tuğrul, F. Nisa Bostancı, Ataberk Olgun, A. Giray Yağlıkçı, and Onur Mutlu

https://arxiv.org/pdf/2308.11030.pdf

DRAM Bender

Ataberk Olgun, Hasan Hassan, A Giray Yağlıkçı, Yahya Can Tuğrul, Lois Orosa,
Haocong Luo, Minesh Patel, Oğuz Ergin, and Onur Mutlu,
"DRAM Bender: An Extensible and Versatile FPGA-based Infrastructure
to Easily Test State-of-the-art DRAM Chips"

<u>IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems</u> (**TCAD**), 2023.

[Extended arXiv version]

[DRAM Bender Source Code]

[DRAM Bender Tutorial Video (43 minutes)]

DRAM Bender: An Extensible and Versatile FPGA-based Infrastructure to Easily Test State-of-the-art DRAM Chips

Ataberk Olgun[§] Hasan Hassan[§] A. Giray Yağlıkçı[§] Yahya Can Tuğrul^{§†} Lois Orosa^{§⊙} Haocong Luo[§] Minesh Patel[§] Oğuz Ergin[†] Onur Mutlu[§] [§]ETH Zürich [†]TOBB ETÜ [⊙]Galician Supercomputing Center

RowHammer & DRAM Exploration (Fall 2022)

Fall 2022 Edition:

https://safari.ethz.ch/projects and seminars/fall2 022/doku.php?id=softmc

Spring 2022 Edition:

https://safari.ethz.ch/projects and seminars/spring2022/doku.php?id=softmc

Youtube Livestream (Spring 2022):

https://www.youtube.com/watch?v=r5QxuoJWttg &list=PL5Q2soXY2Zi 1trfCckr6PTN8WR72icUO

Bachelor's course

- Elective at ETH Zurich
- Introduction to DRAM organization & operation
- Tutorial on using FPGA-based infrastructure
- Verilog & C++
- Potential research exploration

Lecture Video Playlist on YouTube



2022 Meetings/Schedule (Tentative)

Week	Date	Livestream	Meeting	Learning Materials	Assignments
W0	23.02 Wed.	You Tube Video	P&S SoftMC Tutorial	SoftMC Tutorial Slides (PDF) (PPT)	
W1	08.03 Tue.	You Tube Video	M1: Logistics & Intro to DRAM and SoftMC	Required Materials Recommended Materials	HW0
W2	15.03 Tue.	You Tube Video	M2: Revisiting RowHammer (PDF) (PPT)	(Paper PDF)	
W3	22.03 Tue.	You Tube Video	M3: Uncovering in-DRAM TRR & TRRespass (PPT) (PPT)		
W4	29.03 Tue.	You Tube Video	M4: Deeper Look Into RowHammer's Sensitivities (PDF) (PPT)		
W5	05.04 Tue.	You Tube Video	M5: QUAC-TRNG (PDF) (PPT)		
W6	12.04 Tue.	You Tube Video	M6: PiDRAM (PDF) (PPT)		

https://www.youtube.com/onurmutlulectures

Exploration of Emerging Memory Systems (Fall 2022)

Fall 2022 Edition:

https://safari.ethz.ch/projects and seminars/fall2 022/doku.php?id=ramulator

Spring 2022 Edition:

https://safari.ethz.ch/projects and seminars/spring2022/doku.php?id=ramulator

Youtube Livestream (Spring 2022):

https://www.youtube.com/watch?v=aMllXRQd3s&list=PL5Q2soXY2Zi TlmLGw Z8hBo292 5ZApqV

Bachelor's course

- Elective at ETH Zurich
- Introduction to memory system simulation
- Tutorial on using Ramulator
- □ C++
- Potential research exploration

Ramulator Course: Meeting 1: Logistics & Int... P&S Ramulator Designing and Evaluating Memory Systems and Modern Software Workloads with Ramulator Hasan Hassan Prof. Onur Mutlu ETH Zürich

2022 Meetings/Schedule (Tentative)

Lecture Video Playlist on YouTube

Week	Date	Livestream	Meeting	Learning Materials	Assignments
W1	09.03 Wed.	You Tube Video	M1: Logistics & Intro to Simulating Memory Systems Using Ramulator (PDF) (PPT)		HW0
W2	16.03 Fri.	You Tube Video	M2: Tutorial on Using Ramulator (PDF) (PPT)		
W3	25.02 Fri.	You Tube Video	M3: BlockHammer (PDF) (PPT)		
W4	01.04 Fri.	You Tube Video	M4: CLR-DRAM (PDF) (PPT)		
W5	08.04 Fri.	You Tube Video	M5: SIMDRAM (PDF) (PPT)		
W6	29.04 Fri.	You Tube Video	M6: DAMOV (PDF) (PPT)		
W7	06.05 Fri.	You Tube Video	M7: Syncron (PDF) (PPT)		

https://www.youtube.com/onurmutlulectures



More RowHammer in 2020-2024

RowHammer in 2020 (I)

MICRO 2020 Submit Work ▼ Program ▼ Atte

Session 1A: Security & Privacy I 5:00 PM CEST - 5:15 PM CEST Graphene: Strong yet Lightweight Row Hammer Protection Yeonhong Park, Woosuk Kwon, Eojin Lee, Tae Jun Ham, Jung Ho Ahn, Jae W. Lee (Seoul National University) 5:15 PM CEST - 5:30 PM CEST Persist Level Parallelism: Streamlining Integrity Tree Updates for Secure Persistent Memory Alexander Freij, Shougang Yuan, Huiyang Zhou (NC State University); Yan Solihin (University of Central Florida) 5:30 PM CEST - 5:45 PM CEST PThammer: Cross-User-Kernel-Boundary Rowhammer through Implicit Accesses Zhi Zhang (University of New South Wales and Data61, CSIRO, Australia); Yueqiang Cheng (Baidu Security); Dongxi Liu, Surya Nepal (Data61, CSIRO, Australia); Zhi Wang (Florida State University); Yuval Yarom (University of Adelaide and Data61, CSIRO, Australia)

RowHammer in 2020 (II)

Session #5: Rowhammer

Room 2

Session chair: Michael Franz (UC Irvine)

RAMBleed: Reading Bits in Memory Without Accessing Them

Andrew Kwong (University of Michigan), Daniel Genkin (University of Michigan), Daniel Gruss Data61)

Are We Susceptible to Rowhammer? An End-to-End Methodology for Cloud Providers Lucian Cojocar (Microsoft Research), Jeremie Kim (ETH Zurich, CMU), Minesh Patel (ETH Zu (Microsoft Research), Onur Mutlu (ETH Zurich, CMU)

Leveraging EM Side-Channel Information to Detect Rowhammer Attacks

Zhenkai Zhang (Texas Tech University), Zihao Zhan (Vanderbilt University), Daniel Balasubrar Peter Volgyesi (Vanderbilt University), Xenofon Koutsoukos (Vanderbilt University)

TRRespass: Exploiting the Many Sides of Target Row Refresh

Pietro Frigo (Vrije Universiteit Amsterdam, The Netherlands), Emanuele Vannacci (Vrije Universiteit Amsterdam, The Netherlands), Cristiano Giuffrida (Vrije Universiteit Amsterdam, The Netherlands)

RowHammer in 2020 (III)

29TH USENIX SECURITY SYMPOSIUM

ATTEND

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DeepHammer: Depleting the Intelligence of Deep Neural Networks through Targeted Chain of Bit Flips

Fan Vao University of Central Florida: Adnan Sirai Rakin and Deliang Fan Arizona State University

Fan Yao, *University of Central Florida*; Adnan Siraj Rakin and Deliang Fan, *Arizona State University*

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Show details ▶

RowHammer in 2020 (IV)

CHES 2020

JackHammer: Efficient Rowhammer on Heterogeneous FPGA-CPU Platforms

Zane Weissman¹, Thore Tiemann², Daniel Moghimi¹, Evan Custodio³, Thomas Eisenbarth² and Berk Sunar¹

Worcester Polytechnic Institute, MA, USA

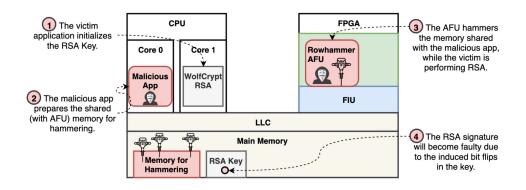
zweissman@wpi.edu, amoghimi@wpi.edu, sunar@wpi.edu

² University of Lübeck, Lübeck, Germany

thore.tiemann@student.uni-luebeck.de, thomas.eisenbarth@uni-luebeck.de

³ Intel Corporation, Hudson, MA, USA

evan.custodio@intel.com



An **FPGA-based** RowHammer attack recovering **private keys** twice as fast compared to **CPU-based** attacks

RowHammer in 2021 (I)

HotOS XVIII

The 18th Workshop on Hot Topics in Operating Systems

31 May 1 June-3 June 2021, Cyberspace, People's Couches, and Zoom

Stop! Hammer Time: Rethinking Our Approach to Rowhammer Mitigations

RowHammer in 2021 (II)



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SMASH: Synchronized Many-sided Rowhammer Attacks from JavaScript

RowHammer in 2021 (III)



Session 10A: Security & Privacy III

Session Chair: Hoda Naghibijouybari (Binghamton)

9:00 PM CEST - 9:15 PM CEST

A Deeper Look into RowHammer's Sensitivities: Experimental Analysis of Real DRAM Chips and Implications on Future Attacks and Defenses

Lois Orosa, Abdullah Giray Yaglikci, Haocong Luo (ETH Zurich); Ataberk Olgun (TOBB University of Economics and Technology); Jisung Park, Hasan Hassan, Minesh Patel, Jeremie S. Kim, Onur Mutlu (ETH Zurich)

Paper

9:15 PM CEST - 9:30 PM CEST

Uncovering In-DRAM RowHammer Protection Mechanisms: A New Methodology, Custom RowHammer Patterns, and Implications

Hasan Hassan (ETH Zurich); Yahya Can Tugrul (TOBB University of Economics and Technology); Jeremie S. Kim (ETH Zurich); Victor van der Veen (Qualcomm); Kaveh Razavi, Onur Mutlu (ETH Zurich)

Paper

SAFARI 253

RowHammer in 2022 (I)

MAY 22-26, 2022 AT THE HYATT REGENCY, SAN FRANCISCO, CA

43rd IEEE Symposium on Security and Privacy

BLACKSMITH: Scalable Rowhammering in the Frequency Domain

SpecHammer: Combining Spectre and Rowhammer for New Speculative Attacks

PROTRR: Principled yet Optimal In-DRAM Target Row Refresh

DeepSteal: Advanced Model Extractions Leveraging Efficient Weight Stealing in Memories

SAFARI

RowHammer in 2022 (II)



Randomized Row-Swap: Mitigating Row Hammer by Breaking Spatial Correlation between Aggressor and Victim Rows

255

RowHammer in 2022 (III)

HPCA 2022

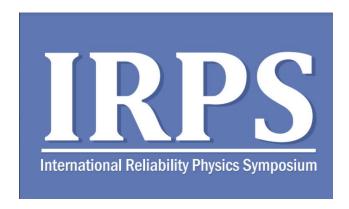
The 28th IEEE International Symposium on High-Performance Computer Architecture (HPCA-28), Seoul, South Korea

SafeGuard: Reducing the Security Risk from Row-Hammer via Low-Cost Integrity Protection

Mithril: Cooperative Row Hammer Protection on Commodity DRAM Leveraging

Managed Refresh

RowHammer in 2022 (IV)



IRPS 2022

The Price of Secrecy: How Hiding Internal DRAM Topologies Hurts Rowhammer Defenses

Stefan Saroiu, Alec Wolman, Lucian Cojocar Microsoft

RowHammer in 2022 (V)



Half-Double: Hammering From the Next Row Over

```
Andreas Kogler<sup>1</sup> Jonas Juffinger<sup>1,2</sup> Salman Qazi<sup>3</sup> Yoongu Kim<sup>3</sup> Moritz Lipp<sup>4*</sup> Nicolas Boichat<sup>3</sup> Eric Shiu<sup>5</sup> Mattias Nissler<sup>3</sup> Daniel Gruss<sup>1</sup>
```

¹Graz University of Technology ²Lamarr Security Research ³Google ⁴Amazon Web Services ⁵Rivos

258

RowHammer in 2022 (VI)



HAMMERScope: Observing DRAM Power Consumption Using Rowhammer

When Frodo Flips: End-to-End Key Recovery on FrodoKEM via Rowhammer

RowHammer in 2022 (VII)



AQUA: Scalable Rowhammer Mitigation by Quarantining Aggressor Rows at Runtime

Anish Saxena, Gururaj Saileshwar (Georgia Institute of Technology); Prashant J. Nair (University of British Columbia); Moinuddin Qureshi (Georgia Institute of Technology)

HiRA: Hidden Row Activation for Reducing Refresh Latency of Off-the-Shelf DRAM Chips

Abdullah Giray Yaglikci (ETH Zürich); Ataberk Olgun (TOBB University of Economics and Technology); Lois Orosa, Minesh Patel, Haocong Luo, Hasan Hassan (ETH Zürich); Oguz Ergin (TOBB University of Economics and Technology); Onur Mutlu (ETH Zürich)

RowHammer in 2022 (VII)

 A. Giray Yaglıkcı, Ataberk Olgun, Minesh Patel, Haocong Luo, Hasan Hassan, Lois Orosa, Oguz Ergin, and Onur Mutlu,

"HiRA: Hidden Row Activation for Reducing Refresh Latency of Off-the-Shelf DRAM Chips"

Proceedings of the <u>55th International Symposium on Microarchitecture</u> (**MICRO**), Chicago, IL, USA, October 2022.

[Slides (pptx) (pdf)]

[Longer Lecture Slides (pptx) (pdf)]

[Lecture Video (36 minutes)]

[arXiv version]

HiRA: Hidden Row Activation

for Reducing Refresh Latency of Off-the-Shelf DRAM Chips

A. Giray Yağlıkçı¹ Ataberk Olgun^{1,2} Minesh Patel¹ Haocong Luo¹ Hasan Hassan¹ Lois Orosa^{1,3} Oğuz Ergin² Onur Mutlu¹

¹ETH Zürich ²TOBB University of Economics and Technology ³Galicia Supercomputing Center (CESGA)

https://arxiv.org/pdf/2209.10198.pdf

261

RowHammer in 2022 (VIII)

A Case for Transparent Reliability in DRAM Systems

```
Minesh Patel<sup>†</sup> Taha Shahroodi<sup>‡†</sup> Aditya Manglik<sup>†</sup> A. Giray Yağlıkçı<sup>†</sup> Ataberk Olgun<sup>†</sup> Haocong Luo<sup>†</sup> Onur Mutlu<sup>†</sup> ^{\dagger}ETH \, Z \ddot{u} rich \quad ^{\ddagger}TU \, Delft
```

https://arxiv.org/pdf/2204.10378.pdf

262

RowHammer in 2022 (IX)

A Case for Self-Managing DRAM Chips: Improving Performance, Efficiency, Reliability, and Security via Autonomous in-DRAM Maintenance Operations

Hasan Hassan

Ataberk Olgun

A. Giray Yağlıkçı

Haocong Luo

Onur Mutlu

ETH Zürich

https://arxiv.org/pdf/2207.13358.pdf

RowHammer in 2023 (I)

MAY 22-26, 2023 AT THE HYATT REGENCY, SAN FRANCISCO, CA

44th IEEE Symposium on Security and Privacy

Session 6C: Rowhammer and spectre Bayview AB 11:00 AM - 12:15 PM

Session Chair: Eyal Ronen

REGA: Scalable Rowhammer Mitigation with Refresh-Generating Activations

Michele Marazzi (ETH Zurich), Flavien Solt (ETH Zurich), Patrick Jattke (ETH Zurich), Kubo Takashi (Zentel Japan), Kaveh Razavi (ETH Zurich)

CSI:Rowhammer - Cryptographic Security and Integrity against Rowhammer

Jonas Juffinger (Lamarr Security Research, Graz University of Technology, Austria), Lukas Lamster (Graz University of Technology, Austria), Andreas Kogler (Graz University of Technology, Austria), Moritz Lipp (Amazon Web Services, Austria), Daniel Gruss (Graz University of Technology, Austria)

Technology, Austria)

Jolt: Recovering TLS Signing Keys via Rowhammer Faults

Koksal Mus (Worcester Polytechnic Institute), Yarkın Doröz (Worcester Polytechnic Institute), M. Caner Tol (Worcester Polytechnic Institute), Kristi Rahman (Worcester Polytechnic Institute), Berk Sunar (Worcester Polytechnic Institute)



RowHammer in 2023 (II)

HPCA 2023

The 29th IEEE International Symposium on High-Performance Computer Architecture (HPCA-29)

Scalable and Secure Row-Swap:
Efficient and Safe Row Hammer
Mitigation in Memory Systems
Jeonghyun Woo (University of
British Columbia),
Gururaj Saileshwar (Georgia
Institute of Technology),
Prashant J. Nair (University of
British Columbia)

SHADOW: Preventing Row Hammer in DRAM with Intra-Subarray Row Shuffling Minbok Wi (Seoul National University), Jaehyun Park (Seoul National University), Seoyoung Ko (Seoul National University), Michael Jaemin Kim (Seoul National University), Nam Sung Kim (UIUC), Eojin Lee (Inha University), Jung Ho Ahn (Seoul National University)

RowHammer in 2023 (III): SK Hynix

ISSCC 2023 / SESSION 28 / HIGH-DENSITY MEMORIES /

28.8 A 1.1V 16Gb DDR5 DRAM with Probabilistic-Aggressor Tracking, Refresh-Management Functionality, Per-Row Hammer Tracking, a Multi-Step Precharge, and Core-Bias Modulation for Security and Reliability Enhancement

Woongrae Kim, Chulmoon Jung, Seongnyuh Yoo, Duckhwa Hong, Jeongjin Hwang, Jungmin Yoon, Ohyong Jung, Joonwoo Choi, Sanga Hyun, Mankeun Kang, Sangho Lee, Dohong Kim, Sanghyun Ku, Donhyun Choi, Nogeun Joo, Sangwoo Yoon, Junseok Noh, Byeongyong Go, Cheolhoe Kim, Sunil Hwang, Mihyun Hwang, Seol-Min Yi, Hyungmin Kim, Sanghyuk Heo, Yeonsu Jang, Kyoungchul Jang, Shinho Chu, Yoonna Oh, Kwidong Kim, Junghyun Kim, Soohwan Kim, Jeongtae Hwang, Sangil Park, Junphyo Lee, Inchul Jeong, Joohwan Cho, Jonghwan Kim

SK hynix Semiconductor, Icheon, Korea

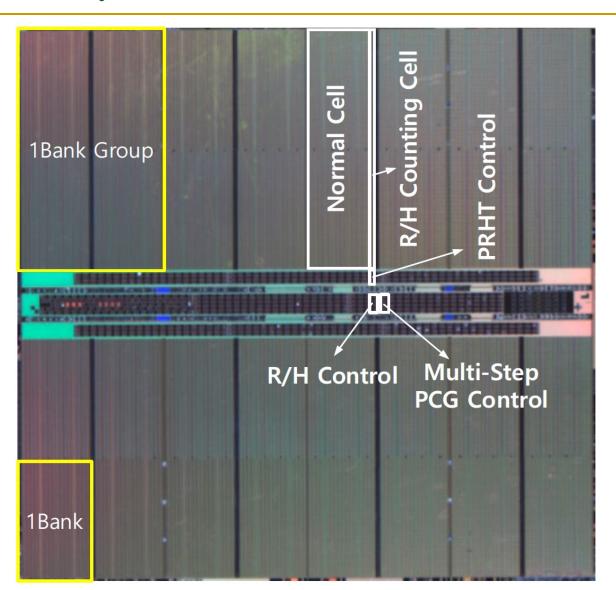


Industry's RowHammer Solutions (I)

SK hynix Semiconductor, Icheon, Korea

DRAM products have been recently adopted in a wide range of high-performance computing applications: such as in cloud computing, in big data systems, and IoT devices. This demand creates larger memory capacity requirements, thereby requiring aggressive DRAM technology node scaling to reduce the cost per bit [1,2]. However, DRAM manufacturers are facing technology scaling challenges due to row hammer and refresh retention time beyond 1a-nm [2]. Row hammer is a failure mechanism, where repeatedly activating a DRAM row disturbs data in adjacent rows. Scaling down severely threatens reliability since a reduction of DRAM cell size leads to a reduction in the intrinsic row hammer tolerance [2,3]. To improve row hammer tolerance, there is a need to probabilistically activate adjacent rows with carefully sampled active addresses and to improve intrinsic row hammer tolerance [2]. In this paper, row-hammer-protection and refresh-management schemes are presented to guarantee DRAM security and reliability despite the aggressive scaling from 1a-nm to sub 10-nm nodes. The probabilisticaggressor-tracking scheme with a refresh-management function (RFM) and per-row hammer tracking (PRHT) improve DRAM resilience. A multi-step precharge reinforces intrinsic row-hammer tolerance and a core-bias modulation improves retention time: even in the face of cell-transistor degradation due to technology scaling. This comprehensive scheme leads to a reduced probability of failure, due to row hammer attacks, by 93.1% and an improvement in retention time by 17%.

Industry's RowHammer Solutions (II)



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SK hynix Semiconductor, Icheon, Korea

RowHammer in 2023 (IV): Samsung

DSAC: Low-Cost Rowhammer Mitigation Using In-DRAM Stochastic and Approximate Counting Algorithm

Seungki Hong Dongha Kim Jaehyung Lee Reum Oh Changsik Yoo Sangjoon Hwang Jooyoung Lee

DRAM Design Team, Memory Division, Samsung Electronics

https://arxiv.org/pdf/2302.03591v1.pdf

269

RowHammer in 2023 (V)





[28 June, 14:30-16:00] RT-3: Memory 1 (Session Chair: TBD)

Compiler-Implemented Differential Checksums: Effective Detection and Correction of Transient and Permanent Memory Errors (REG)

C. Borchert; H. Schirmeier; O. Spinczyk

PT-Guard: Integrity-Protected Page Tables to Defend Against Breakthrough Rowhammer Attacks (REG)

A. Saxena; G. Saileshwar; J. Juffinger; A. Kogler; D. Gruss; M. Qureshi

Don't Knock! Rowhammer at the Backdoor of DNN Models (REG)

M. Tol; S. Islam; A. Adiletta; B. Sunar; Z. Zhang

[29 June, 16:00-17:30] DS23-4: Hardware Resilience and Human Factors (Session Chair: TBD)

An Experimental Analysis of RowHammer in HBM2 DRAM Chips

Ataberk Olgun, Majd Osseiran, Abdullah Giray Yaglikci, Yahya Can Tugrul, Juan Gomez Luna, Haocong Luo, Behzad Salami, Steve Rhyner and Onur Mutlu

SAFARI

RowHammer in 2023 (VI)

SOSP 2023

SOSP 2023

The 29th ACM Symposium on Operating Systems Principles
October 23-26, 2023

Siloz: Leveraging DRAM Isolation Domains to Prevent Inter-VM Rowhammer

Kevin Loughlin University of Michigan

> Alec Wolman Microsoft

Jonah Rosenblum University of Michigan

Dimitrios Skarlatos Carnegie Mellon University Stefan Saroiu Microsoft

Baris Kasikci University of Washington and Google

RowHammer in 2023 (VII)

IEEE Computer Architecture Letters, 2023

NoHammer: Preventing Row Hammer with Last-Level Cache Management

Seunghak Lee, Ki-Dong Kang, Gyeongseo Park, Nam Sung Kim, and Daehoon Kim

Ramulator 2.0: A Modern, Modular, and Extensible DRAM Simulator

Haocong Luo, Yahya Can Tuğrul, F. Nisa Bostancı, Ataberk Olgun, A. Giray Yağlıkçı, and Onur Mutlu

IEEE Embedded Systems Letters, 2023

Flipping Bits Like a Pro: Precise Rowhammering on Embedded Devices

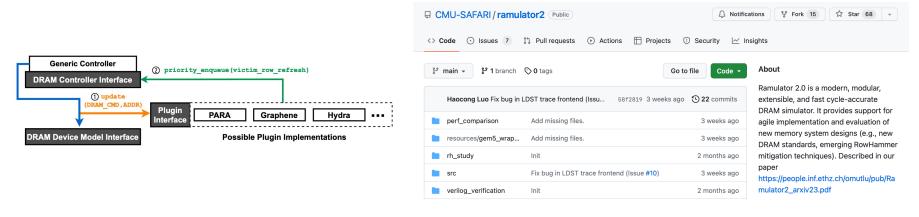
Anandpreet Kaur, Pravin Srivastav, Bibhas Ghoshal Systems Lab, Indian Institute of Information Technology Allahabad (IIITA)

Ramulator 2.0

"Ramulator 2.0: A Modern, Modular, and Extensible DRAM Simulator"

IEEE Computer Architecture Letters, August 2023. (Preprint on arxiv)

[arXiv version] [Ramulator 2.0 Source Code]



Ramulator 2.0: A Modern, Modular, and Extensible DRAM Simulator

Haocong Luo, Yahya Can Tuğrul, F. Nisa Bostancı, Ataberk Olgun, A. Giray Yağlıkçı, and Onur Mutlu

RowHammer in 2023 (VIII)

MEMSYS 2023

RAMPART: RowHammer Mitigation and Repair for Server Memory Systems

Steven C. Woo Rambus Labs Rambus Inc. San Jose, CA swoo@rambus.com Wendy Elsasser Rambus Labs Rambus Inc. San Jose, CA welsasser@rambus.com Mike Hamburg
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Taeksang Song Rambus Labs Rambus Inc. San Jose, CA tsong@rambus.com James Tringali Rambus Labs Rambus Inc. San Jose, CA jamestr@rambus.com

MICRO 2023

How to Kill the Second Bird with One ECC: The Pursuit of Row Hammer Resilient DRAM

Michael Jaemin Kim, Minbok Wi, Jaehyun Park, Seoyoung Ko, Jae Young Choi, Hwayoung Nam (Seoul National University); Nam Sung Kim (University of Illinois Urbana Champaign); Jung Ho Ahn (Seoul National University); Eojin Lee (Inha University)

Related Courses

DDCA (Spring 2022)

Spring 2022 Edition:

https://safari.ethz.ch/digitaltechnik/spring2022/do ku.php?id=schedule

Spring 2021 Edition:

https://safari.ethz.ch/digitaltechnik/spring2021/do ku.php?id=schedule

Youtube Livestream (Spring 2022):

https://www.youtube.com/watch?v=cpXdE3HwvK 0&list=PL5O2soXY2Zi97Ya5DEUpMpO2bbAoaG7c6

Youtube Livestream (Spring 2021):

https://www.youtube.com/watch?v=LbC0EZY8yw 4&list=PL5O2soXY2Zi uei3aY39YB5pfW4SJ7LIN

Bachelor's course

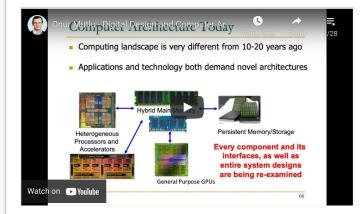
- 2nd semester at ETH Zurich
- Rigorous introduction into "How Computers Work"
- Digital Design/Logic
- Computer Architecture
- 10 FPGA Lab Assignments



- Lectures/Schedule
- Lecture Buzzwords
- Readings
- Ontional HWs
- Extra Assignments Technical Docs
- Exams

- Computer Architecture (CMU)
- SS15: Lecture Videos
- Computer Architecture (CMU) SS15: Course Website
- Digitaltechnik SS18: Lecture
- Digitaltechnik SS18: Course Website
- Digitaltechnik SS19: Lecture
- Digitaltechnik SS19: Course Digitaltechnik SS20: Lecture
- Digitaltechnik SS20: Course Website
- Moodle Moodle

Lecture Video Playlist on YouTube



Recent Changes Media Manager Siter

Recorded Lecture Playlist



Spring 2021 Lectures/Schedule

Week	Date	Livestream	Lecture	Readings	Lab	HW
W1	25.02 Thu.	You Tube Live	L1: Introduction and Basics	Required Suggested Mentioned		
	26.02 Fri.	You Live	L2a: Tradeoffs, Metrics, Mindset	Required		
			L2b: Mysteries in Computer Architecture (PDF) an (PPT)	Required Mentioned		
W2	04.03 Thu.	You Tube Live	L3a: Mysteries in Computer Architecture II	Required Suggested		

https://www.youtube.com/onurmutlulectures

Comp Arch (Fall 2022)

Fall 2022 Edition:

https://safari.ethz.ch/architecture/fall2022/doku. php?id=schedule

Fall 2021 Edition:

https://safari.ethz.ch/architecture/fall2021/doku. php?id=schedule

Youtube Livestream (2022):

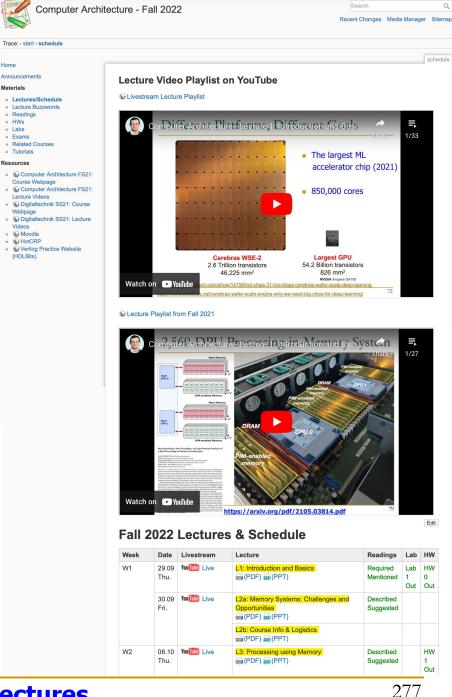
https://www.youtube.com/watch?v=4yfkM 5EFq o&list=PL5Q2soXY2Zi-Mnk1PxjEIG32HAGILkTOF

Youtube Livestream (2021):

https://www.youtube.com/watch?v=4yfkM 5EFq o&list=PL5O2soXY2Zi-Mnk1PxiEIG32HAGILkTOF

Master's level course

- Taken by Bachelor's/Masters/PhD students
- Cutting-edge research topics + fundamentals in Computer Architecture
- 5 Simulator-based Lab Assignments
- Potential research exploration
- Many research readings



RowHammer & DRAM Exploration (Fall 2022)

Fall 2022 Edition:

https://safari.ethz.ch/projects and seminars/fall2 022/doku.php?id=softmc

Spring 2022 Edition:

https://safari.ethz.ch/projects and seminars/spring2022/doku.php?id=softmc

Youtube Livestream (Spring 2022):

https://www.youtube.com/watch?v=r5QxuoJWttg &list=PL5Q2soXY2Zi 1trfCckr6PTN8WR72icUO

Bachelor's course

- Elective at ETH Zurich
- Introduction to DRAM organization & operation
- Tutorial on using FPGA-based infrastructure
- Verilog & C++
- Potential research exploration

Lecture Video Playlist on YouTube

Lecture Playlist



2022 Meetings/Schedule (Tentative)

Week	Date	Livestream	Meeting	Learning Materials	Assignments
W0	23.02 Wed.	You Tube Video	P&S SoftMC Tutorial	SoftMC Tutorial Slides (PDF) (PPT)	
W1	08.03 Tue.	You Tube Video	M1: Logistics & Intro to DRAM and SoftMC	Required Materials Recommended Materials	HW0
W2	15.03 Tue.	You Tube Video	M2: Revisiting RowHammer (PDF) (PPT)	(Paper PDF)	
W3	22.03 Tue.	YouTube Video	M3: Uncovering in-DRAM TRR & TRRespass (PPT) (PPT)		
W4	29.03 Tue.	You Tube Video	M4: Deeper Look Into RowHammer's Sensitivities (PDF) (PPT)		
W5	05.04 Tue.	You Tube Video	M5: QUAC-TRNG (PDF) (PPT)		
W6	12.04 Tue.	You Tube Video	M6: PiDRAM (PDF) (PPT)		

https://www.youtube.com/onurmutlulectures

Exploration of Emerging Memory Systems (Fall 2022)

Fall 2022 Edition:

https://safari.ethz.ch/projects and seminars/fall2022/doku.php?id=ramulator

Spring 2022 Edition:

https://safari.ethz.ch/projects and seminars/spring2022/doku.php?id=ramulator

Youtube Livestream (Spring 2022):

 https://www.youtube.com/watch?v=aM- | IIXRQd3s&list=PL5Q2soXY2Zi TlmLGw Z8hBo292 | 5ZApqV

Bachelor's course

- Elective at ETH Zurich
- Introduction to memory system simulation
- Tutorial on using Ramulator
- C++
- Potential research exploration



2022 Meetings/Schedule (Tentative)

Week	Date	Livestream	Meeting	Learning Materials	Assignments
W1	09.03 Wed.	You Tube Video	M1: Logistics & Intro to Simulating Memory Systems Using Ramulator (PDF) (PPT)		HW0
W2	16.03 Fri.	You Tube Video	M2: Tutorial on Using Ramulator (PDF) (PPT)		
W3	25.02 Fri.	You Tube Video	M3: BlockHammer (PDF) (PPT)		
W4	01.04 Fri.	You Tube Video	M4: CLR-DRAM (PDF) (PPT)		
W5	08.04 Fri.	You Tube Video	M5: SIMDRAM (PDF) (PPT)		
W6	29.04 Fri.	You Tube Video	M6: DAMOV (PDF) (PPT)		
W7	06.05 Fri.	You Tube Video	M7: Syncron (PDF) (PPT)		

https://www.youtube.com/onurmutlulectures